

MSPM0C110x-Q1 車載ミックスド・シグナル・マイクロコントローラ

1 特長

- 車載アプリケーション向けに **AEC-Q100** 認証済み
 - 温度グレード 1: -40°C ~ +125°C、T_A
- コア
 - Arm® 32 ビット Cortex®-M0+ CPU、最高 24MHz の周波数
- 動作特性
 - 拡張動作温度範囲: -40°C ~ 125°C
 - 広い電源電圧範囲: 1.62V ~ 3.6V
- メモリ
 - 最大 16KB のフラッシュ
 - 1KB の SRAM
- 高性能アナログ ペリフェラル
 - 1 つの A/D コンバータ (ADC)、合計最大 10 本の外部チャネルを装備、VDD を電圧リファレンスとして使用して 1.7MSPS (10 ビット) または 1.5MSPS (12 ビット)
 - 1.4V または 2.5V の構成可能な内部共有電圧リファレンス (VREF)
 - 温度センサ内蔵
 - 統合型電源監視
- 最適化された低消費電力モード
 - RUN: 87µA/MHz
 - STOP: 4MHz で 609µA、32kHz で 311µA
 - STANDBY: 5µA (SRAM 保持)
 - SHUTDOWN: 200nA
- インテリジェント デジタル ペリフェラル
 - ADC 専用の 1 チャネル DMA コントローラ
 - 最大 14 の PWM チャネルをサポートする 3 つのタイマ
 - 1 つの 16 ビット高度タイマ、最大 8 個の PWM チャネルのデッドバンドをサポート
 - 1 つの 16 ビット汎用タイマ、4 つのキャプチャ / コンパレータを搭載
 - 1 つの 16 ビット汎用タイマ、2 つのキャプチャ / コンパレータを搭載
 - ウィンドウ付きウォッチドッグ タイマ
 - 外部ビープ音を駆動するための 1kHz、2kHz、4kHz、または 8kHz の方形波を生成する BEEPER
- 拡張通信インターフェイス
 - 1 つの UART インターフェイス: LIN、IrDA、DALI、スマートカード、マンチェスターをサポート、STANDBY モードで低消費電力動作
 - 1 つの I²C インターフェイス。FM+ (1Mbps)、SMBus、PMBus、STOP モードからのウェークアップをサポート

- 最大 12Mbps をサポートする 1 つの SPI
- クロック システム
 - -2% ~ +1.2% の精度 (SYSOSC) の 24MHz 発振器を内蔵
 - 32kHz の低周波数発振器 (LFOSC) を内蔵
- データの整合性
 - 巡回冗長検査 (CRC-16)
- 柔軟な I/O 機能
 - 最大 18 の GPIO
 - 2 つの 5V 許容オープンドレイン IO
- 開発サポート
 - 2 ピン シリアル ワイヤ デバッグ (SWD)
- パッケージ オプション
 - 20 ピン VSSOP (DGS)
 - 20 ピン WQFN (RUK)
 - 16 ピン SOT (DYY)
 - 8 ピン SOT (DDF)
 - 8 ピン WSON (DSG)
- ファミリの製品 ([「製品比較」](#)も参照)
 - MSPM0C1104: 16KB のフラッシュ、1KB の RAM
 - MSPM0C1103: 8KB のフラッシュ、1KB の RAM
- 開発キットとソフトウェア ([「ツールとソフトウェア」](#)も参照)
 - LP-MSPM0C1104 LaunchPad™ 開発キット
 - MSP ソフトウェア開発キット (SDK)

2 アプリケーション

- 車載用ボディ・エレクトロニクス / ライティング
- 車載用ゲートウェイ
- ステアリング・ホイール・システム
- 車載用モーター制御
- DC / AC インバータ
- 車内照明
- ドア・ハンドル・モジュール
- キック・ツル・オープン・モジュール
- 車両の乗員検出
- コンフォート・シート・モジュール



3 概要

MSPM0C110x マイクロコントローラ (MCU) は、最大 24MHz の周波数で動作する拡張 Arm® Cortex®-M0+ コアプラットフォームに基づく MSP 高集積超低消費電力 32 ビット MCU ファミリの一部です。コスト最適化されたこれらの MCU は高性能アナログ ペリフェラルを統合しており、-40°C ~ 125°C の拡張温度範囲をサポートしており、1.62V ~ 3.6V の電源電圧で動作します。

MSPM0C110x デバイスは最大 16KB の組込みフラッシュ プログラム メモリと 1KB の SRAM を内蔵しています。これらの MCU は -2% ~ +1.2% の精度の高速オンチップ発振器を内蔵しているため、外部水晶振動子は不要です。追加機能には、1 チャンネル DMA、CRC-16 アクセラレータ、各種の高性能アナログ ペリフェラル (電圧リファレンスとして VDD を含む 12 ビット 1.5MSPS ADC、1 つのオンチップ温度センサなど) が含まれます。これらのデバイスは、1 つの 16 ビット高度タイマ、2 つの 16 ビット汎用タイマ、1 つのウィンドウ付きウォッチドッグ タイマ、各種通信ペリフェラル (1 つの UART、1 つの SPI、1 つの I²C など) などのインテリジェントなデジタル ペリフェラルも備えています。これらの通信ペリフェラルは LIN、IrDA、DALI、マンチェスター、スマート カード、SMBus、PMBus プロトコルをサポートしています。

テキサス・インスツルメンツの MSPM0 低消費電力 MCU ファミリーは、各種のアナログおよびデジタル集積度のデバイスで構成されているため、お客様はプロジェクトのニーズを満たす MCU を見つけることができます。そのアーキテクチャと豊富な低消費電力モードは、携帯型測定アプリケーションで長いバッテリー駆動時間を実現するように最適化されています。

MSPM0C110x MCU は、広範囲にわたるハードウェアおよびソフトウェアのエコシステムによってサポートされており、リファレンス デザインやコード サンプルを使って設計をすぐに開始できます。開発キットには、購入可能な LaunchPad™ キットとターゲット ソケット ボード用の設計ファイルが含まれています。また、テキサス・インスツルメンツは無償の MSP ソフトウェア開発キット (SDK) も提供しており、Code Composer Studio™ IDE デスクトップのコンポーネントとして利用できます。また、TI Resource Explorer ではクラウド バージョンを利用できます。MSPM0 MCU には、広範囲にわたるオンライン資料、MSP Academy によるトレーニング、TI E2E™ サポート フォーラムによるオンライン サポートも用意されています。

モジュールの詳細については、『MSPM0 C シリーズ 24MHz マイクロコントローラ テクニカル リファレンス マニュアル』を参照してください。

注意

電氣的な過剰ストレスや、データやコード メモリの不安定化を防止するために、デバイス レベルの ESD 仕様に従って、システム レベルの ESD 保護を適用する必要があります。詳細については、『MSP430™ のシステム レベルの ESD に関する考慮事項』を参照してください (このアプリケーション ノートの原理は MSPM0 MCU にも当てはまるため)。

4 機能ブロック図

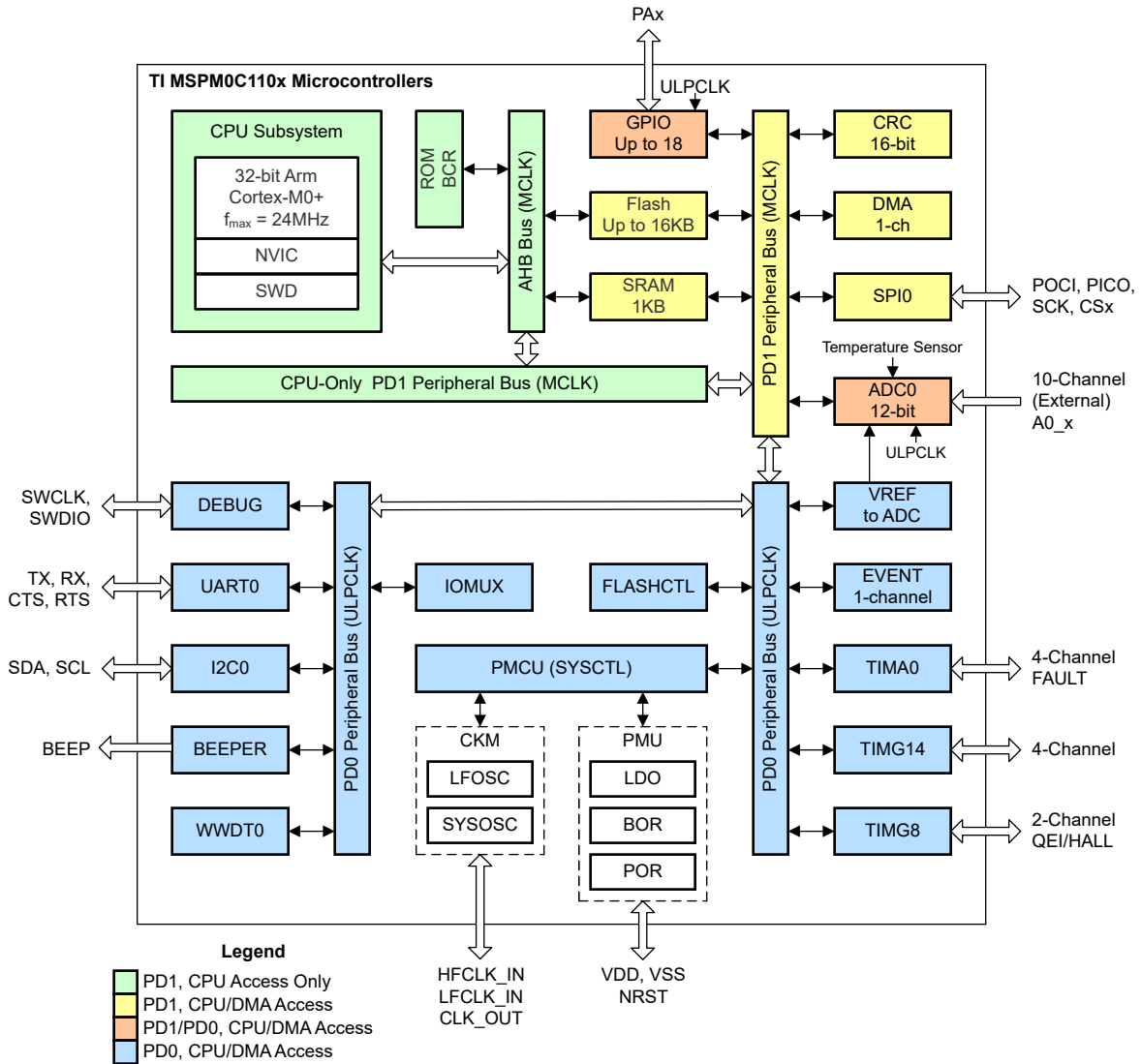


図 4-1. MSPM0C110x の機能ブロック図

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5 Device Comparison

表 5-1. Device Comparison

| DEVICE NAME ^{(1) (3)} | FLASH / SRAM (KB) | ADC CH. | UART / I2C / SPI | TIMG | TIMA | GPIOs | 5V TOL. IO | PACKAGE [PACKAGE SIZE] ⁽²⁾ |
|--------------------------------|-------------------|---------|------------------|------|------|-------|------------|---------------------------------------|
| M0C1104QDGS20RQ1 | 16 / 1 | 10 | 1 / 1 / 1 | 2 | 1 | 18 | 2 | 20 VSSOP [5.1mm × 4.9mm] |
| M0C1103QDGS20RQ1 | 8 / 1 | | | | | | | |
| M0C1104QRUKRQ1 | 16 / 1 | 10 | 1 / 1 / 1 | 2 | 1 | 18 | 2 | 20 WQFN [3mm × 3mm] ⁽⁴⁾ |
| M0C1103QRUKRQ1 | 8 / 1 | | | | | | | |
| M0C1104QDYRQ1 | 16 / 1 | 8 | 1 / 1 / 1 | 2 | 1 | 14 | 2 | 16 SOT [4.2mm × 3.26mm] |
| M0C1103QDYRQ1 | 8 / 1 | | | | | | | |
| M0C1104QDSGRQ1 | 16 / 1 | 3 | 1 / 1 / 1 | 2 | 1 | 6 | 2 | 8 WSON [2mm × 2mm] ⁽⁴⁾ |
| M0C1103QDSGRQ1 | 8 / 1 | | | | | | | |
| M0C1104QDDFRQ1 | 16 / 1 | 3 | 1 / 1 / 1 | 2 | 1 | 6 | 2 | 8 SOT [2.9mm × 2.8mm] |
| M0C1103QDDFRQ1 | 8 / 1 | | | | | | | |

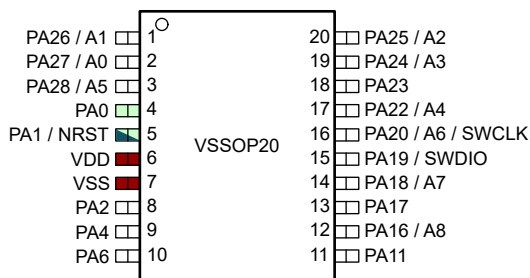
- (1) For the most current part, package, and ordering information for all available devices, see the *Package Option Addendum* in [セクション 12](#), or see the [TI web site](#).
- (2) The package size (length × width) is a nominal value and includes pins, where applicable. For package dimensions with tolerances, see the *Mechanical Data* in [セクション 12](#).
- (3) For more information about the device name, see [セクション 10.1](#).
- (4) The 8-pin WSON and 20-pin WQFN packages are available with wettable flanks.

6 Pin Configuration and Functions

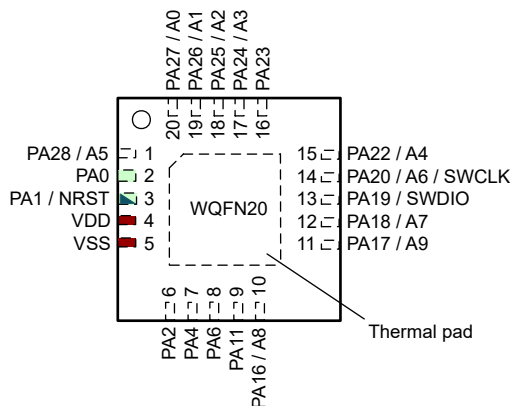
6.1 Pin Diagrams

- Power
- Reset
- 5-V Tolerant Open-Drain I/O (ODIO)

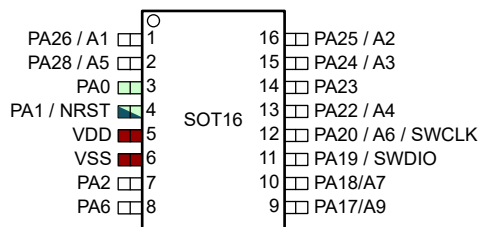
6-1. Pin Diagram Color Coding



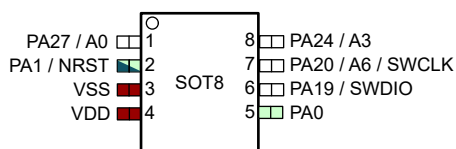
6-2. 20-Pin DGS20 (VSSOP) (Top View)



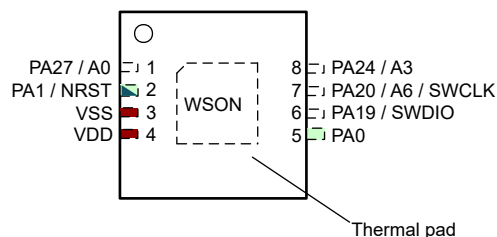
6-3. 20-Pin RUK (WQFN) (Top View)



6-4. 16-Pin DYY (SOT) (Top View)



6-5. 8-Pin DDF (SOT) (Top View)



6-6. 8-Pin DSG (WSO) (Top View)

6.2 Pin Attributes

The following table describes the functions available on every pin for each device package.

注

Each digital I/O on a device is mapped to a specific Pin Control Management Register (PINCMx) that lets users configure the desired *Pin Function* using the PINCM.PF control bits.

表 6-1. Pin Attributes

| PINCMx | PIN FUNCTION | | | PIN NUMBER | | | | | I/O Structure |
|--------|--------------|--------|---|------------|---------|--------|-------|--------|------------------------|
| | PIN NAME | ANALOG | DIGITAL ⁽¹⁾ | 20 VSSOP | 20 WQFN | 16 SOT | 8 SOT | 8 WSON | |
| N/A | | | VDD | 6 | 4 | 5 | 4 | 4 | Power |
| N/A | | | VSS | 7 | 5 | 6 | 3 | 3 | Power |
| 1 | PA0 | | BEEP [2] / I2C0_SDA [3] / TIMG8_C0 [4] / SPI0_CS1 [5] / FCC_IN [6] / TIMA_FAL1 [7] | 4 | 2 | 3 | 5 | 5 | 5V Tolerant Open-Drain |
| 2 | PA1 | | I2C0_SCL [2] / TIM8_C0 [3] / HFCLK_IN [4] / TIMA0_C1 [5] | 5 | 3 | 4 | 2 | 2 | 5V Tolerant Open-Drain |
| N/A | | | NRST | | | | | | Reset |
| 3 | PA2 | | TIMG8_C1[2] / SPI0_CS0[3] / TIMA0_C0[4] / TIMG8_IDX[5] | 8 | 6 | 7 | - | - | Standard |
| 5 | PA4 | | TIMA0_C0N[2] / SPI0_POCI[3] / LFCLK_IN[4] / HFCLK_IN[5] / TIMA0_C1N[6] | 9 | 7 | - | - | - | Standard |
| 7 | PA6 | | TIMG14_C1[2] / SPI0_SCK[3] / TIMA0_C1[4] / TIMG14_C2[5] / SPI0_CS0[6] / TIMA_FAL0[7] | 10 | 8 | 8 | - | - | Standard |
| 12 | PA11 | | SPI0_SCK[2] / I2C0_SCL[3] / TIMA_FAL0[4] | 11 | 9 | - | - | - | Standard |
| 17 | PA16 | A8 | TIMA0_C1N[2] / SPI0_POCI[3] / TIMG14_C0[4] / FCC_IN[5] | 12 | 10 | - | - | - | Standard |
| 18 | PA17 | A9 | UART0_TX[2] / TIMA0_C0N[3] / SPI0_SCK[4] / TIMA0_C2[5] / SPI0_CS1[6] / TIMA0_C3[7] | 13 | 11 | 9 | - | - | Standard |
| 19 | PA18 | A7 | UART0_RX[2] / SPI0_PICO[3] / TIMA0_C1N[4] / CLK_OUT[5] / TIMA0_C3[6] / TIMA0_C3N[7] | 14 | 12 | 10 | - | - | Standard |
| 20 | PA19 | | SWDIO[2] / SPI0_SCK[3] / SPI0_POCI[4] / TIMA0_C2[5] / TIMG14_C0[6] / UART0_CTS[7] | 15 | 13 | 11 | 6 | 6 | Standard |
| 21 | PA20 | A6 | SWCLK[2] / TIMA_FAL1[3] / SPI0_PICO[4] / TIMA0_C2N[5] / TIMA0_C0[6] / UART0_RTS[7] | 16 | 14 | 12 | 7 | 7 | Standard |
| 23 | PA22 | A4 | UART0_RX[2] / SPI0_POCI[3] / UART0_RTS[4] / CLK_OUT[5] / TIMA0_C1[6] | 17 | 15 | 13 | - | - | Standard |
| 24 | PA23 | | UART0_TX[2] / SPI0_CS3[3] / TIMG14_C0[4] / UART0_CTS[5] / TIMA0_C3[6] / TIMG14_C1[7] | 18 | 16 | 14 | - | - | Standard |
| 25 | PA24 | A3 | SPI0_CS2[2] / TIMG14_C1[3] / UART0_RTS[4] / TIMG14_C2[5] / TIMA0_C3N[6] / UART0_RX[7] | 19 | 17 | 15 | 8 | 8 | Standard |
| 26 | PA25 | A2 | TIMG14_C3[2] / UART0_TX[3] / SPI0_PICO[4] / TIMG14_C1[5] / TIMA_FAL2[6] | 20 | 18 | 16 | - | - | Standard |
| 27 | PA26 | A1 | TIMG8_C0[2] / UART0_RX[3] / SPI0_POCI[4] / BEEP[5] / TIMG14_C0[6] / TIMA_FAL0[7] | 1 | 19 | 1 | - | - | Standard |
| 28 | PA27 | A0 | TIMG8_C1[2] / SPI0_CS3[3] / TIMA0_C0N[4] / UART0_TX[5] / SPI0_POCI[6] / TIMA_FAL2[7] | 2 | 20 | - | 1 | 1 | Standard |
| 29 | PA28 | A5 | TIMA0_C0[2] / UART0_RX[3] / TIMG8_IDX[4] | 3 | 1 | 2 | - | - | Standard |

(1) PINCM.PF and PINCM.PC in IOMUX must be set to 0 for analog functions like ADC inputs. Each digital I/O on a device is mapped to a specific Pin Control Management Register (PINCMx) that lets users configure the desired *Pin Function* using the PINCM.PF control bits.

表 6-2. Digital IO Features by IO Type

| IO Structure | INVERSION CONTROL | DRIVE STRENGTH CONTROL | HYSTERESIS CONTROL | PULLUP RESISTOR | PULLDOWN RESISTOR |
|------------------------|-------------------|------------------------|--------------------|-----------------|-------------------|
| Standard-drive | Y | | | Y | Y |
| 5V tolerant open-drain | Y | | Y | | Y |

6.3 Signal Descriptions

| FUNCTION | SIGNAL NAME | PIN NO. ⁽¹⁾ | | | | | PIN TYPE ⁽²⁾ | DESCRIPTION |
|------------------|-------------|------------------------|---------|--------|-------|--------|-----------------------------|--|
| | | 20 VSSOP | 20 WQFN | 16 SOT | 8 SOT | 8 WSON | | |
| ADC | A0 | 2 | 20 | - | 1 | 1 | I | ADC0 analog input 0 |
| | A1 | 1 | 19 | 1 | - | - | I | ADC0 analog input 1 |
| | A2 | 20 | 18 | 16 | - | - | I | ADC0 analog input 2 |
| | A3 | 19 | 17 | 15 | 8 | 8 | I | ADC0 analog input 3 |
| | A4 | 17 | 15 | 13 | - | - | I | ADC0 analog input 4 |
| | A5 | 3 | 1 | 2 | - | - | I | ADC0 analog input 5 |
| | A6 | 16 | 14 | 12 | 7 | 7 | I | ADC0 analog input 6 |
| | A7 | 14 | 12 | 10 | - | - | I | ADC0 analog input 7 |
| | A8 | 12 | 10 | - | - | - | I | ADC0 analog input 8 |
| | A9 | 13 | 11 | 9 | - | - | I | ADC0 analog input 9 |
| Clock | CLK_OUT | 14, 17 | 12, 15 | 10, 13 | - | - | O | Configurable clock output |
| Debug | SWDIO | 15 | 14 | 11 | 6 | 6 | I/O | Serial wire debug data input/output |
| | SWCLK | 16 | 13 | 12 | 7 | 7 | I | Serial wire debug input clock |
| GPIO | PA0 | 4 | 2 | 3 | 5 | 5 | I/O | General-purpose digital I/O with open-drain capability |
| | PA1 | 5 | 3 | 4 | 2 | 2 | I/O | General-purpose digital I/O with open-drain capability |
| | PA2 | 8 | 6 | 7 | - | - | I/O | General-purpose digital I/O |
| | PA4 | 9 | 7 | - | - | - | I/O | General-purpose digital I/O |
| | PA6 | 10 | 8 | 8 | - | - | I/O | General-purpose digital I/O |
| | PA11 | 11 | 9 | - | - | - | I/O | General-purpose digital I/O |
| | PA16 | 12 | 10 | - | - | - | I/O | General-purpose digital I/O |
| | PA17 | 13 | 11 | 9 | - | - | I/O | General-purpose digital I/O |
| | PA18 | 14 | 12 | 10 | - | - | I/O | General-purpose digital I/O |
| | PA19 | 15 | 13 | 11 | 6 | 6 | I/O | General-purpose digital I/O |
| | PA20 | 16 | 14 | 12 | 7 | 7 | I/O | General-purpose digital I/O |
| | PA22 | 17 | 15 | 13 | - | - | I/O | General-purpose digital I/O |
| | PA23 | 18 | 16 | 14 | - | - | I/O | General-purpose digital I/O |
| | PA24 | 19 | 17 | 15 | 8 | 8 | I/O | General-purpose digital I/O |
| | PA25 | 20 | 18 | 16 | - | - | I/O | General-purpose digital I/O |
| | PA26 | 1 | 19 | 1 | - | - | I/O | General-purpose digital I/O |
| | PA27 | 2 | 20 | - | 1 | 1 | I/O | General-purpose digital I/O |
| PA28 | 3 | 1 | 2 | - | - | I/O | General-purpose digital I/O | |
| I ² C | I2C0_SCL | 5, 11 | 3, 9 | 4 | 2 | 2 | I/O | I2C0 serial clock |
| | I2C0_SDA | 4 | 2 | 3 | 5 | 5 | I/O | I2C0 serial data |

| FUNCTION | SIGNAL NAME | PIN NO. ⁽¹⁾ | | | | | PIN TYPE ⁽²⁾ | DESCRIPTION |
|-----------|-------------|------------------------|-----------------------|-----------|-------|--------|-----------------------------------|--|
| | | 20 VSSOP | 20 WQFN | 16 SOT | 8 SOT | 8 WSON | | |
| Power | VSS | 7 | 5 | 6 | 3 | 3 | P | Ground supply |
| | VDD | 6 | 4 | 5 | 4 | 4 | P | Power supply |
| | QFN Pad | - | Pad | - | - | Pad | P | QFN package exposed thermal pad. TI recommends connection to V _{SS} . |
| SPI | SPI0_CS0 | 8 | 6 | 7 | - | - | I/O | SPI0 chip-select 0 |
| | SPI0_CS1 | 4, 13 | 2, 11 | 3, 9 | 5 | 5 | I/O | SPI0 chip-select 1 |
| | SPI0_CS2 | 19 | 17 | 15 | 8 | 8 | I/O | SPI0 chip-select 2 |
| | SPI0_CS3 | 2, 18 | 16, 20 | 14 | 1 | 1 | I/O | SPI0 chip-select 3 |
| | SPI0_SCK | 10, 11, 13, 15 | 8, 9, 11, 13 | 8, 9, 11 | 6 | 6 | I/O | SPI0 clock signal input – SPI peripheral mode Clock signal output – SPI controller mode |
| | SPI0_POCI | 1, 2, 9, 12, 15, 17 | 7, 10, 13, 15, 19, 20 | 1, 11, 13 | 1, 6 | 1, 6 | I/O | SPI0 controller in/peripheral out |
| SPI0_PICO | 14, 16, 20 | 12, 14, 18 | 10, 12, 16 | 7 | 7 | I/O | SPI0 controller out/peripheral in | |
| System | NRST | 5 | 3 | 4 | 2 | 2 | I | Reset input active low |

| FUNCTION | SIGNAL NAME | PIN NO. ⁽¹⁾ | | | | | PIN TYPE ⁽²⁾ | DESCRIPTION |
|-----------|-------------|------------------------|---------------------|------------------|-------|--------|--|--|
| | | 20 VSSOP | 20 WQFN | 16 SOT | 8 SOT | 8 WSON | | |
| Timer | TIMA_FAL0 | 1, 10, 11 | 8, 9, 19 | 1, 8 | - | - | I/O | Advanced control timer fault 0 handling input |
| | TIMA_FAL1 | 4, 16 | 2, 14 | 3, 12 | 5, 7 | 5, 7 | I/O | Advanced control timer fault 1 handling input |
| | TIMA_FAL2 | 2, 20 | 18, 20 | 16 | 1 | 1 | I/O | Advanced control timer fault 2 handling input |
| | TIMA0_C0 | 2, 3, 8, 9, 13, 16 | 1, 6, 7, 11, 14, 20 | 2, 7, 9, 12 | 1, 7 | 1, 7 | I/O | Advanced control timer 0 CCR0 capture input/compare output |
| | TIMA0_C0N | 2, 9, 13 | 7, 11, 20 | 9 | 1 | 1 | I/O | Advanced control timer 0 CCR0 capture input/compare output (inverting) |
| | TIMA0_C1 | 5, 9, 10, 12, 14, 17 | 3, 7, 8, 10, 12, 15 | 4, 8, 10, 13 | 2 | 2 | I/O | Advanced control timer 0 CCR1 capture input/compare output |
| | TIMA0_C1N | 9, 12, 14 | 7, 10, 12 | 10 | - | - | I/O | Advanced control timer 0 CCR1 capture input/compare output (inverting) |
| | TIMA0_C2 | 13, 15, 16 | 11, 13, 14 | 9, 11, 12 | 6, 7 | 6, 7 | I/O | Advanced control timer 0 CCR2 capture input/compare output |
| | TIMA0_C2N | 16 | 14 | 12 | 7 | 7 | I/O | Advanced control timer 0 CCR2 capture input/compare output (inverting) |
| | TIMA0_C3 | 13, 14, 18, 19 | 11, 12, 16, 17 | 9, 10, 14, 15 | 8 | 8 | I/O | Advanced control timer 0 CCR3 capture input/compare output |
| | TIMA0_C3N | 14, 19 | 12, 17 | 10, 15 | 8 | 8 | I/O | Advanced control timer 0 CCR3 capture input/compare output (inverting) |
| | TIMG14_C0 | 1, 12, 15, 18 | 10, 13, 16, 19 | 1, 11, 14 | 6 | 6 | I/O | General purpose timer 0 CCR0 capture input/compare output |
| | TIMG14_C1 | 10, 18, 19, 20 | 8, 16, 17, 18 | 8, 14, 15, 16 | 8 | 8 | I/O | General purpose timer 0 CCR1 capture input/compare output |
| | TIMG14_C2 | 10, 19 | 8, 17 | 8, 15 | 8 | 8 | I/O | General purpose timer 0 CCR2 capture input/compare output |
| | TIMG14_C3 | 20 | 18 | 16 | - | - | I/O | General purpose timer 0 CCR3 capture input/compare output |
| | TIMG8_C0 | 1, 4 | 2, 19 | 1, 3 | 5 | 5 | I/O | General purpose timer 8 CCR0 capture input/compare output |
| | TIMG8_C1 | 2, 5, 8 | 3, 6, 20 | 4, 7 | 1, 2 | 1, 2 | I/O | General purpose timer 8 CCR1 capture input/compare output |
| TIMG8_IDX | 3, 8 | 1, 6 | 2, 7 | - | - | I | General purpose timer 8 quadrature encoder index pulse input | |
| UART | UART0_TX | 2, 13, 18, 20 | 11, 16, 18, 20 | 9, 14, 16 | 1 | 1 | O | UART0 transmit data |
| | UART0_RX | 1, 3, 14, 17, 19 | 1, 12, 15, 17, 19 | 1, 2, 10, 13, 15 | 8 | 8 | I | UART0 receive data |
| | UART0_CTS | 15, 18 | 13, 16 | 11, 14 | 6 | 6 | I | UART0 "clear to send" flow control input |
| | UART0_RTS | 16, 17, 19 | 14, 15, 17 | 12, 13, 15 | 7, 8 | 7, 8 | O | UART0 "request to send" flow control output |
| Beeper | BEEP | 1, 4 | 2, 19 | 1, 3 | 5 | 5 | O | Beep output |

| FUNCTION | SIGNAL NAME | PIN NO. ⁽¹⁾ | | | | | PIN TYPE ⁽²⁾ | DESCRIPTION |
|----------|-------------|------------------------|---------|--------|-------|--------|-------------------------|-------------------------------|
| | | 20 VSSOP | 20 WQFN | 16 SOT | 8 SOT | 8 WSON | | |
| FCC | FCC_IN | 4, 12 | 2, 10 | 3 | 5 | 6 | I | Frequency clock counter input |

6.4 Connections for Unused Pins

表 6-3 lists the correct termination of unused pins.

表 6-3. Connection of Unused Pins

| PIN ⁽¹⁾ | POTENTIAL | COMMENT |
|--------------------|-----------|---|
| PAX | Open | Set corresponding pin functions to GPIO (PINCMx.PF = 0x1) and configure unused pins to output low or input with internal pullup or pulldown resistor. |
| NRST | VCC | NRST is an active-low reset signal. Pull high to VCC or the device cannot start. For more information, see セクション 9.1 . |

(1) Any unused pin with a function that is shared with general-purpose I/O must follow the "PAX" unused pin connection guidelines.

7 Specifications

7.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

| | | | MIN | MAX | UNIT |
|------------------|-------------------------|---|------|------------------------------------|------|
| VDD | Supply voltage | At VDD pin | -0.3 | 4.1 | V |
| V _I | Input voltage | Applied to any 5-V tolerant open-drain pins | -0.3 | 5.5 | V |
| V _I | Input voltage | Applied to any common tolerance pins | -0.3 | V _{DD} + 0.3 (4.1 MAX) | V |
| I _{VDD} | Current of VDD pin | Current into VDD pin (source), VDD ≥ 2.7V, -40 °C ≤ T _a ≤ 85 °C | | 80 | mA |
| I _{VSS} | Current of VSS pin | Current out of VSS pin (sink), VDD ≥ 2.7V, -40 °C ≤ T _a ≤ 85 °C | | 80 | mA |
| I _{VDD} | Current of VDD pin | Current into VDD pin (source), VDD ≥ 2.7V, -40 °C ≤ T _a ≤ 125 °C | | 48 | mA |
| I _{VSS} | Current of VSS pin | Current out of VSS pin (sink), VDD ≥ 2.7V, -40 °C ≤ T _a ≤ 125 °C | | 48 | mA |
| I _{IO} | Current for SDIO pin | Current sunk or sourced by SDIO pin, VDD ≥ 2.7V | | 6 | mA |
| | Current for ODIO pin | Current sunk by ODIO pin | | 20 | mA |
| I _D | Supported diode current | Diode current at any device pin except PA0, PA1 and PA24 | | ±2 ⁽²⁾ | mA |
| T _{stg} | | Storage temperature | -40 | 150 | °C |

- (1) Stresses beyond those listed under *Absolute Maximum Rating* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Condition*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) Open drain IOs PA0 and PA1 do not have the high side clamps, and PA24 has an internal connection for the testing purpose, there is no injection current allowed on these pins.

7.2 ESD Ratings

| | | | VALUE | UNIT |
|--------------------|-------------------------|---|-------|------|
| V _(ESD) | Electrostatic discharge | Human body model (HBM), per AEC Q100-002, all pins ⁽¹⁾ | ±2000 | V |
| V _(ESD) | Electrostatic discharge | Charged device model (CDM), per pAEC Q100-011, all pins | ±500 | V |
| V _(ESD) | Electrostatic discharge | Charged device model (CDM), per AEC-Q100-011, Corner pins | ±750 | V |

- (1) AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

7.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

| | | | MIN | NOM | MAX | UNIT |
|-------------------|--|--|------|-----|-----|------|
| VDD | Supply voltage | | 1.62 | | 3.6 | V |
| C _{VDD} | Capacitor placed between VDD and VSS ⁽¹⁾ | | | 10 | | uF |
| T _A | Ambient temperature | | -40 | | 125 | °C |
| T _J | Max junction temperature | | | | 130 | °C |
| f _{MCLK} | MCLK, CPUCLK, ULPCLK frequency with 0 flash wait states ⁽²⁾ | | | | 24 | MHz |

- (1) Connect C_{VDD} between VDD/VSS, as close to the device pins as possible. A low-ESR capacitor with at least the specified value and tolerance of ±20% or better is required for C_{VDD}.
- (2) Wait states are managed automatically by the system controller (SYSCTL) and do not need to be configured by application software.

7.4 Thermal Information

| THERMAL METRIC ⁽¹⁾ | | PACKAGE | VALUE | UNIT |
|-------------------------------|--|------------------|-------|------|
| R _{θJA} | Junction-to-ambient thermal resistance | VSSOP-20 (DGS20) | 91.3 | °C/W |
| R _{θJC(top)} | Junction-to-case (top) thermal resistance | | 29.3 | °C/W |
| R _{θJB} | Junction-to-board thermal resistance | | 48.3 | °C/W |
| Ψ _{JT} | Junction-to-top characterization parameter | | 0.7 | °C/W |
| Ψ _{JB} | Junction-to-board characterization parameter | | 47.9 | °C/W |
| R _{θJC(bot)} | Junction-to-case (bottom) thermal resistance | | N/A | °C/W |
| R _{θJA} | Junction-to-ambient thermal resistance | WQFN-20 (RUK) | 52.9 | °C/W |
| R _{θJC(top)} | Junction-to-case (top) thermal resistance | | 55.5 | °C/W |
| R _{θJB} | Junction-to-board thermal resistance | | 26.4 | °C/W |
| Ψ _{JT} | Junction-to-top characterization parameter | | 2.1 | °C/W |
| Ψ _{JB} | Junction-to-board characterization parameter | | 26.4 | °C/W |
| R _{θJC(bot)} | Junction-to-case (bottom) thermal resistance | | 12.0 | °C/W |
| R _{θJA} | Junction-to-ambient thermal resistance | SOT-16 (DYY) | 117.1 | °C/W |
| R _{θJC(top)} | Junction-to-case (top) thermal resistance | | 54.5 | °C/W |
| R _{θJB} | Junction-to-board thermal resistance | | 54.6 | °C/W |
| Ψ _{JT} | Junction-to-top characterization parameter | | 3.0 | °C/W |
| Ψ _{JB} | Junction-to-board characterization parameter | | 54.5 | °C/W |
| R _{θJC(bot)} | Junction-to-case (bottom) thermal resistance | | N/A | °C/W |
| R _{θJA} | Junction-to-ambient thermal resistance | SOT-8 (DDF) | 142.3 | °C/W |
| R _{θJC(top)} | Junction-to-case (top) thermal resistance | | 65.7 | °C/W |
| R _{θJB} | Junction-to-board thermal resistance | | 62.7 | °C/W |
| Ψ _{JT} | Junction-to-top characterization parameter | | 3.2 | °C/W |
| Ψ _{JB} | Junction-to-board characterization parameter | | 62.5 | °C/W |
| R _{θJC(bot)} | Junction-to-case (bottom) thermal resistance | | N/A | °C/W |
| R _{θJA} | Junction-to-ambient thermal resistance | WSON-8 (DSG) | 70.7 | °C/W |
| R _{θJC(top)} | Junction-to-case (top) thermal resistance | | 85.6 | °C/W |
| R _{θJB} | Junction-to-board thermal resistance | | 37.5 | °C/W |
| Ψ _{JT} | Junction-to-top characterization parameter | | 2.7 | °C/W |
| Ψ _{JB} | Junction-to-board characterization parameter | | 37.5 | °C/W |
| R _{θJC(bot)} | Junction-to-case (bottom) thermal resistance | | 12.8 | °C/W |

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

7.5 Supply Current Characteristics

7.5.1 RUN/SLEEP Modes

VDD=3.3V. All inputs tied to 0V or VDD. Outputs do not source or sink any current. All peripherals are disabled.

| PARAMETER | MCLK | -40°C | | 25°C | | 85°C | | 125°C | | UNIT | |
|-------------------|---|-------|------|------|------|------|------|-------|------|------|--------|
| | | TYP | MAX | TYP | MAX | TYP | MAX | TYP | MAX | | |
| RUN Mode | | | | | | | | | | | |
| IDDRUN | MCLK=SYSOSC, While(1), execute from flash | 24MHz | 2.06 | 2.20 | 2.08 | 2.35 | 2.09 | 2.40 | 2.21 | 2.45 | mA |
| IDDRUN, per MHz | MCLK=SYSOSC, While(1), execute from flash | 24MHz | 86 | 92 | 87 | 98 | 87 | 100 | 92 | 102 | uA/Mhz |
| SLEEP Mode | | | | | | | | | | | |

7.5.1 RUN/SLEEP Modes (続き)

VDD=3.3V. All inputs tied to 0V or VDD. Outputs do not source or sink any current. All peripherals are disabled.

| PARAMETER | | MCLK | -40°C | | 25°C | | 85°C | | 125°C | | UNIT |
|-----------|----------------------------|-------|-------|------|------|------|------|------|-------|------|------|
| | | | TYP | MAX | TYP | MAX | TYP | MAX | TYP | MAX | |
| IDDSLEEP | MCLK=SYSOSC, CPU is halted | 24MHz | 1115 | 1256 | 1132 | 1268 | 1149 | 1380 | 1214 | 1680 | uA |

7.5.2 STOP/STANDBY Modes

VDD=3.3V unless otherwise noted. All inputs tied to 0V or VDD. Outputs do not source or sink any current. All peripherals not noted are disabled.

| PARAMETER | | ULPCLK | -40°C | | 25°C | | 85°C | | 125°C | | UNIT |
|---------------------|--|--------|-------|-----|------|-----|------|------|-------|-----|------|
| | | | TYP | MAX | TYP | MAX | TYP | MAX | TYP | MAX | |
| STOP Mode | | | | | | | | | | | |
| IDDSTOP0 | SYSOSC=24MHz, DISABLESTOP=0 | 4MHz | 598 | 640 | 609 | 646 | 622 | 710 | 662 | 733 | uA |
| IDDSTOP2 | SYSOSC off, DISABLESTOP=1, ULPCLK=LFCLK | 32kHz | 305 | 343 | 311 | 346 | 324 | 359 | 364 | 430 | |
| STANDBY Mode | | | | | | | | | | | |
| IDDSTBY0 | STOPCLKSTBY=0, TIMG8, TIMG14 and TIMA0 enabled | 32kHz | 3.8 | 8.3 | 5.1 | 14 | 17.8 | 35.4 | 57.4 | 93 | uA |
| IDDSTBY1 | STOPCLKSTBY=1, TIMG8, TIMG14 and TIMA0 enabled | | 3.4 | 8.5 | 5.1 | 14 | 17.5 | 35.1 | 57 | 93 | |
| | STOPCLKSTBY=1, GPIOA enabled | | 3.4 | 8.5 | 5.0 | 14 | 17.5 | 35.2 | 57 | 93 | |

7.5.3 SHUTDOWN Mode

All inputs tied to 0V or VDD. Outputs do not source or sink any current. Core regulator is powered down.

| PARAMETER | | VDD | -40°C | | 25°C | | 85°C | | 125°C | | UNIT |
|-----------|---------------------------------|------|-------|-----|------|-----|------|-----|-------|------|------|
| | | | TYP | MAX | TYP | MAX | TYP | MAX | TYP | MAX | |
| IDDSHDN | Supply current in SHUTDOWN mode | 3.3V | 140 | 320 | 200 | 350 | 428 | 932 | 1933 | 4680 | nA |

7.6 Power Supply Sequencing

7.6.1 POR and BOR

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------------|---|-----------------------------------|------|-------|-------|------|
| dVDD/dt | VDD (supply voltage) slew rate | Rising | | | 0.1 | V/us |
| | | Falling ⁽²⁾ | | | 0.01 | |
| | | Falling, STANDBY | | | 0.1 | V/ms |
| V _{POR+} | Power-on reset voltage level | Rising ⁽¹⁾ | 0.92 | 1.284 | 1.59 | V |
| V _{POR-} | | Falling ⁽¹⁾ | 0.87 | 1.236 | 1.54 | V |
| V _{HYS, POR} | POR hysteresis | ⁽¹⁾ | 16 | 47 | 80 | mV |
| V _{BOR0+, COLD} | Brown-out reset voltage level 0 (default level) | Cold start, rising ⁽¹⁾ | 1.45 | 1.54 | 1.615 | V |
| V _{BOR0+} | | Rising ^{(1) (2)} | 1.57 | 1.59 | 1.61 | |
| V _{BOR0-} | | Falling ^{(1) (2)} | 1.56 | 1.57 | 1.60 | |
| V _{BOR0, STBY} | Brown-out reset voltage level 0 (default level) | STANDBY mode ⁽¹⁾ | 1.52 | 1.57 | 1.60 | V |
| V _{BOR1+} | Brown-out-reset voltage level 1 | Rising ^{(1) (2)} | 2.15 | 2.17 | 2.23 | V |
| V _{BOR1-} | | Falling ^{(1) (2)} | 2.11 | 2.14 | 2.19 | |
| V _{BOR1, STBY} | Brown-out-reset voltage level 1 | STANDBY mode ⁽¹⁾ | 2.07 | 2.14 | 2.19 | V |

7.6.1 POR and BOR (続き)

over operating free-air temperature range (unless otherwise noted)

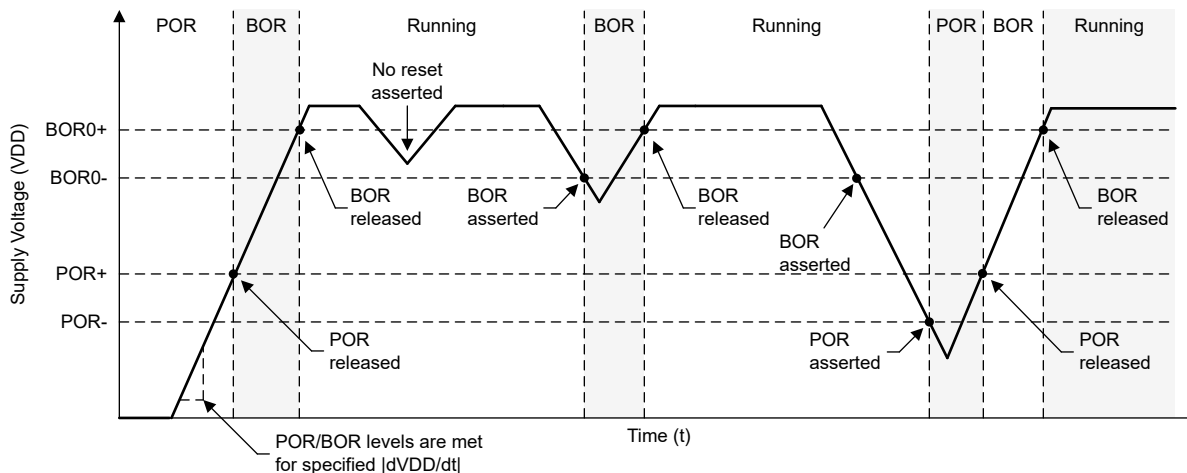
| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-------------------------|---------------------------------|---------------------------------------|------|------|------|------|
| V _{BOR2+} | Brown-out-reset voltage level 2 | Rising ⁽¹⁾ ⁽²⁾ | 2.74 | 2.77 | 2.83 | V |
| V _{BOR2-} | | Falling ⁽¹⁾ ⁽²⁾ | 2.71 | 2.73 | 2.80 | |
| V _{BOR2, STBY} | Brown-out-reset voltage level 2 | STANDBY mode ⁽¹⁾ | 2.67 | 2.73 | 2.80 | V |
| V _{BOR3+} | Brown-out-reset voltage level 3 | Rising ⁽¹⁾ ⁽²⁾ | 2.88 | 2.96 | 3.04 | V |
| V _{BOR3-} | | Falling ⁽¹⁾ ⁽²⁾ | 2.85 | 2.93 | 3.01 | |
| V _{BOR3, STBY} | Brown-out-reset voltage level 3 | STANDBY mode ⁽¹⁾ | 2.83 | 2.92 | 3.00 | V |
| V _{HYS,BOR} | Brown-out reset hysteresis | Level 0 ⁽¹⁾ | | 14 | 18 | mV |
| | | Levels 1-3 ⁽¹⁾ | | 34 | 41 | |
| T _{PD, BOR} | BOR propagation delay | RUN/SLEEP/STOP mode | | | 10 | us |
| | | STANDBY mode | | | 100 | us |

(1) |dVDD/dt| ≤ 3V/s

(2) Device operating in RUN, SLEEP, or STOP mode.

7.6.2 Power Supply Ramp

☒ 7-1 gives the relationship of POR-, POR+, BOR0-, and BOR0+ during power-up and power-down.



☒ 7-1. Power Cycle POR/BOR Conditions

7.7 Flash Memory Characteristics

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|--------------------------|--|------|-----|-----|--------------------|
| Supply | | | | | |
| V _{DDPGM/ERASE} | Program and erase supply voltage | 1.62 | | 3.6 | V |
| I _{DDERASE} | Supply current from VDD during erase operation | | 2 | | mA |
| I _{DDPGM} | Supply current from VDD during program operation | | 2.5 | | mA |
| Endurance | | | | | |
| NWEC _(LOWER) | Erase/program cycle endurance | 100 | | | k cycles |
| NE _(MAX) | Total erase operations before failure ⁽¹⁾ | 802 | | | k erase operations |

7.7 Flash Memory Characteristics (続き)

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------------|---|--------------------------------|------|-----|-----|------------------|
| NW _(MAX) | Write operations per word line before sector erase ⁽¹⁾ | | | | 83 | write operations |
| Retention | | | | | | |
| t _{RET_85} | Flash memory data retention | -40°C ≤ T _j ≤ 85°C | 60 | | | years |
| t _{RET_105} | Flash memory data retention | -40°C ≤ T _j ≤ 105°C | 11.4 | | | years |
| t _{RET_130} | Flash memory data retention | -40°C ≤ T _j ≤ 130°C | 2.4 | | | years |
| Program and Erase Timing | | | | | | |
| t _{PROG (WORD, 64)} | Program time for flash word ⁽²⁾ | | | 40 | | μs |
| t _{PROG (SEC, 64)} | Program time for 1kB sector | | | 5.1 | | ms |
| t _{ERASE (SEC)} | Sector erase time | <10k erase/program cycles | | 20 | 200 | ms |
| t _{ERASE (BANK)} | Bank erase time | <10k erase/program cycles | | 22 | 220 | ms |

- (1) Maximum number of write operations allowed per word line before the word line must be erased. If additional writes to the same word line are required, a sector erase is required once the maximum number of write operations per word line is reached.
- (2) Sector program time is defined as the time from when the first word program command is triggered until the final word program command completes and the interrupt flag is set in the flash controller. This time includes the time needed for software to load each flash word (after the first flash word) into the flash controller during programming of the sector.

7.8 Timing Characteristics

VDD=3.3V, T_a=25 °C (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---|---|------------------|-----|-----|-----|--------|
| Wakeup Timing | | | | | | |
| t _{WAKE, SLEEP} | Wakeup time from SLEEP to RUN | | | 2 | | cycles |
| t _{WAKE, STOP} | Wakeup time from STOP0 to RUN (SYSOSC enabled) | | | 14 | | us |
| | Wakeup time from STOP2 to RUN (SYSOSC disabled) | | | 15 | | us |
| t _{WAKE, STBY} | Wakeup time from STANDBY to RUN | | | 20 | | us |
| t _{WAKE, SHDN} | Wakeup time from SHUTDOWN to RUN | | | 112 | | us |
| Asynchronous Fast Clock Request Timing | | | | | | |
| t _{DELAY} | Delay time from edge of asynchronous request to first 24MHz MCLK edge | Mode is SLEEP2 | | 1.2 | | us |
| | | Mode is STOP2 | | 1.2 | | us |
| | | Mode is STANDBY1 | | 5.0 | | us |
| Startup Timing | | | | | | |
| t _{START, RESET} | Device cold start-up time from reset/ power-up ⁽¹⁾ | | | 210 | | us |
| NRST Timing | | | | | | |
| t _{RST, BOOTRST} | Pulse length on NRST pin to generate BOOTRST | ULPCLK≥4MHz | | 2 | | us |
| | | ULPCLK=32kHz | | 100 | | us |
| t _{RST, POR} | Pulse length on NRST pin to generate POR | | | 1 | | s |

- (1) The start-up time is measured from the time that VDD crosses VBOR0+ (cold start-up) to the time that the first instruction of the user program is executed.

7.9 Clock Specifications

7.9.1 System Oscillator (SYSOSC)

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-----------------------------|--|---|------|-----|-----|------|
| f_{SYSOSC} | Factory trimmed SYSOSC frequency | SYSOSCCFG.FREQ=00 (BASE) | | 24 | | MHz |
| f_{SYSOSC} | SYSOSC frequency accuracy when frequency correction loop (FCL) is enabled when the internal ROSC resistor is used ⁽¹⁾ | SETUSEFCL=1, $T_a = 25\text{ }^\circ\text{C}$ | -1.2 | | 1.2 | % |
| | | SETUSEFCL=1, $0\text{ }^\circ\text{C} \leq T_a \leq 85\text{ }^\circ\text{C}$ | -1.6 | | 1.4 | |
| | | SETUSEFCL=1 $-40\text{ }^\circ\text{C} \leq T_a \leq 125\text{ }^\circ\text{C}$ | -2 | | 1.4 | |
| f_{SYSOSC} | SYSOSC accuracy when frequency correction loop (FCL) is disabled, 24MHz | SETUSEFCL=0, SYSOSCCFG.FREQ=00, $-40\text{ }^\circ\text{C} \leq T_a \leq 125\text{ }^\circ\text{C}$ | -2.5 | | 2.5 | % |
| $t_{\text{settle, SYSOSC}}$ | Settling time to target accuracy ⁽²⁾ | SETUSEFCL=1 | | | 30 | us |

- (1) The SYSOSC frequency correction loop (FCL) enables high SYSOSC accuracy via an internal reference resistor when using the FCL. See the SYSOSC section of the technical reference manual for details on computing SYSOSC accuracy.
- (2) When SYSOSC is enabled from a disabled state, the SYSOSC output will be released to the device within the time specified by $t_{\text{start, SYSOSC}}$. Once the output is released, the SYSOSC worst-case accuracy is specified by $f_{\text{settle, SYSOSC}}$. After the time specified by $t_{\text{settle, SYSOSC}}$, the SYSOSC will have settled to the target f_{SYSOSC} accuracy.

7.9.2 Low Frequency Oscillator (LFOSC)

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------|---------------------------|---|-----|-------|-----|------|
| f_{LFOSC} | LFOSC frequency | | | 32768 | | Hz |
| f_{LFOSC} | LFOSC accuracy | $-40\text{ }^\circ\text{C} \leq T_a \leq 125\text{ }^\circ\text{C}$ | -5 | | 5 | % |
| f_{LFOSC} | LFOSC accuracy | $-40\text{ }^\circ\text{C} \leq T_a \leq 85\text{ }^\circ\text{C}$ | -3 | | 3 | % |
| I_{LFOSC} | LFOSC current consumption | | | 300 | | nA |
| $t_{\text{start, LFOSC}}$ | LFOSC start-up time | | | 1.7 | | ms |

7.10 Digital IO

7.10.1 Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|------------------|--------------------------|------------------------------------|-----------------------------------|----------------------------|-----|---------------------------|------------|
| V_{IH} | High level input voltage | ODIO ⁽¹⁾ | $V_{\text{DD}} \geq 1.62\text{V}$ | $0.7 \cdot V_{\text{DD}}$ | | 5.5 | V |
| | | ODIO ⁽¹⁾ | $V_{\text{DD}} \geq 2.7\text{V}$ | 2 | | 5.5 | V |
| | | All I/O except ODIO & Reset | $V_{\text{DD}} \geq 1.62\text{V}$ | $0.7 \cdot V_{\text{DD}}$ | | $V_{\text{DD}} + 0.3$ | V |
| V_{IL} | Low level input voltage | ODIO | $V_{\text{DD}} \geq 1.62\text{V}$ | -0.3 | | $0.3 \cdot V_{\text{DD}}$ | V |
| | | ODIO | $V_{\text{DD}} \geq 2.7\text{V}$ | -0.3 | | 0.8 | V |
| | | All I/O except ODIO & Reset | $V_{\text{DD}} \geq 1.62\text{V}$ | -0.3 | | $0.3 \cdot V_{\text{DD}}$ | V |
| V_{HYS} | Hysteresis | ODIO | | $0.05 \cdot V_{\text{DD}}$ | | | V |
| | | All I/O except ODIO | | $0.1 \cdot V_{\text{DD}}$ | | | V |
| I_{lk} | High-Z leakage current | SDIO ⁽²⁾ ⁽³⁾ | $V_{\text{DD}} = 3\text{V}$ | | | 50 | nA |
| R_{PU} | Pull up resistance | All I/O except ODIO | $V_{\text{IN}} = V_{\text{SS}}$ | | 40 | | k Ω |
| R_{PD} | Pull down resistance | | $V_{\text{IN}} = V_{\text{DD}}$ | | 40 | | k Ω |
| C_{I} | Input capacitance | | $V_{\text{DD}} = 3.3\text{V}$ | | 5 | | pF |

7.10.1 Electrical Characteristics (続き)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|-----------------|---------------------------|-----------------|---|---------|-----|-----|------|
| V _{OH} | High level output voltage | SDIO | VDD ≥ 2.7V, I _{IO} _{max} = 6mA | VDD-0.5 | | | V |
| V _{OH} | High level output voltage | SDIO | VDD ≥ 1.71V, I _{IO} _{max} = 2mA | VDD-0.4 | | | V |
| V _{OL} | Low level output voltage | SDIO | VDD ≥ 2.7V, I _{IO} _{max} = 6mA VDD ≥ 1.71V, I _{IO} _{max} = 2mA | | | 0.4 | V |
| V _{OL} | Low level output voltage | ODIO | VDD ≥ 2.7V, I _{OL,max} = 8mA VDD ≥ 1.71V, I _{OL,max} = 4mA | | | 0.5 | V |

- (1) I/O Types: ODIO = 5V Tolerant Open-Drain , SDIO = Standard-Drive , HSIO = High-Speed
- (2) The leakage current is measured with VSS or VDD applied to the corresponding pin(s), unless otherwise noted.
- (3) The leakage of the digital port pins is measured individually. The port pin is selected for input and the pullup/pulldown resistor is disabled.

7.10.2 Switching Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|---------------------------------|-----------------------|------------------------------|--|------------|-----|----------------------|------|
| f _{max} | Port output frequency | SDIO (1) | VDD ≥ 1.71V, C _L = 20pF | | | 24 | MHz |
| f _{max} | Port output frequency | ODIO | VDD ≥ 1.71V, FM ⁺ , CL = 20pF - 100pF | | | 1 | MHz |
| t _r , t _f | Output rise/fall time | All output ports except ODIO | VDD ≥ 1.71V | | | 0.3*f _{max} | s |
| t _f | Output fall time | ODIO | VDD ≥ 1.71V, FM ⁺ , CL = 20pF-100pF | 20*VDD/5.5 | | 120 | ns |

- (1) I/O Types: ODIO = 5V Tolerant Open-Drain , SDIO = Standard-Drive , HSIO = High-Speed , HDIO = High-Drive

7.11 ADC

7.11.1 Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted), all TYP values are measured at 25°C and all accuracy parameters are measured using 12-bit resolution mode (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|----------------------|--|---|--|-----|------|-------|------|
| V _{IN(ADC)} | Analog input voltage range(1) | Applies to all ADC analog input pins | | 0 | | VDD | V |
| V _{R+} | Positive ADC reference voltage | V _{R+} sourced from VDD | | | VDD | | V |
| | | V _{R+} sourced from internal reference (VREF) | | | VREF | | V |
| V _{R-} | Negative ADC reference voltage | | | | 0 | | V |
| F _S | ADC sampling frequency | RES = 0x0 (12-bit mode), VDD Reference | | | | 1.5 | MSPS |
| | | RES = 0x1 (10-bit mode), VDD Reference | | | | 1.7 | |
| | | RES = 0x2 (8-bit mode), VDD Reference | | | | 2 | |
| F _S | ADC sampling frequency | RES = 0x0 (12-bit mode), Internal Reference | | | | 0.866 | MSPS |
| | | RES = 0x1 (10-bit mode), Internal Reference | | | | 1 | |
| | | RES = 0x2 (8-bit mode), Internal Reference | | | | 1.2 | |
| I _(ADC) | Operating supply current into VDD terminal | F _S = 1.5MSPS, V _{R+} = VDD | | | 200 | 220 | μA |
| | | F _S = 0.856MSPS, V _{R+} = VREF = 2.5V (VREF power consumption included) | | | 220 | 250 | |
| C _{S/H} | ADC sample-and-hold capacitance | | | | 0.22 | | pF |
| R _{in} | ADC switch resistance | | | | 25 | | kΩ |
| ENOB | Effective number of bits | VDD reference (2) | | 9.3 | 10.4 | | bit |
| | | VDD reference with over sampling | | | 12.2 | | |
| | | Internal reference, V _{R+} = VREF = 2.5V | | 9.4 | 9.8 | | |
| SNR | Signal-to-noise ratio | VDD reference (2) | | | 64 | | dB |
| | | VDD reference with over sampling | | | 75 | | |
| | | Internal reference, V _{R+} = VREF = 2.5V | | | 61 | | |

7.11.1 Electrical Characteristics (続き)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted), all TYP values are measured at 25°C and all accuracy parameters are measured using 12-bit resolution mode (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|------------------------|--|---|------|-----|------|------|
| PSRR _{DC} | Power supply rejection ratio, DC | VDD = VDD _(min) to VDD _(max) Internal reference, V _{R+} = VREF = 2.5V | | 61 | | dB |
| T _{wakeup} | ADC Wakeup Time | Assumes internal reference is active | | | 5 | us |
| V _{SupplyMon} | Supply Monitor voltage divider (VDD/3) accuracy | ADC input channel: Supply Monitor ⁽³⁾ | -0.6 | | +2.5 | % |
| I _{SupplyMon} | Supply Monitor voltage divider current consumption | ADC input channel: Supply Monitor | | 10 | | uA |

- (1) The analog input voltage range must be within the selected ADC reference voltage range V_{R+} to V_{R-} for valid conversion results.
- (2) VDD reference specifications are measured with V_{R+} = VDD = 3.3V and V_{R-} = VSS = 0V
- (3) Analog power supply monitor. Analog input on channel 15 is disconnected and is internally connected to the voltage divider which is VDD/3.

7.11.2 Switching Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-------------------------------|---|---|-------|-----|-----|---------------|
| f _{ADCCLK} | ADC clock frequency | | 12 | | 24 | MHz |
| t _{ADC trigger} | Software trigger minimum width | | 3 | | | ADCCLK cycles |
| t _{Sample_step} | Sampling time for step input | 12-bit mode, R _S = 50Ω, C _{pext} = 10pF | 0.166 | | | μs |
| t _{Sample_VREF} | Sample time with VREF | ADC CHANNEL=12, 12-bit mode, VDD as reference | 4 | | | μs |
| t _{Sample_SupplyMon} | Sample time with Supply Monitor (VDD/3) | | 3 | | | μs |

7.11.3 Linearity Parameters

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted), all TYP values are measured at 25°C and all linearity parameters are measured using 12-bit resolution mode (unless otherwise noted) ⁽¹⁾

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------|------------------------------------|--|------|-----|------|------|
| E _I | Integral linearity error (INL) | VDD reference, 10-bit ⁽²⁾ | -1.0 | | +1.0 | LSB |
| | | VDD reference, 12-bit ⁽²⁾ | -4.0 | | +4.0 | LSB |
| E _D | Differential linearity error (DNL) | VDD reference, 10-bit ⁽²⁾ | -1.0 | | +1.0 | LSB |
| | | VDD reference, 12-bit ⁽²⁾ | -1.0 | | +4.0 | LSB |
| E _O | Offset error | VDD reference, 10-bit ^{(2) (3)} | -3 | | 3 | mV |
| | | VDD reference, 12-bit ^{(2) (3)} | -3 | | 3 | mV |
| E _G | Gain error | VDD reference, 10-bit ⁽²⁾ | -5 | | 5 | LSB |
| | | VDD reference, 12-bit ⁽²⁾ | -25 | | 25 | LSB |

- (1) Total Unadjusted Error (TUE) can be calculated from E_I, E_O, and E_G using the following formula: TUE = √(E_I² + |E_O|² + E_G²)
Note: You must convert all of the errors into the same unit, usually LSB, for the above equation to be accurate
- (2) VDD reference specifications are measured with V_{R+} = VDD and V_{R-} = VSS = 0V.
- (3) Offset error achieves +/-3mV after software calibration

7.11.4 Typical Connection Diagram

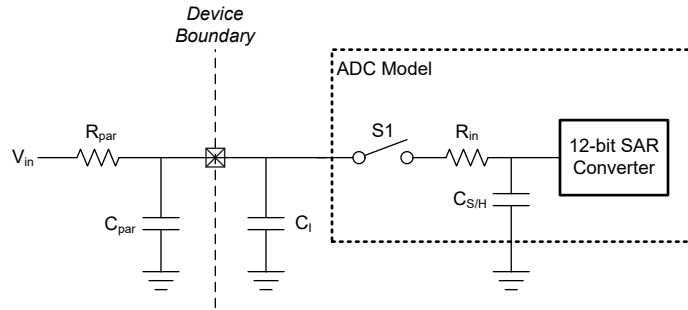


図 7-2. ADC Input Network

1. Refer to [ADC Electrical Characteristics](#) for the values of R_{in} and $C_{S/H}$
2. Refer to [Digital IO Electrical Characteristics](#) for the value of C_i
3. C_{par} and R_{par} represent the parasitic capacitance and resistance of the external ADC input circuitry

Use the following equations to solve for the minimum sampling time (T) required for an ADC conversion:

1. $\tau = (R_{par} + R_{in}) \times C_{S/H} + R_{par} \times (C_{par} + C_i)$
2. $K = \ln(2^N / \text{Settling error}) - \ln((C_{par} + C_i) / C_{S/H})$
3. $T \text{ (minimum sampling time)} = K \times \tau$

7.12 Temperature Sensor

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------|---|---|------|------|------|-------|
| T_{TRIM} | Factory trim temperature ⁽¹⁾ | | 27 | 30 | 33 | °C |
| TS_c | Temperature coefficient | | -1.9 | -1.8 | -1.7 | mV/°C |
| $t_{SET, TS}$ | Temperature sensor settling time ⁽²⁾ | ADC and VREF configuration: RES=0 (12-bit mode), VRSEL=2h (VREF=1.4V), ADC CHANNEL=11 | | 2.5 | 10 | us |

- (1) Higher absolute accuracy may be achieved through user calibration.
- (2) This is the minimum required ADC sampling time when measuring the temperature sensor.

7.13 VREF

7.13.1 Voltage Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------|--|-----------------|-------|-----|-------|------|
| $V_{DD_{min}}$ | Minimum supply voltage needed for VREF operation | BUFCONFIG = 1 | 1.62 | | | V |
| | | BUFCONFIG = 0 | 2.7 | | | |
| VREF | Voltage reference output voltage | BUFCONFIG = 1 | 1.378 | 1.4 | 1.421 | V |
| | | BUFCONFIG = 0 | 2.462 | 2.5 | 2.541 | |

7.13.2 Electrical Characteristics

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|-------------|---|-----------------------------|------------------------------|-----|-----|-----|--------|
| I_{VREF} | VREF operating supply current (this spec is an estimation and will be more reliable once the IP is further in the design phase) | BUFCONFIG = {0, 1}, No load | BUFCONFIG = {0, 1}, No load. | | 80 | 100 | μA |
| TC_{VREF} | Temperature coefficient of VREF ⁽¹⁾ | BUFCONFIG = {0, 1} | BUFCONFIG = {0, 1} | | | 75 | ppm/°C |

7.13.2 Electrical Characteristics (続き)

over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | | MIN | TYP | MAX | UNIT |
|----------------------|----------------------|---|---|-----|-----|-----|------|
| TC_{drift} | Long term VREF drift | Time = 1000 hours, BUFCONFIG = {0, 1}, T = 25°C | Time = 1000 hours, BUFCONFIG = {0, 1}, T = 25°C | | | 300 | ppm |
| T_{startup} | VREF startup time | BUFCONFIG = {0, 1}, VDD = 2.7 V | BUFCONFIG = {0, 1}, VDD = 2.7 V | | | 10 | us |

- (1) The temperature coefficient of the VREF output is the sum of $TC_{V_{\text{RBUF}}}$ and the temperature coefficient of the internal bandgap reference.

7.14 I2C

7.14.1 I2C Characteristics

over operating free-air temperature range (unless otherwise noted)

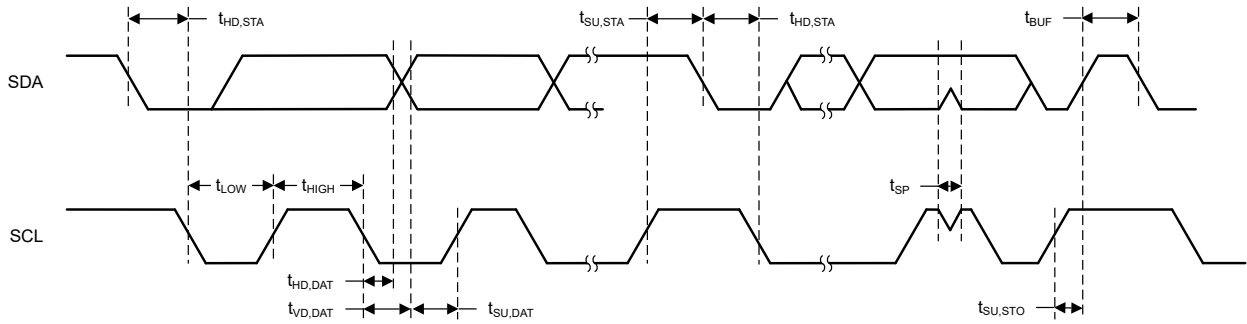
| PARAMETERS | | TEST CONDITIONS | Standard mode | | Fast mode | | Fast mode plus | | UNIT |
|---------------------|--|----------------------|---------------|------|-----------|-----|----------------|------|------|
| | | | MIN | MAX | MIN | MAX | MIN | MAX | |
| f_{I2C} | I2C input clock frequency | I2C in Power Domain0 | 24 | | 24 | | 24 | | MHz |
| f_{SCL} | SCL clock frequency | | 100 | | 400 | | 1000 | | kHz |
| $t_{\text{HD,STA}}$ | Hold time (repeated) START | | 4 | | 0.6 | | 0.26 | | us |
| t_{LOW} | LOW period of the SCL clock | | 4.7 | | 1.3 | | 0.5 | | us |
| t_{HIGH} | High period of the SCL clock | | 4 | | 0.6 | | 0.26 | | us |
| $t_{\text{SU,STA}}$ | Setup time for a repeated START | | 4.7 | | 0.6 | | 0.26 | | us |
| $t_{\text{HD,DAT}}$ | Data hold time | | 0 | | 0 | | 0 | | ns |
| $t_{\text{SU,DAT}}$ | Data setup time | | 250 | | 100 | | 50 | | ns |
| $t_{\text{SU,STO}}$ | Setup time for STOP | | 4 | | 0.6 | | 0.26 | | us |
| t_{BUF} | bus free time between a STOP and START condition | | 4.7 | | 1.3 | | 0.5 | | us |
| $t_{\text{VD,DAT}}$ | data valid time | | | 3.45 | | 0.9 | | 0.45 | us |
| $t_{\text{VD,ACK}}$ | data valid acknowledge time | | | 3.45 | | 0.9 | | 0.45 | us |

7.14.2 I2C Filter

over operating free-air temperature range (unless otherwise noted)

| PARAMETERS | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-----------------|---|-----------------|-----|-----|-----|------|
| f_{SP} | Pulse duration of spikes suppressed by input filter | AGFSELx = 0 | | 11 | 35 | ns |
| f_{SP} | Pulse duration of spikes suppressed by input filter | AGFSELx = 1 | | 14 | 35 | ns |
| f_{SP} | Pulse duration of spikes suppressed by input filter | AGFSELx = 2 | | 22 | 60 | ns |
| f_{SP} | Pulse duration of spikes suppressed by input filter | AGFSELx = 3 | | 35 | 90 | ns |

7.14.3 I²C Timing Diagram



7-3. I2C Timing Diagram

7.15 SPI

7.15.1 SPI

over operating free-air temperature range (unless otherwise noted)

| PARAMETERS | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|-------------------|---|---|-------------------|---------------|-------------------|------|
| SPI | | | | | | |
| f_{SPI} | SPI clock frequency | Clock max speed = 24MHz 1.62 < VDD < 3.6V Controller mode | | | 12 | MHz |
| f_{SPI} | SPI clock frequency | Clock max speed = 24MHz 1.62 < VDD < 3.6V Peripheral mode | | | 12 | MHz |
| DC_{SCK} | SCK Duty Cycle | | 40 | 50 | 60 | % |
| Controller | | | | | | |
| $t_{SCLK_H/L}$ | SCLK High or Low time | | $(t_{SPI}/2) - 1$ | $t_{SPI} / 2$ | $(t_{SPI}/2) + 1$ | ns |
| t_{CS_LEAD} | CS lead-time, CS active to clock | | 1 | | | ns |
| t_{CS_LAG} | CS lag time, Last clock to CS inactive | | 11 | | | ns |
| t_{CS_ACC} | CS access time, CS active to PICO data out | | | | 93 | ns |
| t_{CS_DIS} | CS disable time, CS inactive to PICO high impedance | | | | 10 | ns |
| $t_{SU,CI}$ | POCI input data setup time ⁽¹⁾ | 2.7 < VDD < 3.6V, delayed sampling enabled | 1 | | | ns |
| | | 1.62 < VDD < 2.7V, delayed sampling enabled | 1 | | | |
| $t_{SU,CI}$ | POCI input data setup time ⁽¹⁾ | 2.7 < VDD < 3.6V, no delayed sampling | 27 | | | ns |
| | | 1.62 < VDD < 2.7V, no delayed sampling | 35 | | | |
| $t_{HD,CI}$ | POCI input data hold time | | 9 | | | ns |
| $t_{VALID,CO}$ | PICO output data valid time ⁽²⁾ | | | | 10 | ns |
| $t_{HD,CO}$ | PICO output data hold time ⁽³⁾ | | 1 | | | ns |
| Peripheral | | | | | | |
| t_{CS_LEAD} | CS lead-time, CS active to clock | | 8 | | | ns |
| t_{CS_LAG} | CS lag time, Last clock to CS inactive | | 0 | | | ns |
| t_{CS_ACC} | CS access time, CS active to POCI data out | | | | 50 | ns |

7.15.1 SPI (続き)

over operating free-air temperature range (unless otherwise noted)

| PARAMETERS | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|----------------|---|---------------------|-----|-----|-----|------|
| $t_{CS,DIS}$ | CS disable time, CS inactive to POCI high impedance | | | | 50 | ns |
| $t_{SU,PI}$ | PICO input data setup time | | 2 | | | ns |
| $t_{HD,PI}$ | PICO input data hold time | | 1 | | | ns |
| $t_{VALID,PO}$ | POCI output data valid time ⁽²⁾ | $2.7 < VDD < 3.6V$ | | | 34 | ns |
| $t_{VALID,PO}$ | POCI output data valid time ⁽²⁾ | $1.62 < VDD < 2.7V$ | | | 41 | ns |
| $t_{HD,PO}$ | POCI output data hold time ⁽³⁾ | | 5 | | | ns |

- (1) The POCI input data setup time can be fully compensated when delayed sampling feature is enabled.
- (2) Specifies the time to drive the next valid data to the output after the output changing SCLK clock edge
- (3) Specifies how long data on the output is valid after the output changing SCLK clock edge

7.15.2 SPI Timing Diagrams

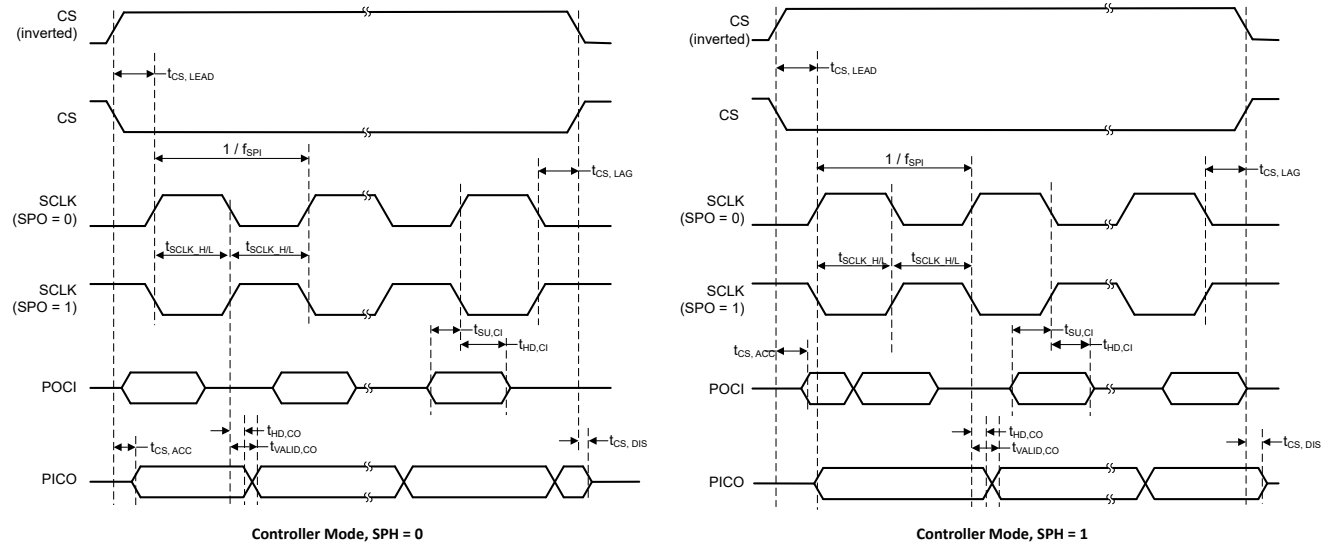


図 7-4. SPI Timing Diagram - Controller Mode

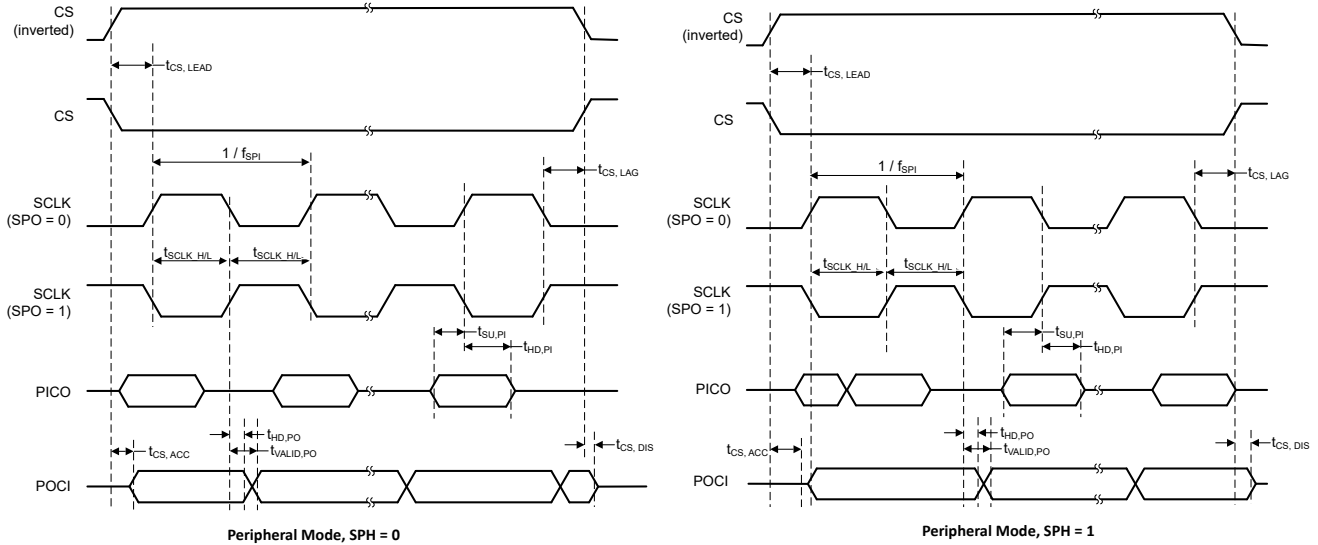


图 7-5. SPI Timing Diagram - Peripheral Mode

7.16 UART

over operating free-air temperature range (unless otherwise noted)

| PARAMETERS | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------|---|-----------------|-----|-----|-----|------|
| f_{UART} | UART input clock frequency | | | | 24 | MHz |
| f_{BITCLK} | BITCLK clock frequency (equals baud rate in MBaud) | | | | 3 | MHz |
| t_{SP} | Pulse duration of spikes suppressed by input filter | AGFSELx = 0 | | 11 | 35 | ns |
| | | AGFSELx = 1 | | 14 | 35 | ns |
| | | AGFSELx = 2 | | 22 | 60 | ns |
| | | AGFSELx = 3 | | 35 | 90 | ns |

7.17 TIMx

over operating free-air temperature range (unless otherwise noted)

| PARAMETERS | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|------------------|-----------------------|-------------------------------------|-------|-----|-----|----------------------|
| t_{res} | Timer resolution time | $f_{\text{TIMxCLK}} = 24\text{MHz}$ | 41.67 | | | ns |
| | | | 1 | | | t_{TIMxCLK} |
| t_{res} | Timer resolution time | TIMx with 16bit counter | | | 16 | bit |

7.18 Windowed Watchdog Characteristics

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|---------------------------------|---------------------------|---|-----|--------|------|---------------|
| $\text{WWDT}_{\text{FREQ}}$ | WWDT operating frequency | | | 32.768 | | kHz |
| $\text{WWDT}_{\text{Tstart}}$ | WWDT counter start time | Write to WWDTCTL0 until WWDT counter starts ($\text{WWDT}_{\text{FREQ}} = 32.768\text{kHz}$) | | | 30.5 | μs |
| $\text{WWDT}_{\text{Trestart}}$ | WWDT counter restart time | Write to WWDCNTRST until WWDT counter restarts ($\text{WWDT}_{\text{FREQ}} = 32.768\text{kHz}$) | | | 30.5 | μs |

7.19 Emulation and Debug

7.19.1 SWD Timing

over operating free-air temperature range (unless otherwise noted)

| PARAMETER | | TEST CONDITIONS | MIN | TYP | MAX | UNIT |
|------------------|---------------|-----------------|-----|-----|-----|------|
| f _{SWD} | SWD frequency | | | | 10 | MHz |

8 Detailed Description

The following sections describe all of the components that make up the devices in this data sheet. The peripherals integrated into these devices are configured by software through Memory Mapped Registers (MMRs). For more details, see the corresponding chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.1 CPU

The CPU subsystem (MCPUSS) implements an Arm Cortex-M0+ CPU, a system timer, and interrupt management features. The Arm Cortex-M0+ is a cost-optimized 32-bit CPU that delivers high performance and low power to embedded applications. Key features of the CPU Sub System include:

- Arm Cortex-M0+ CPU supports clock frequencies from 32kHz to 24MHz
 - ARMv6-M Thumb instruction set (little endian) with 32-cycle 32x32 slow multiply instruction
- Nested vectored interrupt controller (NVIC) with 4 programmable priority levels and tail chaining

8.2 Operating Modes

MSPM0C MCUs provide five main operating modes (power modes) to allow for optimization of the device power consumption based on application requirements. In order of decreasing power, the modes are: RUN, SLEEP, STOP, STANDBY, and SHUTDOWN. The CPU is active executing code in RUN mode. Peripheral interrupt events can wake the device from SLEEP, STOP, or STANDBY mode to the RUN mode. SHUTDOWN mode completely disables the internal core regulator to minimize power consumption, and wake is only possible via NRST or SWD. RUN, SLEEP, STOP, and STANDBY modes also include several configurable policy options (for example, RUN.x) for balancing performance with power consumption.

To further balance performance and power consumption, MSPM0C devices implement two power domains: **PD1** (for the CPU, memories, and high performance peripherals), and **PD0** (for low speed, low power peripherals).

- **PD1** is always powered in RUN and SLEEP modes, but is disabled in all other modes.
- **PD0** is always powered in RUN, SLEEP, STOP, and STANDBY modes.
- PD1 and PD0 are both disabled in SHUTDOWN mode.

8.2.1 Functionality by Operating Mode (MSPM0C110x)

表 8-1 lists the supported functionality in each operating mode.

Functional key:

- **EN**: The function is enabled in the specified mode.
- **DIS**: The function is disabled (either clock or power gated) in the specified mode, but the function's configuration is retained.
- **OPT**: The function is optional in the specified mode, and remains enabled if configured to be enabled.
- **NS**: The function is not automatically disabled in the specified mode, but use of the function is not supported.
- **OFF**: The function is fully powered off in the specified mode, and no configuration information is retained.

表 8-1. Supported Functionality by Operating Mode

| Operating Mode | | RUN | | | SLEEP | | | STOP | | STANDBY | | SHUTDOWN |
|----------------|--------|------|------|------|--------|--------|--------|--------------------|-------|----------|----------|----------|
| | | RUN0 | RUN1 | RUN2 | SLEEP0 | SLEEP1 | SLEEP2 | STOP0 | STOP2 | STANDBY0 | STANDBY1 | |
| Oscillators | SYSOSC | EN | EN | DIS | EN | EN | DIS | OPT ⁽¹⁾ | DIS | DIS | DIS | OFF |
| | LFOSC | EN | | | | | | | | | | OFF |

表 8-1. Supported Functionality by Operating Mode (続き)

| Operating Mode | | RUN | | | SLEEP | | | STOP | | STANDBY | | SHUTDOWN |
|---------------------|-------------------------|------------|------|---------|--------|--------|-------------------------|-------------------|-----------|-----------|--------------------|----------|
| | | RUN0 | RUN1 | RUN2 | SLEEP0 | SLEEP1 | SLEEP2 | STOP0 | STOP2 | STANDBY0 | STANDBY1 | |
| Clocks | CPUCLK | 24M | 32k | 32k | DIS | | | | | | | OFF |
| | MCLK to PD1 | 24M | 32k | 32k | 24M | 32k | 32k | DIS | | | | OFF |
| | ULPCLK to PD0 | 24M | 32k | 32k | 24M | 32k | 32k | 4M ⁽¹⁾ | 32k | DIS | OFF | |
| | ULPCLK to TIMG14, TIMG8 | 24M | 32k | 32k | 24M | 32k | 32k | 4M ⁽¹⁾ | 32k | | OFF | |
| | MFCLK | OPT | DIS | | OPT | DIS | | OPT | DIS | | OFF | |
| | LFCLK | 32k | | | | | | | DIS | | OFF | |
| | LFCLK to TIMG14, TIMG8 | 32k | | | | | | | | | OFF | |
| | MCLK Monitor | OPT | | | | | | | DIS | | OFF | |
| PMU | POR Monitor | EN | | | | | | | | | | |
| | BOR Monitor | EN | | | | | | | | | | |
| | Core Regulator | Full drive | | | | | | | Low drive | | OFF | |
| Core Functions | CPU | EN | | | DIS | | | | | OFF | | |
| | DMA | OPT | | | | | NS (triggers supported) | | | | OFF | |
| | Flash | EN | | | | | OPT | DIS | | OFF | | |
| | SRAM | EN | | | | | OPT | DIS | | OFF | | |
| PD1 Peripherals | SPI0 | OPT | | | | | DIS | | | | OFF | |
| | CRC | OPT | | | | | DIS | | | | OFF | |
| PD0 Peripherals | TIMA0 | OPT | | | | | | | | | OFF | |
| | TIMG8 | OPT | | | | | | | | | OFF | |
| | TIMG14 | OPT | | | | | | | | | OFF | |
| | UART0 | OPT | | | | | | | | | OPT ⁽²⁾ | OFF |
| | I2C0 | OPT | | | | | | | | | OPT ⁽²⁾ | OFF |
| | GPIOA | OPT | | | | | | | | | OPT ⁽²⁾ | OFF |
| | WWDT0 | OPT | | | | | | | | | DIS | OFF |
| Analog | ADC0 | OPT | | | | | NS (triggers supported) | | | | OFF | |
| | VREF | OPT | | | | | NS | | | | OFF | |
| | Temperature Sensor | OPT | | | | | NS | | | | OFF | |
| IOMUX and IO Wakeup | EN | | | | | | | | | | DIS | |
| Wake Sources | N/A | | | ANY IRQ | | | PD0 IRQ | | | NRST, SWD | | |

- (1) If STOP0 is entered from RUN1 (SYSOSC enabled but MCLK sourced from LFCLK), SYSOSC remains enabled as it was in RUN1, and ULPCLK remains at 32kHz as it was in RUN1. If STOP0 is entered from RUN2 (SYSOSC was disabled and MCLK was sourced from LFCLK), SYSOSC remains disabled as it was in RUN2, and ULPCLK remains at 32kHz as it was in RUN2.
- (2) When using the STANDBY1 policy for STANDBY, only TIMG8, TIMG14 and TIMA0 are clocked. Other PD0 peripherals can generate an asynchronous fast clock request upon external activity but are not actively clocked.

8.3 Power Management Unit (PMU)

The power management unit (PMU) generates the internally regulated core supplies for the device and provides supervision of the external supply (VDD). The PMU also contains the bandgap voltage reference used by the PMU itself as well as analog peripherals. Key features of the PMU include:

- Power-on reset (POR) supply monitor

- Brown-out reset (BOR) supply monitor with early warning capability using three programmable thresholds
- Core regulator with support for RUN, SLEEP, STOP, and STANDBY operating modes to dynamically balance performance with power consumption
- Parity-protected trim to immediately generate a power-on reset (POR) in the event that a power management trim is corrupted

For more details, see the PMU chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.4 Clock Module (CKM)

The clock module provides the following oscillators:

- **LFOSC**: Internal low-frequency oscillator (32kHz)
- **SYSOSC**: Internal high-frequency oscillator (24MHz)
- **LFCKIN**: low-frequency digital clock input (32KHz)
- **HFCKIN**: high-frequency digital clock input (4 to 24MHz)

The following clocks are distributed by the clock module for use by the processor, bus, and peripherals:

- **MCLK**: Main system clock for PD1 peripherals, derived from SYSOSC or LFCLK, active in RUN and SLEEP modes
- **CPUCLK**: Clock for the processor (derived from MCLK), active in RUN mode
- **ULPCLK**: Ultra-low power clock for PD0 peripherals, active in RUN, SLEEP, STOP, and STANDBY modes
- **MFCLK**: 4MHz fixed mid-frequency clock for peripherals, available in RUN, SLEEP, and STOP modes
- **LFCLK**: 32kHz fixed low-frequency clock for peripherals or MCLK, active in RUN, SLEEP, STOP, and STANDBY modes
- **ADCCLK**: ADC clock, available in RUN, SLEEP and STOP modes
- **CLK_OUT**: Used to output a clock externally, available in RUN, SLEEP, STOP, and STANDBY modes

For more details, see the CKM chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.5 DMA

The direct memory access (DMA) controller allows movement of data from one memory address to another without CPU intervention. For example, the DMA can be used to move data from ADC conversion memory to SRAM. The DMA reduces system power consumption by allowing the CPU to remain in low power mode, without having to awaken to move data to or from a peripheral.

The DMA in these devices support the following key features:

- 1 DMA transfer channel
- Direct peripheral to DMA trigger is supported only from ADC.
- Byte (8-bit), short word (16-bit), word (32-bit) and long word (64-bit) or mixed byte and word transfer capability
- Transfer counter block size supports up to 64k transfers of any data type
- Configurable DMA transfer trigger selection

表 8-2 lists the available triggers for the DMA which are configured using the DMATCTL.DMATSEL control bits in the DMA memory mapped registers.

表 8-2. DMA Trigger Mapping

| TRIGGER 0:6 | SOURCE |
|-------------|-------------------------------|
| 0 | Software |
| 1 | Generic Subscriber 0 (FSUB_0) |
| 2 | Generic Subscriber 1 (FSUB_1) |
| 3 | ADC0 Publisher 2 |

8.6 Events

The event manager transfers digital events from one entity (for example, a peripheral) to another (for example, a second peripheral, the DMA or the CPU). The event manager implements event transfer through a defined set of event publishers (generators) and subscribers (receivers) that are interconnected through an event fabric containing a combination of static and programmable routes.

Events that are transferred by the event manager include:

- Peripheral event transferred to the CPU as an interrupt request (IRQ) (Static Event)
 - Example: GPIO interrupt is sent to the CPU
- Peripheral event transferred to the DMA as a DMA trigger (DMA Event)
 - Example: ADC trigger to DMA to request a DMA transfer
- Peripheral event transferred to another peripheral to directly trigger an action in hardware (Generic Event)
 - Example: TIMx timer peripheral publishes a periodic event to the ADC subscriber port, and the ADC uses the event to trigger start-of-sampling

For more details, see the Event chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

表 8-3. Generic Event Channels

A generic route is a point-to-point (1:1) route in which the peripheral publishing the event is configured to use the available generic route channel to publish the event to another entity. An entity can be another peripheral, a generic DMA trigger event, or a generic CPU event.

| CHANID | Generic Route Channel Selection | Channel Type |
|--------|-----------------------------------|--------------|
| 0 | No generic event channel selected | N/A |
| 1 | Generic event channel 1 selected | 1 : 1 |

8.7 Memory

8.7.1 Memory Organization

表 8-4 summarizes the memory map of the devices. For more information about the memory region detail, see the *Platform Memory Map* section in the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

表 8-4. Memory Organization

| Memory Region | Subregion | MSPM0C1103, MSPS003F3 | MSPM0C1104, MSPS003F4 |
|---------------|-------------------|--|---|
| Code (Flash) | Flash | 8KB ⁽¹⁾ 0x0000.0000 to 0x0000.1FFF | 16KB ⁽¹⁾ 0x0000.0000 to 0x0000.3FFF |
| SRAM (SRAM) | SRAM | 1KB 0x2000.0000 to 0x2000.03FF | 1KB 0x2000.0000 to 0x2000.03FF |
| Peripheral | Peripherals | 0x4000.0000 to 0x40FF.FFFF | 0x4000.0000 to 0x40FF.FFFF |
| | Flash | 0x0040.0000 to 0x0040.1FFF | 0x0040.0000 to 0x0040.3FFF |
| | Configuration NVM | 512 bytes 0x41C0.0000 to 0x41C0.0200 | 512 bytes 0x41C0.0000 to 0x41C0.0200 |
| | FACTORY | 0x41C4.0000 to 0x41C4.0080 | 0x41C4.0000 to 0x41C4.0080 |
| Subsystem | | 0x6000.0000 to 0x7FFF.FFFF | 0x6000.0000 to 0x7FFF.FFFF |
| System PPB | | 0xE000.0000 to 0xE00F.FFFF | 0xE000.0000 to 0xE00F.FFFF |

(1) Up to 100000 program and erase cycles.

8.7.2 Peripheral File Map

表 8-5 lists the available peripherals and the register base address for each.

表 8-5. Peripherals Summary

| PERIPHERAL NAME | BASE ADDRESS | SIZE |
|---------------------|--------------|--------|
| VREF | 0x40030000 | 0x2000 |
| WWDT0 | 0x40080000 | 0x2000 |
| TIMG14 | 0x40084000 | 0x2000 |
| TIMG8 | 0x40090000 | 0x2000 |
| GPIO0 | 0x400A0000 | 0x2000 |
| SYSCTL | 0x400AF000 | 0x3000 |
| DEBUGSS | 0x400C7000 | 0x2000 |
| EVENT | 0x400C9000 | 0x3000 |
| NVMNW | 0x400CD000 | 0x2000 |
| I2C0 | 0x400F0000 | 0x2000 |
| UART0 | 0x40108000 | 0x2000 |
| MCPUSS | 0x40400000 | 0x2000 |
| WUC | 0x40424000 | 0x1000 |
| IOMUX | 0x40428000 | 0x2000 |
| DMA | 0x4042A000 | 0x2000 |
| CRC | 0x40440000 | 0x2000 |
| SPI0 | 0x40468000 | 0x2000 |
| ADC0 | 0x40004000 | 0x2000 |
| TIMA0 | 0x40860000 | 0x2000 |
| ADC0 ⁽¹⁾ | 0x4055A000 | 0x2000 |

(1) Aliased region of ADC0 memory-mapped registers

8.7.3 Peripheral Interrupt Vector

表 8-6 shows the IRQ number and the interrupt group number for each peripherals. There is only one group GROUP0 in this device.

表 8-6. Interrupt Vector Number

| PERIPHERAL NAME | NVIC IRQ | GROUP0 IIDX |
|-----------------|----------|-------------|
| WWDTO | 0 | 0 |
| DEBUGSS | 0 | 2 |
| NVMNW | 0 | 3 |
| SYSCTL | 0 | 6 |
| GPIO0 | 1 | - |
| TIMG8 | 2 | - |
| ADC | 4 | - |
| SPI0 | 9 | - |
| UART0 | 15 | - |
| TIMG14 | 16 | - |
| TIMA0 | 18 | - |
| I2C0 | 24 | - |
| DMA | 31 | - |

8.8 Flash Memory

A single bank of nonvolatile flash memory is provided for storing executable program code and application data.

Key features of the flash include:

- In-circuit program and erase operations supported across the entire recommended supply range
- Small 1KB sector sizes (minimum erase resolution of 1KB)
- Up to 100000 program and erase cycles

For a complete description of the flash memory, see the NVM chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.9 SRAM

MSPM0Cxx MCUs include a low-power high-performance SRAM memory with zero wait state access across the supported CPU frequency range of the device. SRAM memory can be used for storing volatile information such as the call stack, heap, global data, and code. The SRAM memory content is fully retained in RUN, SLEEP, STOP, and STANDBY operating modes and is lost in SHUTDOWN mode. A write protection mechanism is provided to allow the application to dynamically write protect the SRAM memory with 1KB resolution. Write protection is useful when placing executable code into SRAM to provide a level of protection against unintentional overwrites of code by either the CPU or DMA. Placing code in SRAM can improve performance of critical loops by enabling zero wait state operation and lower power consumption.

8.10 GPIO

The general purpose input/output (GPIO) peripheral lets the application write data out and read data in through the device pins. Through the use of the Port A GPIO peripheral, these devices support up to 18 GPIO pins.

The key features of the GPIO module include:

- 0 wait state MMR access from CPU
- Set, clear, or toggle multiple bits without the need of a read-modify-write construct in software
- "FastWake" feature enables low-power wakeup from STOP and STANDBY modes for any GPIO port
- User controlled input filtering

8.11 IOMUX

The IOMUX peripheral enables IO pad configuration and controls digital data flow to and from the device pins. The key features of the IOMUX include:

- IO pad configuration registers allow for programmable drive strength, speed, pullup or pulldown, and more
- Digital pin muxing allows for multiple peripheral signals to be routed to the same IO pad
- Pin functions and capabilities are user-configured using the PINCM register

For more details, see the IOMUX chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#) ..

8.12 ADC

The 12-bit analog-to-digital converter (ADC) module in these devices support fast 12-bit conversions with single-ended inputs.

ADC features include:

- 12-bit output resolution at up to 1.5-Msps with greater than 10-bit ENOB
- Up to 10 external input channels
- Internal channels for temperature sensing, supply monitoring, and analog signal chain
- Software selectable reference:
 - Configurable internal dedicated ADC reference voltage of 1.4V and 2.5V (VREF)
 - MCU supply voltage (VDD)
- Operates in RUN, SLEEP, and STOP modes and supports triggers from STANDBY mode

表 8-7. ADC0 Channel Mapping

| CHANNEL[0:7] | SIGNAL NAME | CHANNEL[8:15] | SIGNAL NAME |
|--------------|-------------|---------------|-------------------------------|
| 0 | A0 | 8 | A8 |
| 1 | A1 | 9 | A9 |
| 2 | A2 | 10 | - |
| 3 | A3 | 11 | <i>Temperature Sensor</i> |
| 4 | A4 | 12 | <i>VREF</i> |
| 5 | A5 | 13 | - |
| 6 | A6 | 14 | - |
| 7 | A7 | 15 | <i>Supply/Battery Monitor</i> |

Italicized signal names are internal to the SoC. These signals are used for internal peripheral interconnections.

For more details, see the ADC chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#) .

8.13 Temperature Sensor

The temperature sensor provides a voltage output that changes linearly with device temperature. The temperature sensor output is internally connected to one of ADC input channels to enable a temperature-to-digital conversion.

A unit-specific single-point calibration value for the temperature sensor is provided in the factory constants memory region. This calibration value represents the ADC conversion result (in ADC code format) corresponding to the temperature sensor being measured in 12-bit mode with the 1.4V internal VREF at the factory trim temperature (TS_{TRIM}). This calibration value can be used with the temperature sensor temperature coefficient (TS_C) to estimate the device temperature. See the temperature sensor section of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#) for guidance on estimating the device temperature with the factory trim value.

8.14 VREF

The voltage reference module (VREF) in these devices contains a configurable voltage reference buffer dedicated for the on-board ADC.

VREF features include:

- 1.4V and 2.5V user-selectable internal references
- Internal reference supports ADC operation up to 1Msps at 10-bit mode

For more details, see the VREF chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.15 CRC

The cyclical redundancy check (CRC) module provides a signature for an input data sequence. Key features of the CRC module include:

- Support for 16-bit CRC based on CRC16-CCITT
- Support for bit reversal

For more details, see the CRC chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.16 UART

The UART peripherals provide the following key features:

- Standard asynchronous communication bits for start, stop, and parity
- Fully programmable serial interface
 - 5, 6, 7, or 8 data bits
 - Even, odd, stick, or no-parity bit generation and detection
 - 1 or 2 stop bit generation
 - Line-break detection
 - Glitch filter on the input signals
 - Programmable baud rate generation with oversampling by 16, 8, or 3
 - Local Interconnect Network (LIN) mode support
- Separated transmit and receive FIFOs
- Support transmit and receive loopback mode operation
- See [表 8-8](#) for detail information on supported protocols

表 8-8. UART Features

| UART FEATURES | UART0 (Extend) |
|-------------------------------------|----------------|
| Active in stop and standby modes | Yes |
| Separate transmit and receive FIFOs | Yes |
| Support hardware flow control | Yes |
| Support 9-bit configuration | Yes |
| Support LIN mode | Yes |
| Support DALI | Yes |
| Support IrDA | Yes |
| Support ISO7816 Smart Card | Yes |
| Support Manchester coding | Yes |

For more details, see the UART chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.17 SPI

The serial peripheral interface (SPI) peripherals in these devices support the following key features:

- Support ULPClk/2 bit rate and up to 12 Mbits/s in both controller and peripheral modes
- Configurable as a controller or a peripheral
- Configurable chip select for both controller and peripheral
- Programmable clock prescaler and bit rate
- Programmable data frame size from 4 bits to 16 bits (controller mode)
- Programmable data frame size from 7 bits to 16 bits (peripheral mode)
- Separated transmit and receive FIFOs
- Supports TI mode, Motorola mode, and National Microwire format

For more details, see the SPI chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.18 I2C

The inter-integrated circuit interface (I²C) peripherals in these devices provide bidirectional data transfer with other I2C devices on the bus and support the following key features:

- 7-bit and 10-bit addressing mode with multiple 7-bit target addresses
- Multiple-controller transmitter or receiver mode
- Target receiver or transmitter mode with configurable clock stretching
- Support Standard-mode (Sm), with a bit rate up to 100 kbit/s
- Support Fast-mode (Fm), with a bit rate up to 400 kbit/s
- Support Fast-mode Plus (Fm+), with a bit rate up to 1 Mbit/s
- Separated transmit and receive FIFOs
- Support SMBus 3.0 with PEC, ARP, timeout detection, and host support
- Wakeup from low-power mode on address match
- Support analog and digital glitch filter for input signal glitch suppression

For more details, see the I2C chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.19 WWDT

The windowed watchdog timer (WWDT) can be used to supervise the operation of the device, specifically code execution. The WWDT can be used to generate a reset or an interrupt if the application software does not successfully reset the watchdog within a specified window of time. Key features of the WWDT include:

- 25-bit counter
- Programmable clock divider
- Eight software selectable watchdog timer periods
- Eight software selectable window sizes
- Support for stopping the WWDT automatically when entering a sleep mode
- Interval timer mode for applications which do not require watchdog functionality

For more details, see the WWDT chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.20 Timers (TIMx)

The timer peripherals in these devices support the following key features. For specific configuration, see [表 8-9](#).

Specific features for the **general-purpose timer (TIMGx)** include:

- 16-bit down, up/down, or up counter with repeat-reload mode
- Selectable and configurable clock source
- 8-bit programmable prescaler to divide the counter clock frequency
- Two independent channels for

- Output compare
- Input capture
- PWM output
- One-shot mode
- Support quadrature encoder interface (QEI) for positioning and movement sensing
- Support synchronization and cross trigger among different TIMx instances in the same power domain
- Support interrupt trigger generation and cross peripherals (such as ADC) trigger capability
- Cross-trigger event logic for Hall sensor inputs

Specific features for the **advanced timer (TIMAx)** include:

- 16-bit down or up-down counter, with repeat-reload mode
- Selectable and configurable clock source
- 8-bit programmable prescaler to divide the counter clock frequency
- Repeat counter to generate an interrupt or event only after a given number of cycles of the counter
- Up to four independent channels for
 - Output compare
 - Input capture
 - PWM output
 - One-shot mode
- Shadow register for load and CC register available
- Complementary output PWM
- Asymmetric PWM with programmable dead band insertion
- Fault handling mechanism to keep the output signals in a safe user-defined state when a fault condition is encountered
- Support synchronization and cross trigger among different TIMx instances in the same power domain
- Support interrupt trigger generation and cross peripherals (such as ADC) trigger capability
- Two additional capture/compare channels for internal events

表 8-9. TIMx Configurations

| TIMER NAME | POWER DOMAIN | RESOLUTION | PRESCALER | REPEAT COUNTER | CAPTURE / COMPARE CHANNELS | PHASE LOAD | SHADOW LOAD | SHADOW CC | DEAD-BAND | FAULT | QEI |
|------------|--------------|------------|-----------|----------------|----------------------------|------------|-------------|-----------|-----------|-------|-----|
| TIMG14 | PD0 | 16 bit | 8 bit | – | 4 | – | – | – | – | – | – |
| TIMG8 | PD0 | 16 bit | 8 bit | – | 2 | – | – | – | – | – | Yes |
| TIMA0 | PD1 | 16 bit | 8 bit | 8-bit | 4 | Yes | Yes | Yes | Yes | Yes | – |

For more details, see the timer chapters of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

8.21 Device Analog Connections

Figure 8-1 shows the internal analog connection of the device.

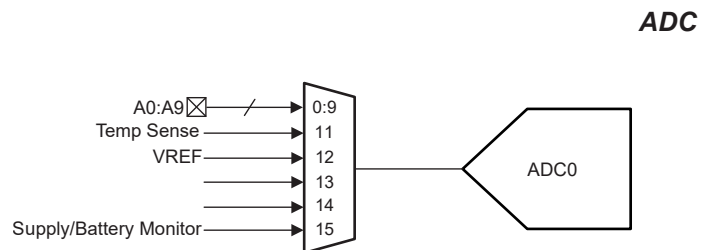


Figure 8-1. Analog Connections

8.22 Input/Output Diagrams

The IOMUX manages the selection of which peripheral function is to be used on a digital IO and provides the controls for the output driver and input path. For more information, see the IOMUX section of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

The mixed-signal IO pin slice diagram for a full featured IO pin is shown in [Figure 8-2](#). Not all pins have analog functions, drive strength control, and pullup or pulldown resistors available.

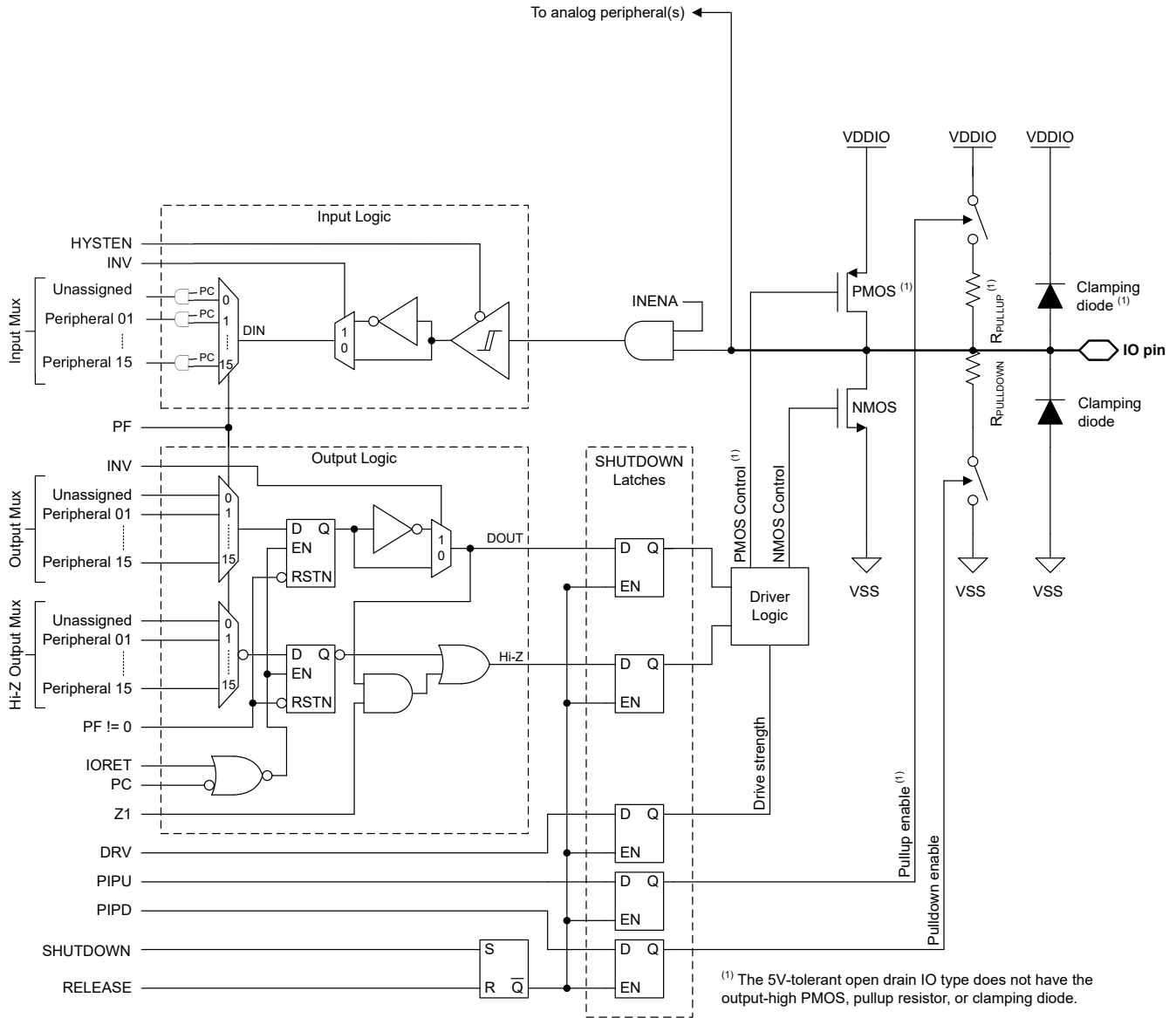


Figure 8-2. Superset Input/Output Diagram

8.23 Serial Wire Debug Interface

A serial wire debug (SWD) two-wire interface is provided via an Arm compatible serial wire debug port (SW-DP) to enable access to multiple debug functions within the device. For a complete description of the debug functionality offered on MSPM0 devices, see the debug chapter of the technical reference manual.

表 8-10. Serial Wire Debug Pin Requirements and Functions

| DEVICE SIGNAL | DIRECTION | SWD FUNCTION |
|---------------|--------------|--|
| SWCLK | Input | Serial wire clock from debug probe |
| SWDIO | Input/Output | Bi-directional (shared) serial wire data |

8.24 Device Factory Constants

All devices include a memory-mapped FACTORY region which provides read-only data describing the capabilities of a device as well as any factory-provided trim information for use by application software. See the *Factory Constants* section of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

表 8-11. DEVICEID

DEVICEID address is 0x41C4.0004, PARTNUM is bit 12 to 27, MANUFACTURER is bit 1 to 11.

| Device | DEVICEID.PARTNUM | DEVICEID.MANUFACTURER |
|---------------|------------------|-----------------------|
| MSPM0C1103-Q1 | 0xBBA1 | 0x17 |
| MSPM0C1104-Q1 | 0xBBA1 | 0x17 |

表 8-12. USERID

USERID address is 0x41C4.0008, PART is bit 0 to 15, VARIANT is bit 16 to 23

| Device | PART | VARIANT | Device | PART | VARIANT |
|------------------|------|---------|------------------|------|---------|
| M0C1104QDGS20RQ1 | A608 | 10 | M0C1103QDGS20RQ1 | 8A2B | 15 |
| M0C1104QRUKRQ1 | A608 | 11 | M0C1103QRUKRQ1 | 8A2B | 16 |
| M0C1104QDYRQ1 | A608 | 12 | M0C1103QDYRQ1 | 8A2B | 17 |
| M0C1104QDDFRQ1 | A608 | 13 | M0C1103QDDFRQ1 | 8A2B | 18 |
| M0C1104QDSGRQ1 | A608 | 14 | M0C1103QDSGRQ1 | 8A2B | 19 |

8.25 Identification

Revision and Device Identification

The hardware revision and device identification values are stored in the memory-mapped FACTORY region (see the Device Factory Constants section) which provides read-only data describing the capabilities of a device as well as any factory-provided trim information for use by application software. For more information, see the *Factory Constants* chapter of the [MSPM0 C-Series 24MHz Microcontrollers Technical Reference Manual](#).

The device revision and identification information are also included as part of the top-side marking on the device package. The device-specific errata describes these markings.

9 Applications, Implementation, and Layout

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Typical Application

9.1.1 Schematic

TI recommends connecting a combination of a 10- μF and a 0.1- μF low-ESR ceramic decoupling capacitor to the VDD and VSS pins. Higher-value capacitors can be used but can affect the supply rail ramp-up time. Decoupling capacitors must be placed as close as possible to the pins (within a few millimeters).

PA1 and NRST are double bonded for some variants. If it's used as a NRST, it must connect an external 47-k Ω pullup resistor with a 10-nF pulldown capacitor.

For 5V-tolerant open drain (ODIO), a pullup resistor is required to output high for I2C and UART functions if the ODIO are used.

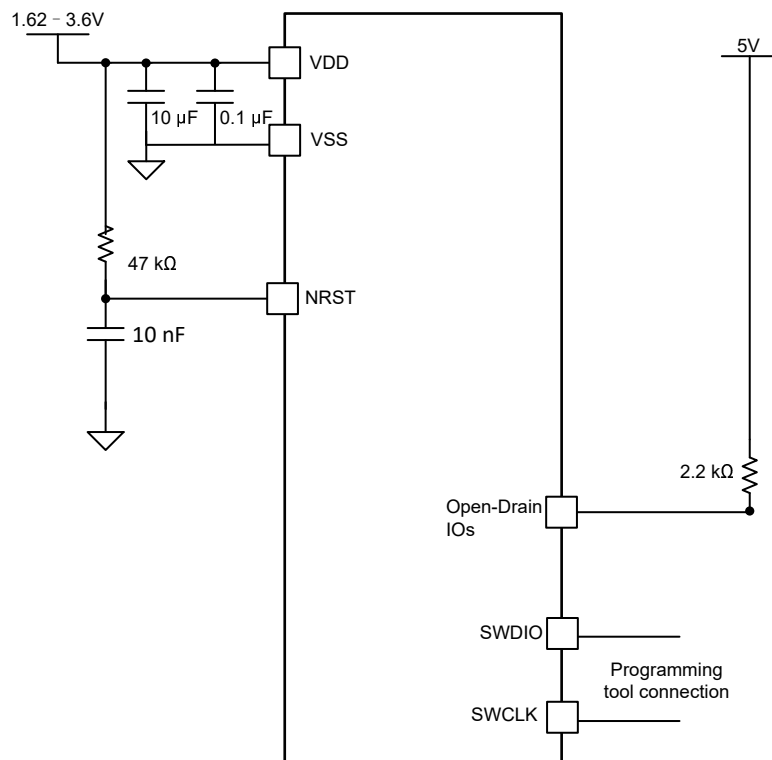


図 9-1. Typical Application Schematic

10 Device and Documentation Support

TI offers an extensive line of development tools. Tools and software to evaluate the performance of the device, generate code, and develop solutions are listed below.

10.1 Device Nomenclature

To designate the stages in the product development cycle, TI assigns prefixes to the part numbers of all MSP MCU devices and support tools. Each MSP MCU commercial family member has one of two prefixes: MSP or X. These prefixes represent evolutionary stages of product development from engineering prototypes (X) through fully qualified production devices (MSP).

X – Experimental device that is not necessarily representative of the final device's electrical specifications

MSP – Fully qualified production device

X devices are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes." MSP devices have been characterized fully, and the quality and reliability of the device have been demonstrated fully. TI's standard warranty applies. Predictions show that prototype devices (X) have a greater failure rate than the standard production devices. TI recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the temperature range, package type, and distribution format. [Figure 10-1](#) provides a legend for reading the complete device name.

Figure 10-1. Device Nomenclature

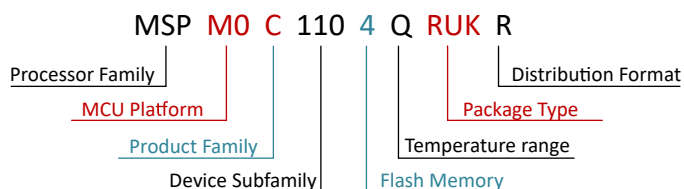


Table 10-1. Device Nomenclature

| | |
|----------------------------|--|
| Processor Family | MSP = Mixed-signal processor X= Experimental silicon |
| MCU Platform | M0 = Arm-based 32-bit M0+ |
| Product Family | C = 24MHz frequency |
| Device Subfamily | 110 = ADC |
| Flash Memory | 3 = 8KB 4 = 16KB |
| Temperature Range | Q = -40°C to 125°C, AEC-Q100 qualified |
| Package Type | See Table 5-1 and www.ti.com/packaging |
| Distribution Format | R = Large reel |

For orderable part numbers of MSP devices in different package types, see the Package Option Addendum of this document, ti.com, or contact your TI sales representative.

10.2 Tools and Software

Design Kits and Evaluation Modules

[MSPM0 LaunchPad \(LP\)](#)
[Boards: LP-MSPM0C1104](#)

Empowers you to immediately start developing on the industry's best integrated analog and most cost-optimized general purpose MSPM0 MCU family. Exposes all device pins and functionality; includes some built-in circuitry, out-of-box software demos, and on-board XDS110 debug probe for programming, debugging, and EnergyTrace™ technology.

The LP ecosystem includes dozens of [BoosterPack™](#) stackable plug-in modules to extend functionality.

Embedded Software

[MSPM0 Software Development Kit \(SDK\)](#)

Contains software drivers, middleware libraries, documentation, tools, and code examples that create a familiar and easy user experience for all MSPM0 devices.

Software Development Tools

[TI Cloud Tools](#)

Start your evaluation and development on a web browser without any installation. Cloud tools also have a downloadable, offline version.

[TI Resource Explorer](#)

Online portal to TI SDKs. Accessible in CCS IDE or in TI Cloud Tools.

[SysConfig](#)

Intuitive GUI to configure device and peripherals, resolve system conflicts, generate configuration code, and automate pin mux settings. Accessible in CCS IDE or in TI Cloud Tools. ([offline version](#))

[MSP Academy](#)

Great starting point for all developers to learn about the MSPM0 MCU Platform with training modules that span a wide range of topics. Part of TIRex.

[GUI Composer](#)

GUIs that simplify evaluation of certain MSPM0 features, such as configuring and monitoring a fully integrated analog signal chain without any code needed.

IDE and compiler tool chains

[Code Composer Studio™ \(CCS\)](#)

Includes [TI Arm-Clang](#) compiler. Supports all TI Arm Cortex MCUs and boasts competitive code size performance advantages, fast compile time, code coverage support, safety certification support, and completely free to use.

[IAR Embedded Workbench® IDE](#)

[Keil® MDK IDE](#)

[GNU Arm Embedded Tool Chain](#)

10.3 サポート・リソース

[テキサス・インスツルメンツ E2E™ サポート・フォーラム](#)は、エンジニアが検証済みの回答と設計に関するヒントをエキスパートから迅速かつ直接得ることができる場所です。既存の回答を検索したり、独自の質問をしたりすることで、設計に必要な支援を迅速に得ることができます。

リンクされているコンテンツは、各寄稿者により「現状のまま」提供されるものです。これらはテキサス・インスツルメンツの仕様を構成するものではなく、必ずしもテキサス・インスツルメンツの見解を反映したものではありません。テキサス・インスツルメンツの[使用条件](#)を参照してください。

10.4 Trademarks

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Arm® and Cortex® are registered trademarks of Arm Limited.

すべての商標は、それぞれの所有者に帰属します。

10.5 静電気放電に関する注意事項



この IC は、ESD によって破損する可能性があります。テキサス・インスツルメンツは、IC を取り扱う際には常に適切な注意を払うことを推奨します。正しい取り扱いおよび設置手順に従わない場合、デバイスを破損するおそれがあります。

ESD による破損は、わずかな性能低下からデバイスの完全な故障まで多岐にわたります。精密な IC の場合、パラメータがわずかに変化するだけで公表されている仕様から外れる可能性があるため、破損が発生しやすくなっています。

10.6 用語集

[テキサス・インスツルメンツ用語集](#) この用語集には、用語や略語の一覧および定義が記載されています。

11 Revision History

資料番号末尾の英字は改訂を表しています。その改訂履歴は英語版に準じています。

| Changes from Revision * (October 2023) to Revision A (August 2024) | Page |
|--|------|
| • このデータシートのステータスを「量産データ」に変更、ドキュメント全体を通して最終的な特性を更新..... | 1 |

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

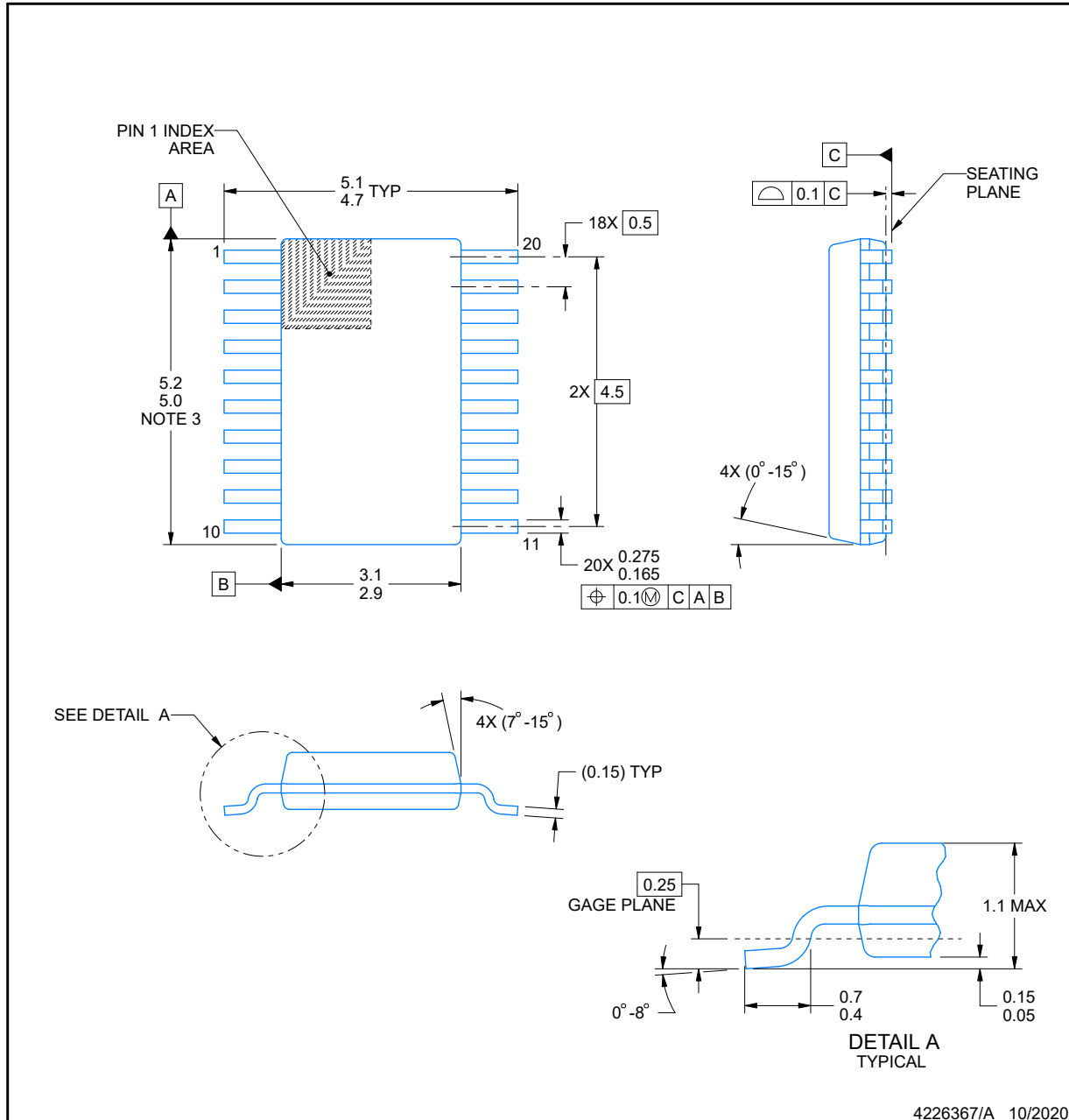
DGS0020A



PACKAGE OUTLINE

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



4226367/A 10/2020

NOTES:

PowerPAD is a trademark of Texas Instruments.

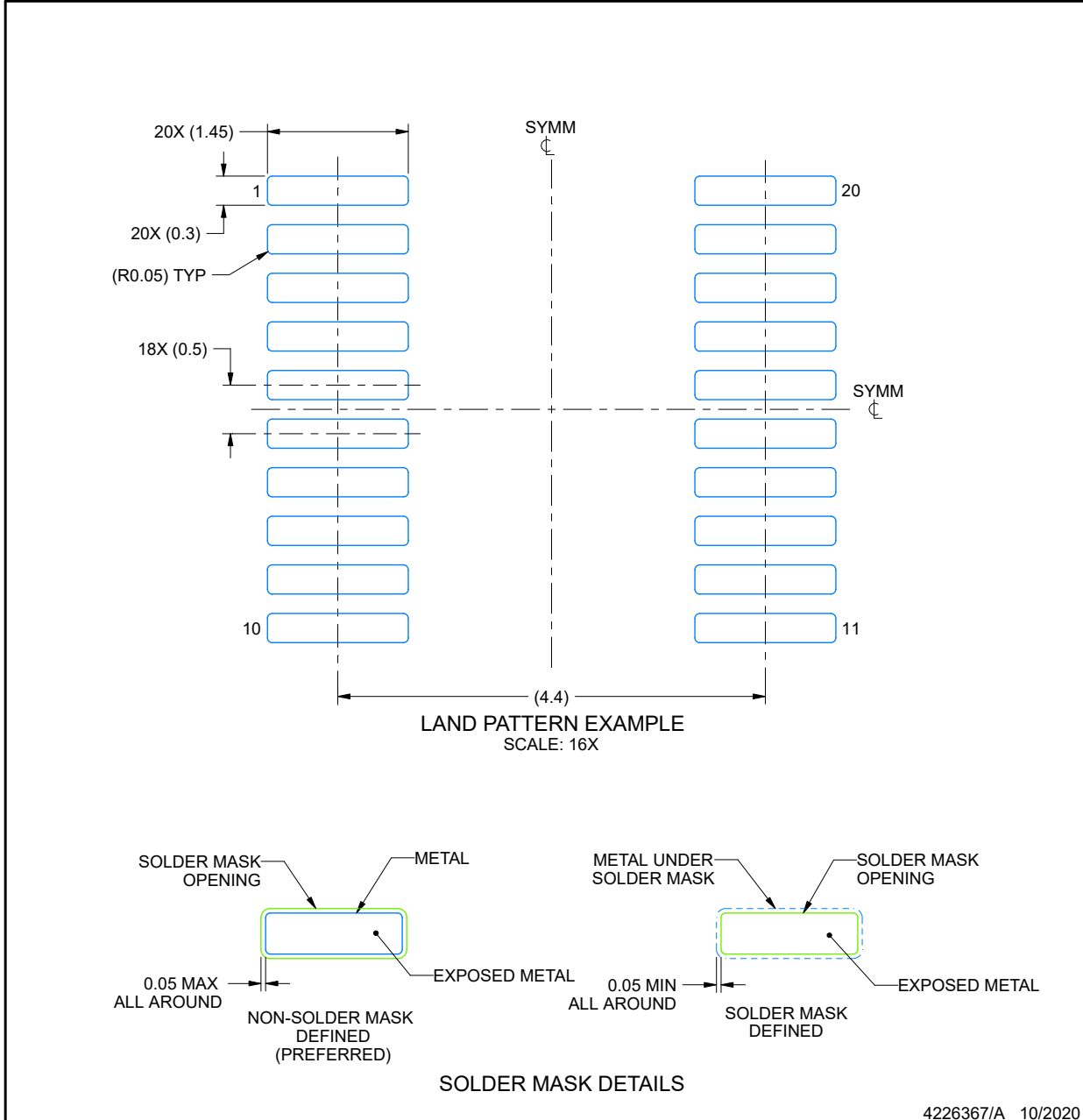
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. No JEDEC registration as of September 2020.
5. Features may differ or may not be present.

EXAMPLE BOARD LAYOUT

DGS0020A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

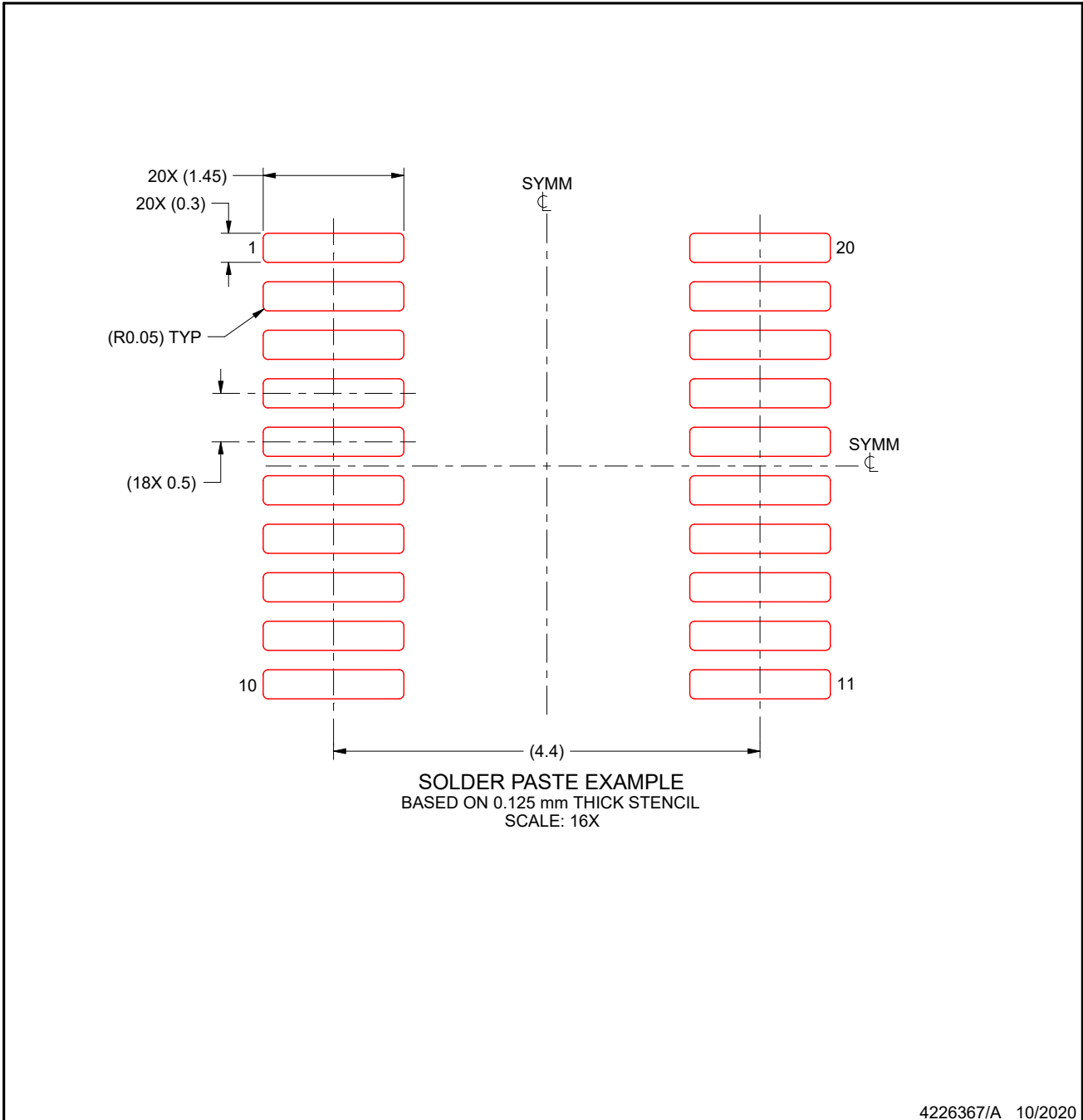
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
8. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature numbers SLMA002 (www.ti.com/lit/slma002) and SLMA004 (www.ti.com/lit/slma004).
9. Size of metal pad may vary due to creepage requirement.
10. Vias are optional depending on application, refer to device data sheet. It is recommended that vias under paste be filled, plugged or tented.

EXAMPLE STENCIL DESIGN

DGS0020A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

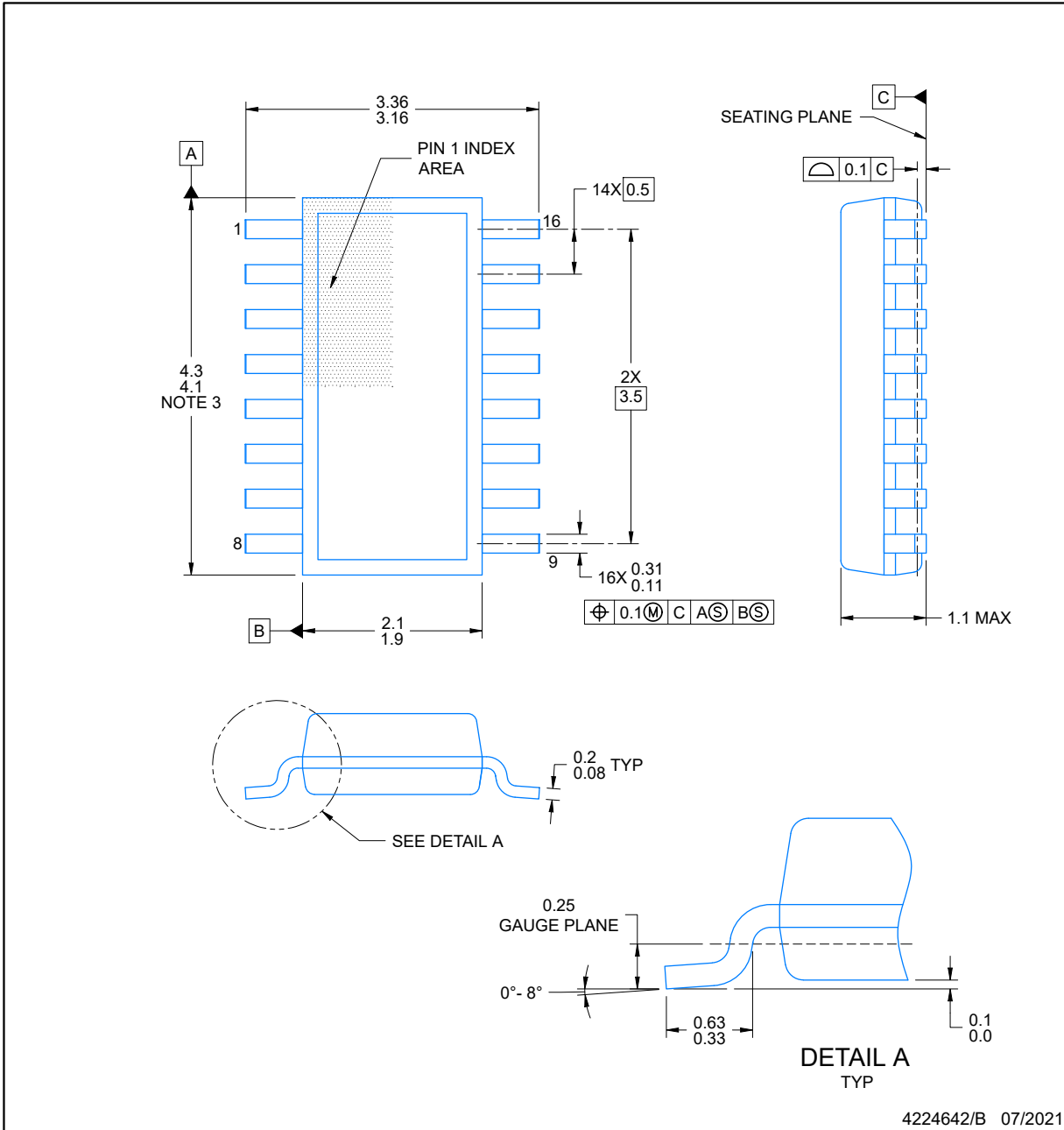
11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
12. Board assembly site may have different recommendations for stencil design.

PACKAGE OUTLINE

DYY0016A

SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE



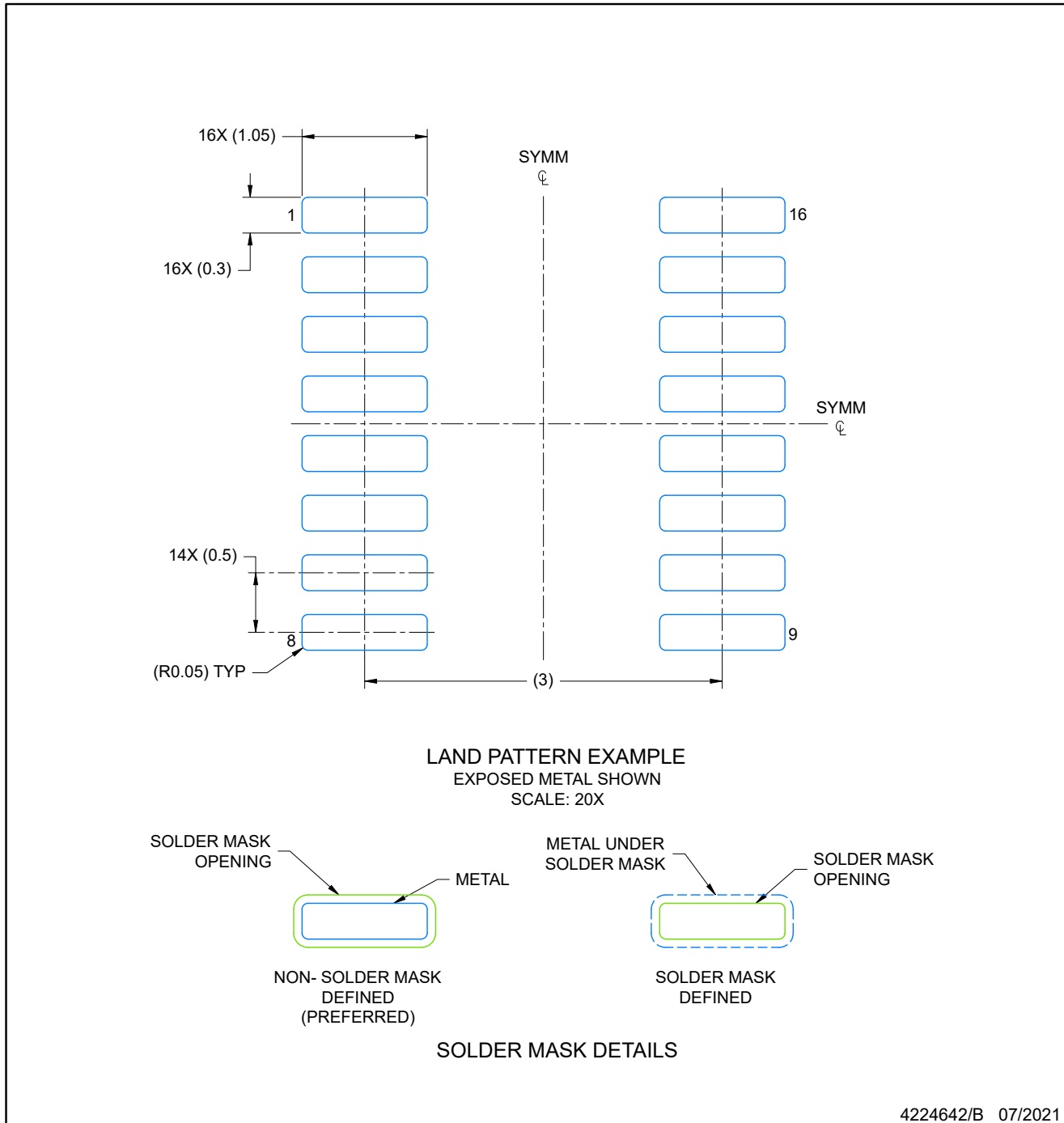
NOTES:

- All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
- This drawing is subject to change without notice.
- This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per side.
- This dimension does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- Reference JEDEC Registration MO-345, Variation AA

DYY0016A

EXAMPLE BOARD LAYOUT SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE



4224642/B 07/2021

NOTES: (continued)

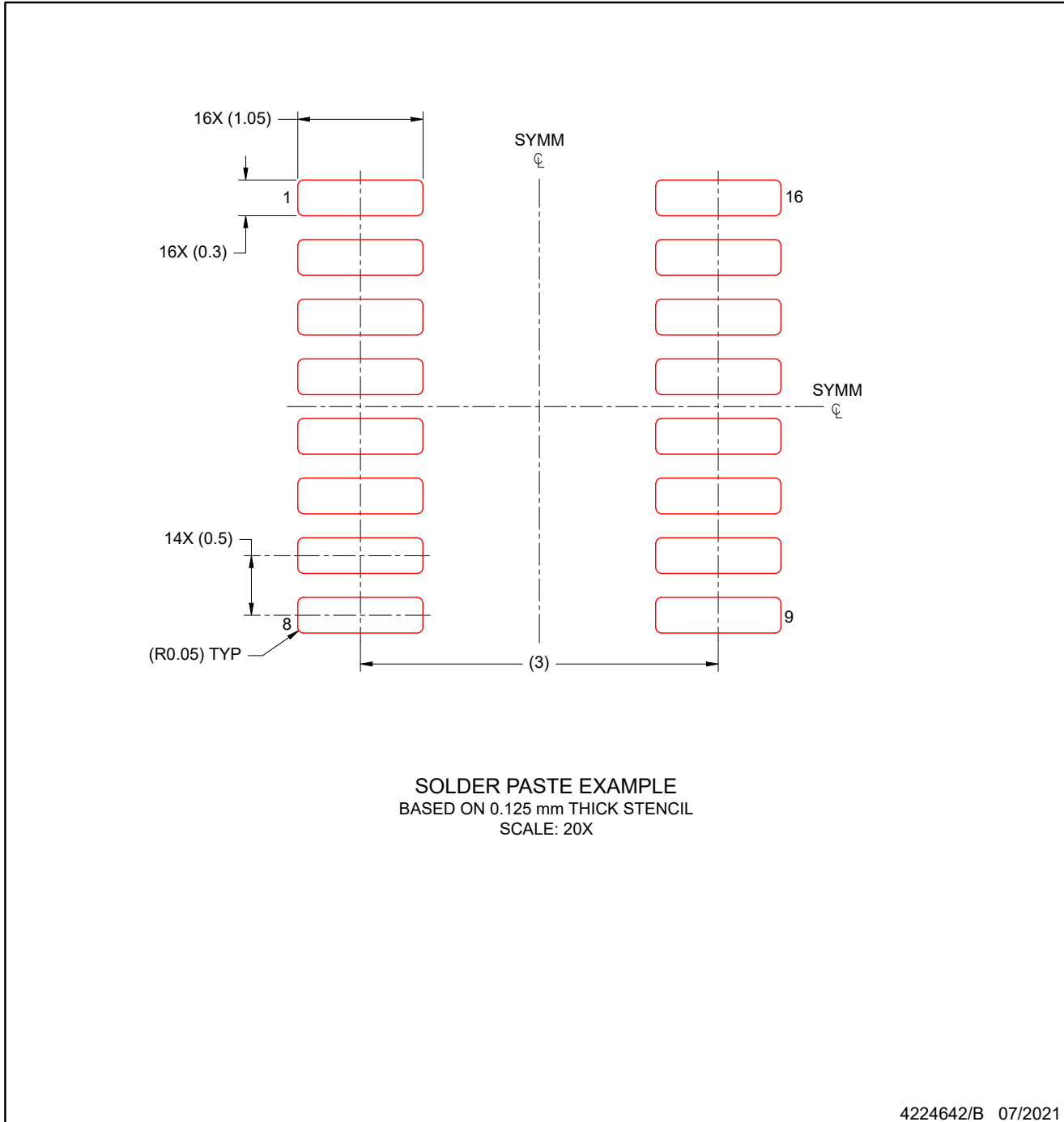
- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

SOT-23-THIN - 1.1 mm max height

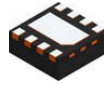
DYY0016A

PLASTIC SMALL OUTLINE



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

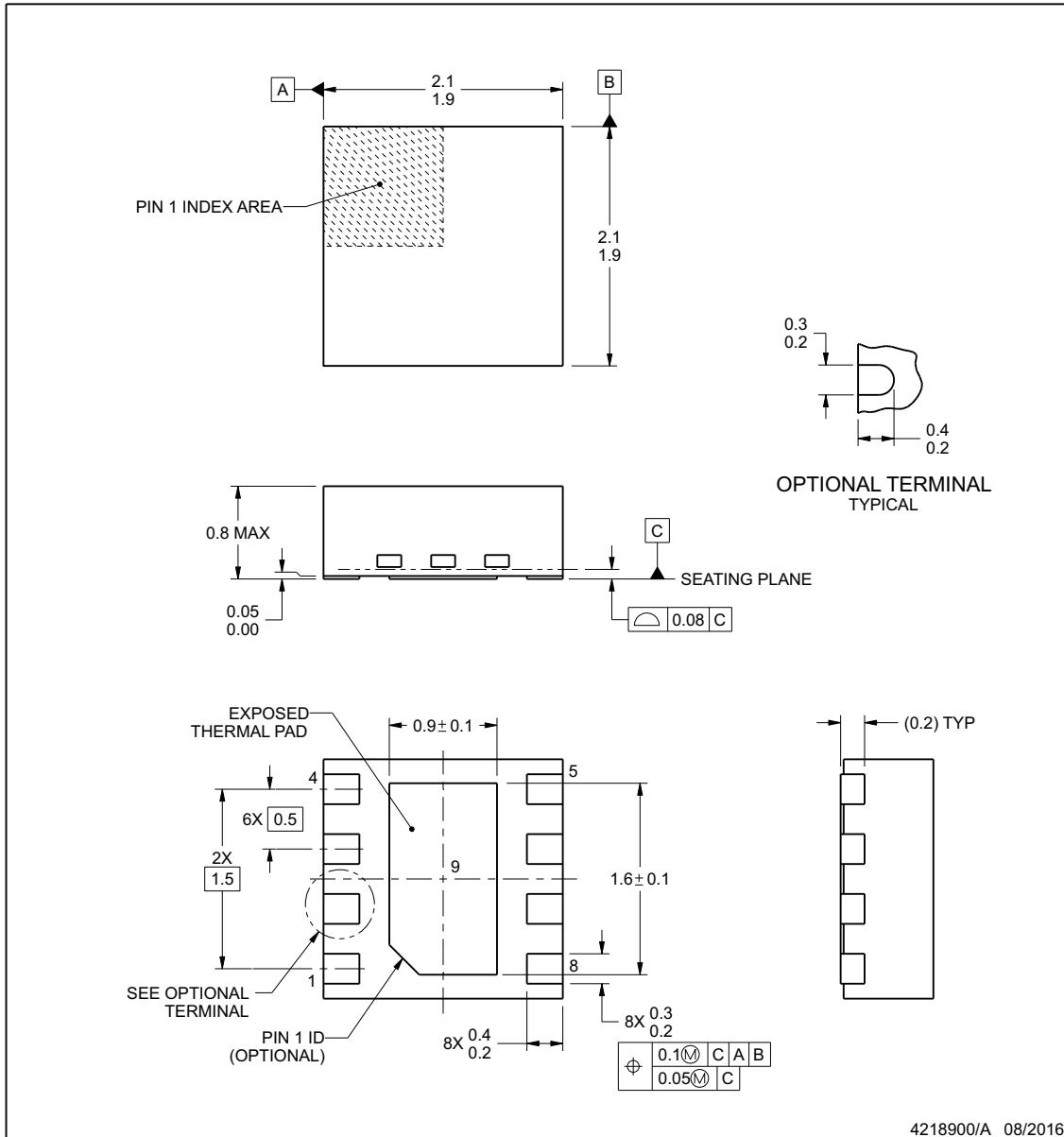


DSG0008A

PACKAGE OUTLINE

WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

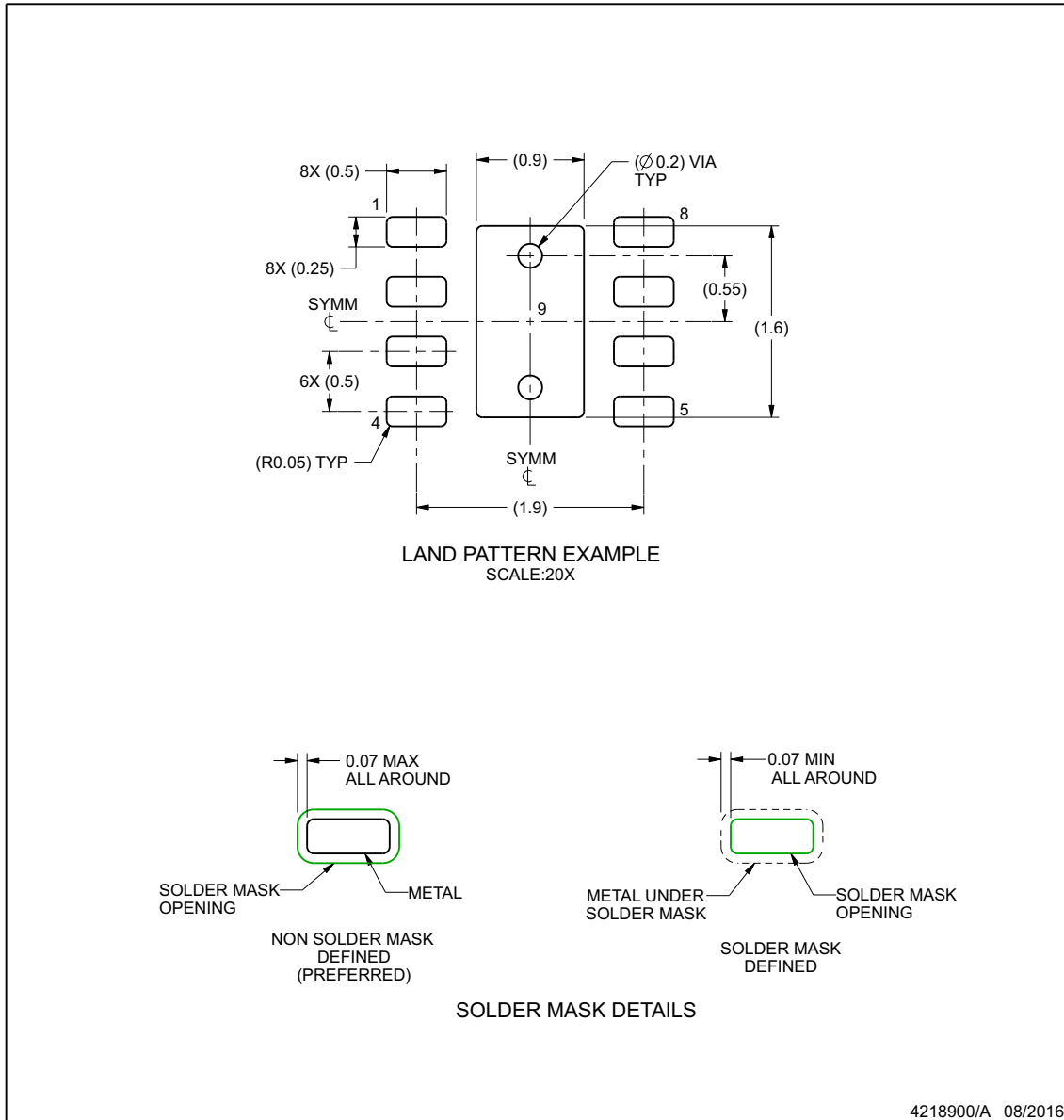
www.ti.com

EXAMPLE BOARD LAYOUT

DSG0008A

WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

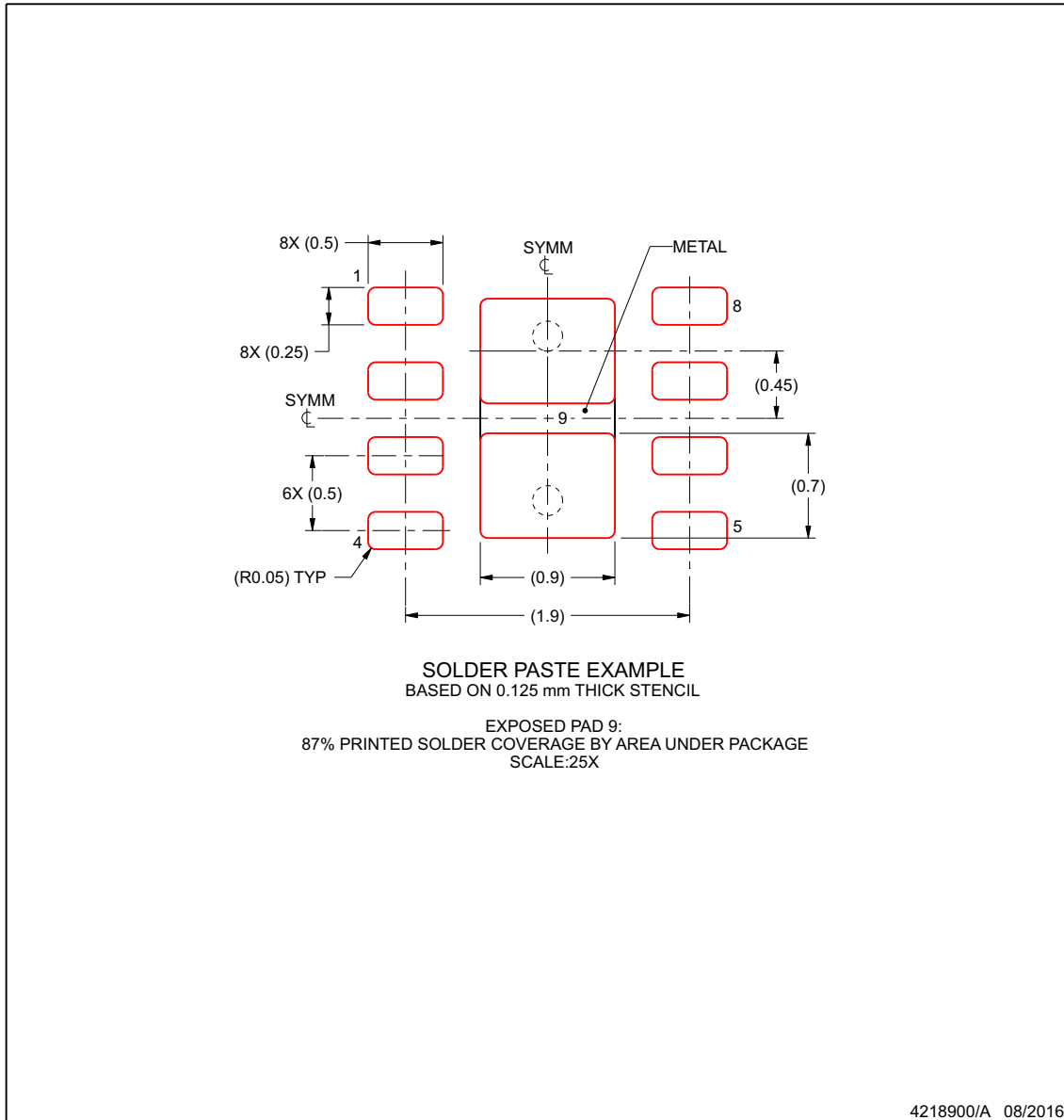
www.ti.com

EXAMPLE STENCIL DESIGN

DSG0008A

WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

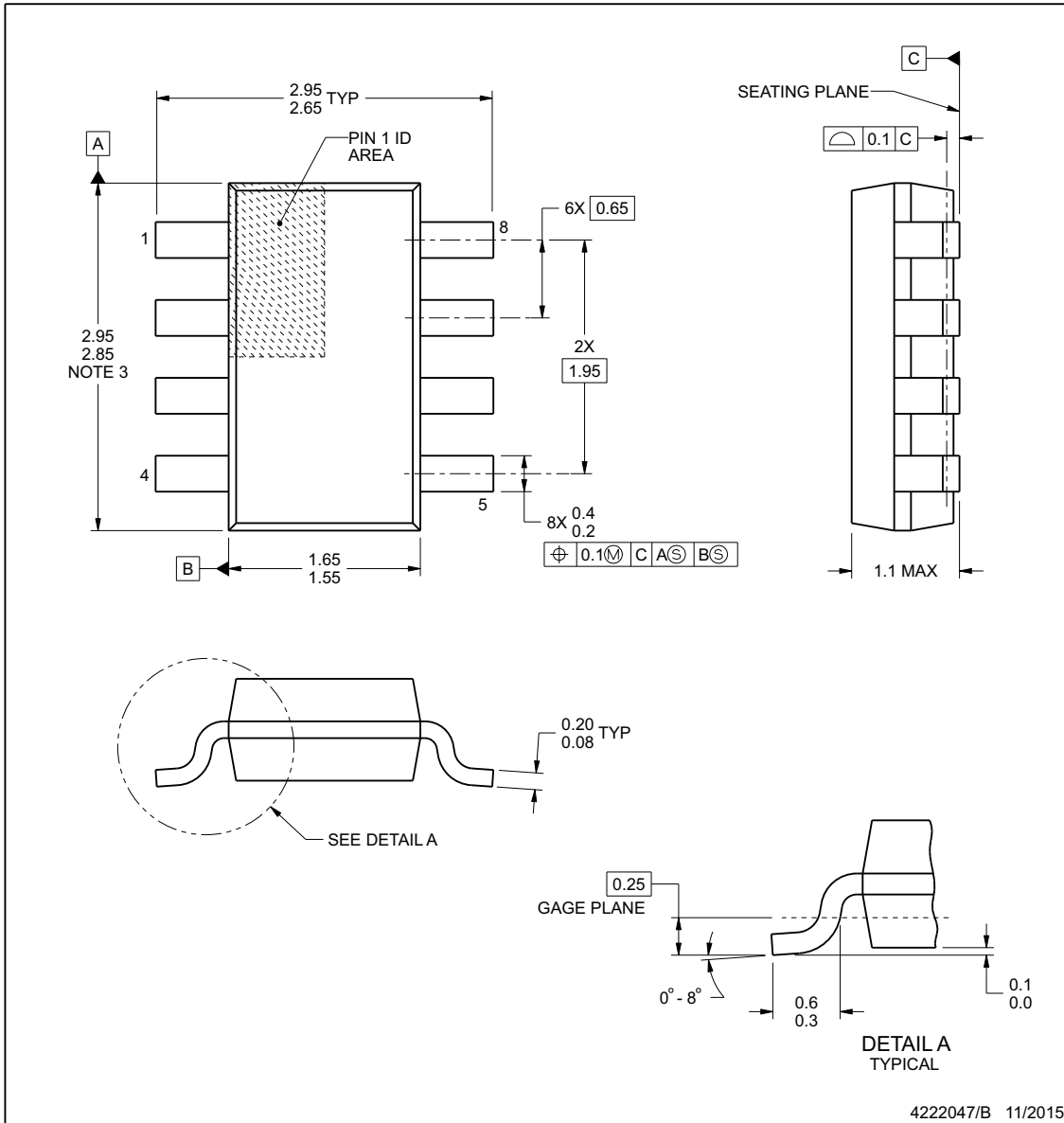
www.ti.com



DDF0008A

PACKAGE OUTLINE
SOT-23 - 1.1 mm max height

PLASTIC SMALL OUTLINE



NOTES:

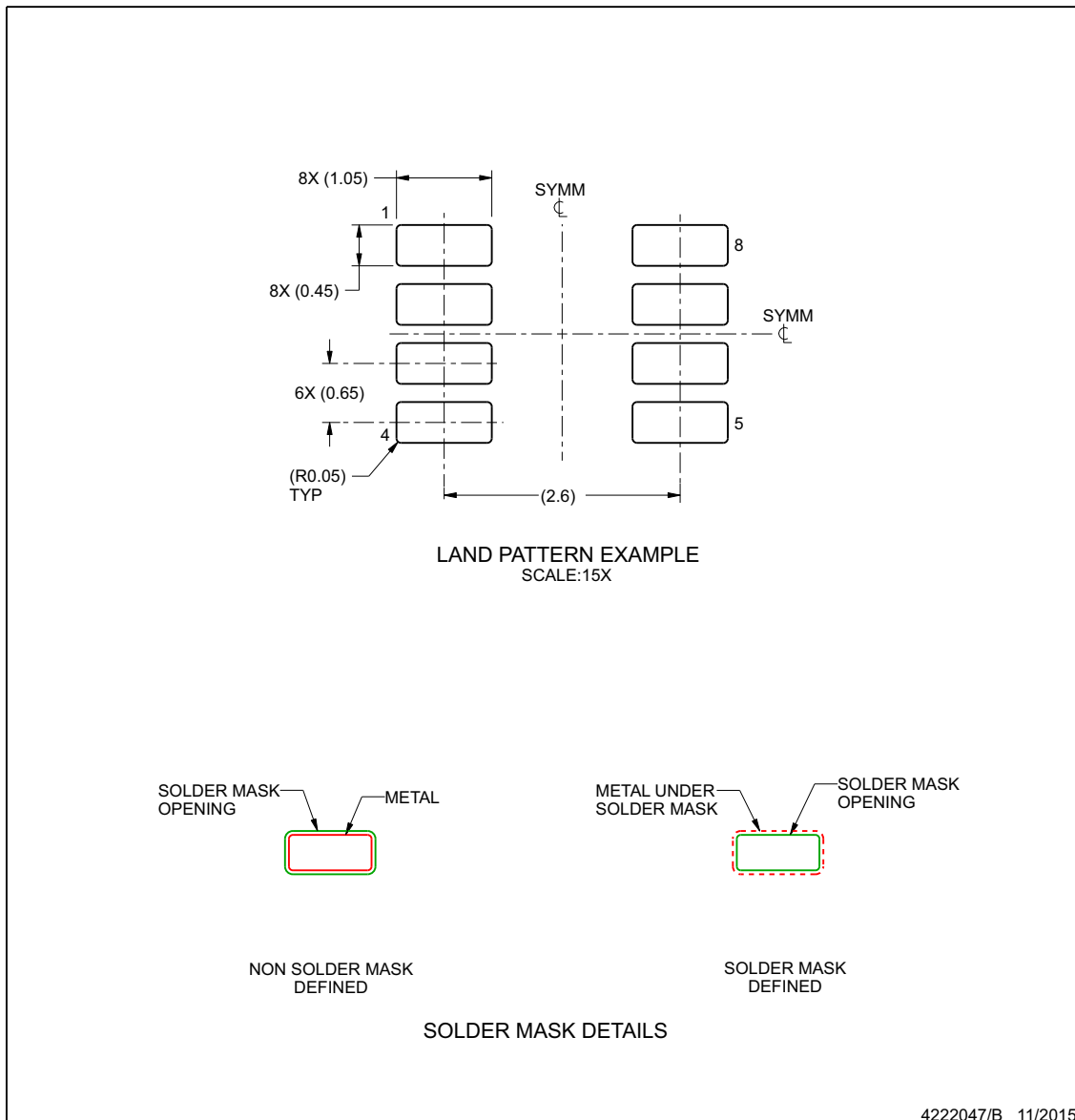
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.

EXAMPLE BOARD LAYOUT

DDF0008A

SOT-23 - 1.1 mm max height

PLASTIC SMALL OUTLINE



NOTES: (continued)

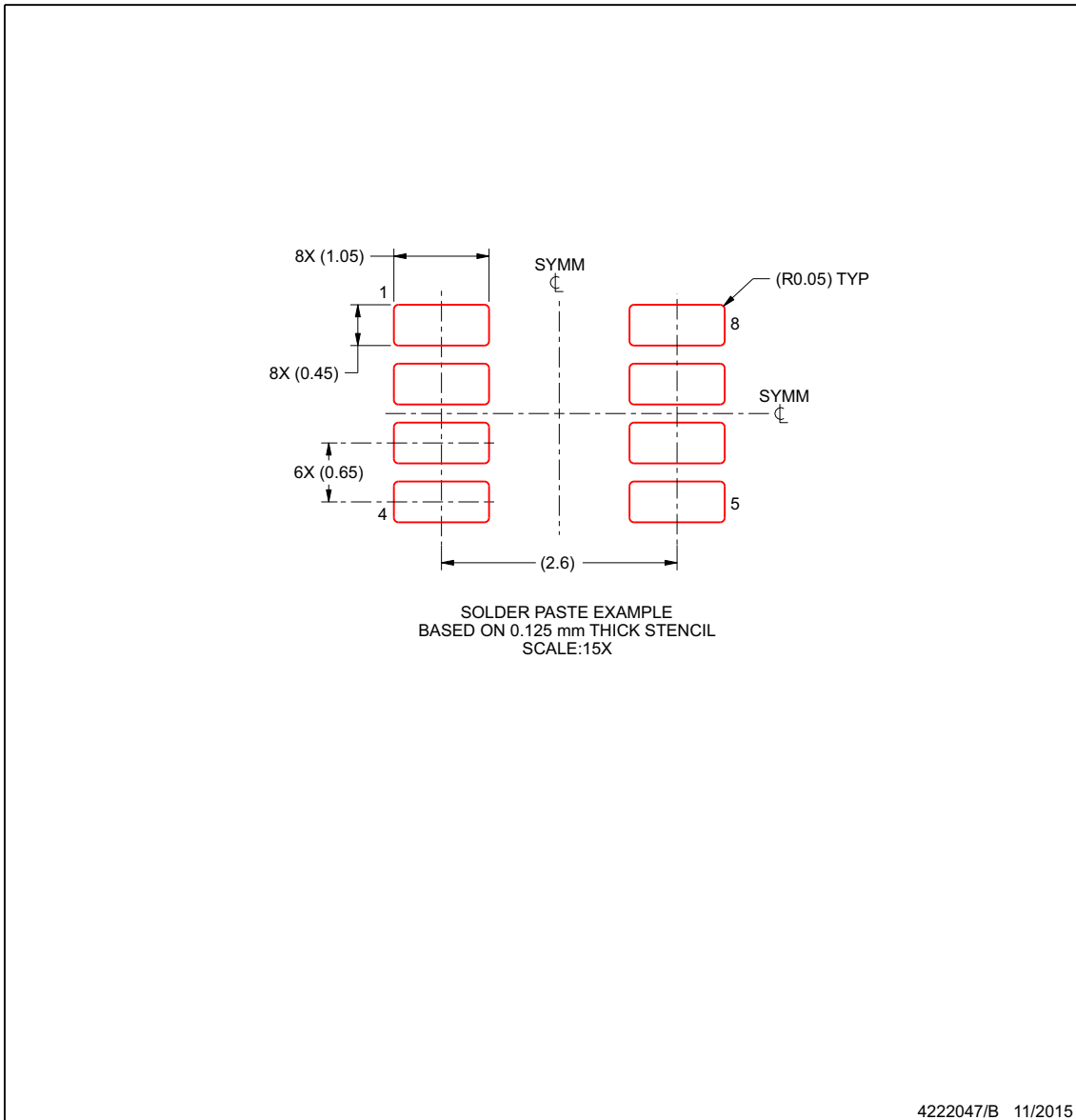
- Publication IPC-7351 may have alternate designs.
- Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DDF0008A

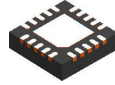
SOT-23 - 1.1 mm max height

PLASTIC SMALL OUTLINE



NOTES: (continued)

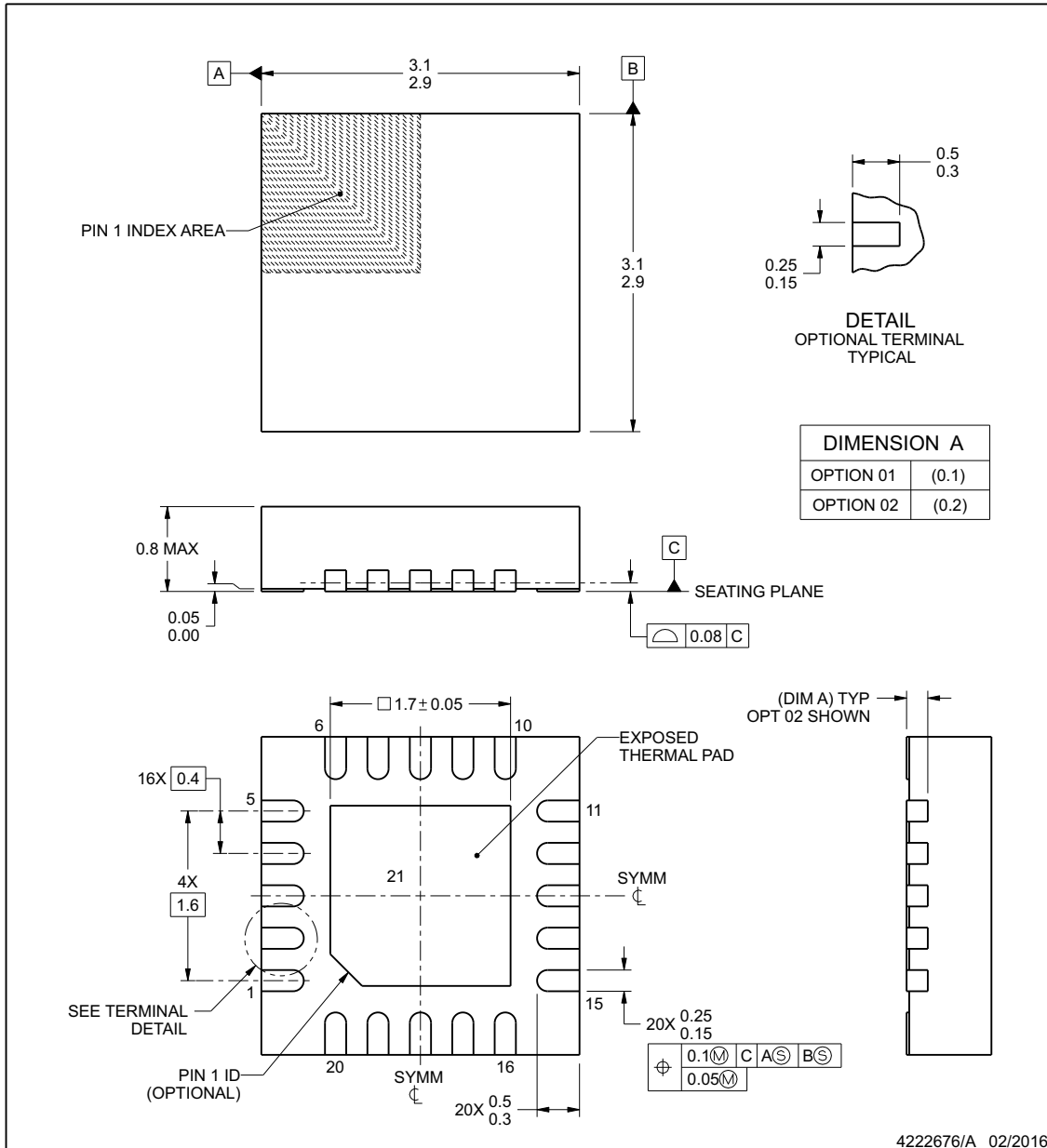
6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
7. Board assembly site may have different recommendations for stencil design.



RUK0020B

PACKAGE OUTLINE
WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

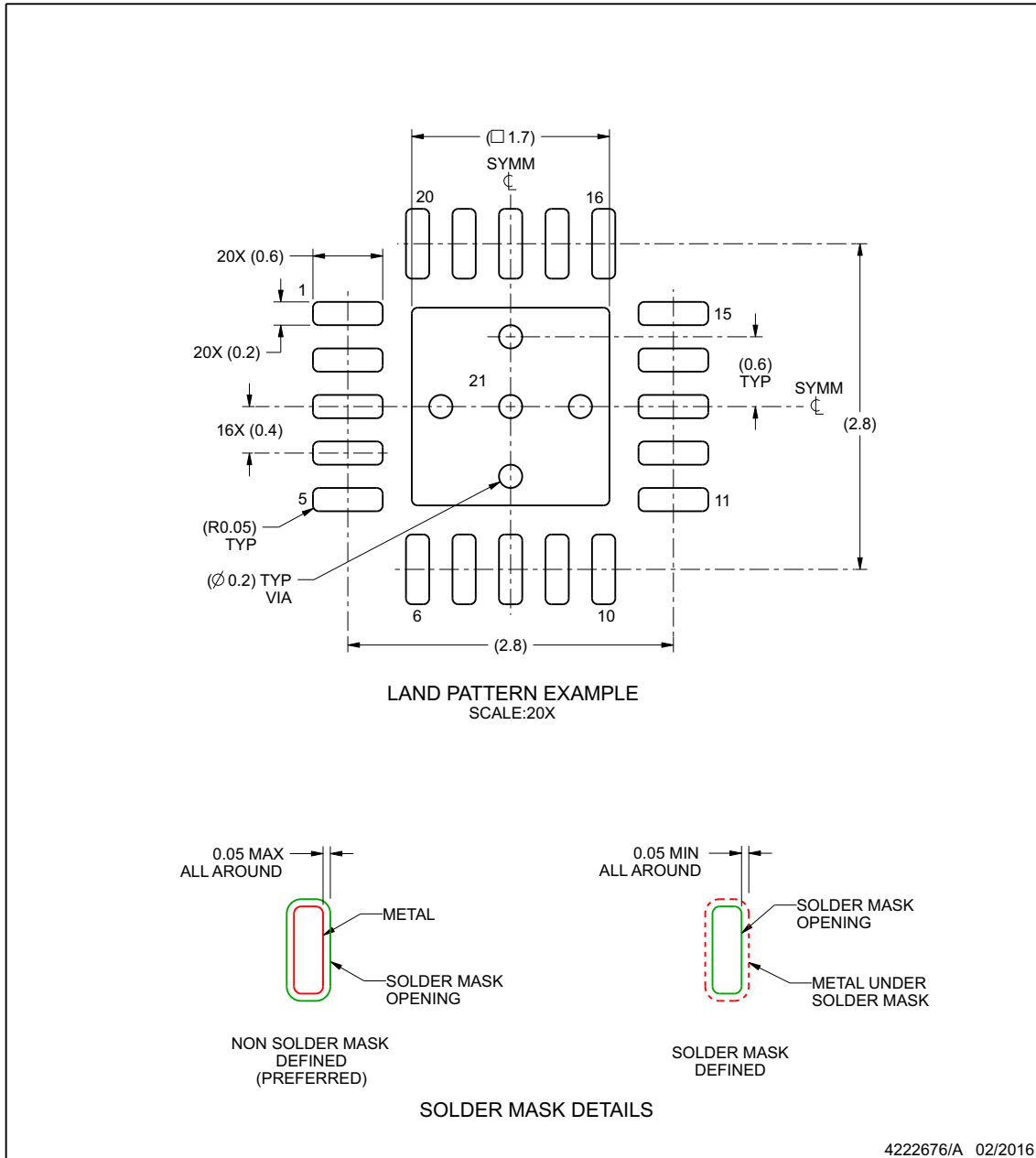
www.ti.com

EXAMPLE BOARD LAYOUT

RUK0020B

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

4. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/sluea271).
5. Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

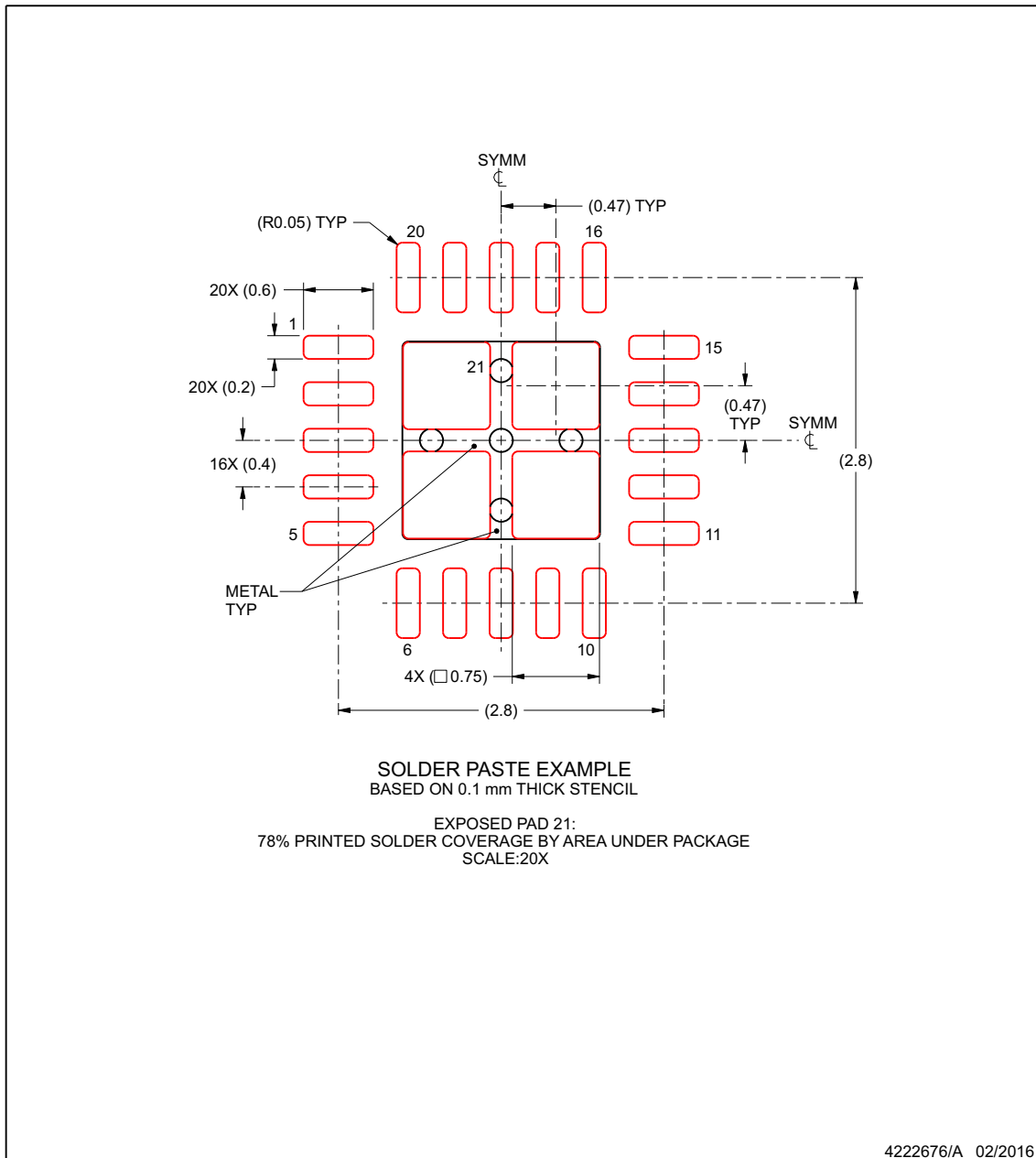
www.ti.com

EXAMPLE STENCIL DESIGN

RUK0020B

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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郵送先住所: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265

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PACKAGING INFORMATION

| Orderable part number | Status (1) | Material type (2) | Package Pins | Package qty Carrier | RoHS (3) | Lead finish/ Ball material (4) | MSL rating/ Peak reflow (5) | Op temp (°C) | Part marking (6) |
|----------------------------------|---------------|----------------------|------------------------|-----------------------|-------------|--------------------------------------|-----------------------------------|--------------|---------------------|
| M0C1103QDDFRQ1 | Active | Production | SOT-23-THIN (DDF) 8 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | C04Q |
| M0C1103QDDFRQ1.Z | Active | Production | SOT-23-THIN (DDF) 8 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | C04Q |
| M0C1103QDGS20RQ1 | Active | Production | VSSOP (DGS) 20 | 5000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1103Q |
| M0C1103QDGS20RQ1.Z | Active | Production | VSSOP (DGS) 20 | 5000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1103Q |
| M0C1103QDSGRQ1 | Active | Production | WSON (DSG) 8 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C03Q |
| M0C1103QDSGRQ1.Z | Active | Production | WSON (DSG) 8 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C03Q |
| M0C1103QDYRQ1 | Active | Production | SOT-23-THIN (DYY) 16 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1103Q |
| M0C1103QDYRQ1.Z | Active | Production | SOT-23-THIN (DYY) 16 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1103Q |
| M0C1103QRUKRQ1 | Active | Production | WQFN (RUK) 20 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C1103Q |
| M0C1103QRUKRQ1.Z | Active | Production | WQFN (RUK) 20 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C1103Q |
| M0C1104QDDFRQ1 | Active | Production | SOT-23-THIN (DDF) 8 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | C04Q |
| M0C1104QDDFRQ1.Z | Active | Production | SOT-23-THIN (DDF) 8 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | C04Q |
| M0C1104QDGS20RQ1 | Active | Production | VSSOP (DGS) 20 | 5000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1104Q |
| M0C1104QDGS20RQ1.Z | Active | Production | VSSOP (DGS) 20 | 5000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1104Q |
| M0C1104QDSGRQ1 | Active | Production | WSON (DSG) 8 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C04Q |
| M0C1104QDSGRQ1.Z | Active | Production | WSON (DSG) 8 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C04Q |
| M0C1104QDYRQ1 | Active | Production | SOT-23-THIN (DYY) 16 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1104Q |
| M0C1104QDYRQ1.Z | Active | Production | SOT-23-THIN (DYY) 16 | 3000 LARGE T&R | Yes | NIPDAU | Level-2-260C-1 YEAR | -40 to 125 | M0C1104Q |
| M0C1104QRUKRQ1 | Active | Production | WQFN (RUK) 20 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C1104Q |
| M0C1104QRUKRQ1.Z | Active | Production | WQFN (RUK) 20 | 3000 LARGE T&R | Yes | SN | Level-1-260C-UNLIM | -40 to 125 | C1104Q |

(1) **Status:** For more details on status, see our [product life cycle](#).

(2) **Material type:** When designated, preproduction parts are prototypes/experimental devices, and are not yet approved or released for full production. Testing and final process, including without limitation quality assurance, reliability performance testing, and/or process qualification, may not yet be complete, and this item is subject to further changes or possible discontinuation. If available for ordering, purchases will be subject to an additional waiver at checkout, and are intended for early internal evaluation purposes only. These items are sold without warranties of any kind.

(3) **RoHS values:** Yes, No, RoHS Exempt. See the [TI RoHS Statement](#) for additional information and value definition.

(4) **Lead finish/Ball material:** Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

(5) **MSL rating/Peak reflow:** The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

(6) **Part marking:** There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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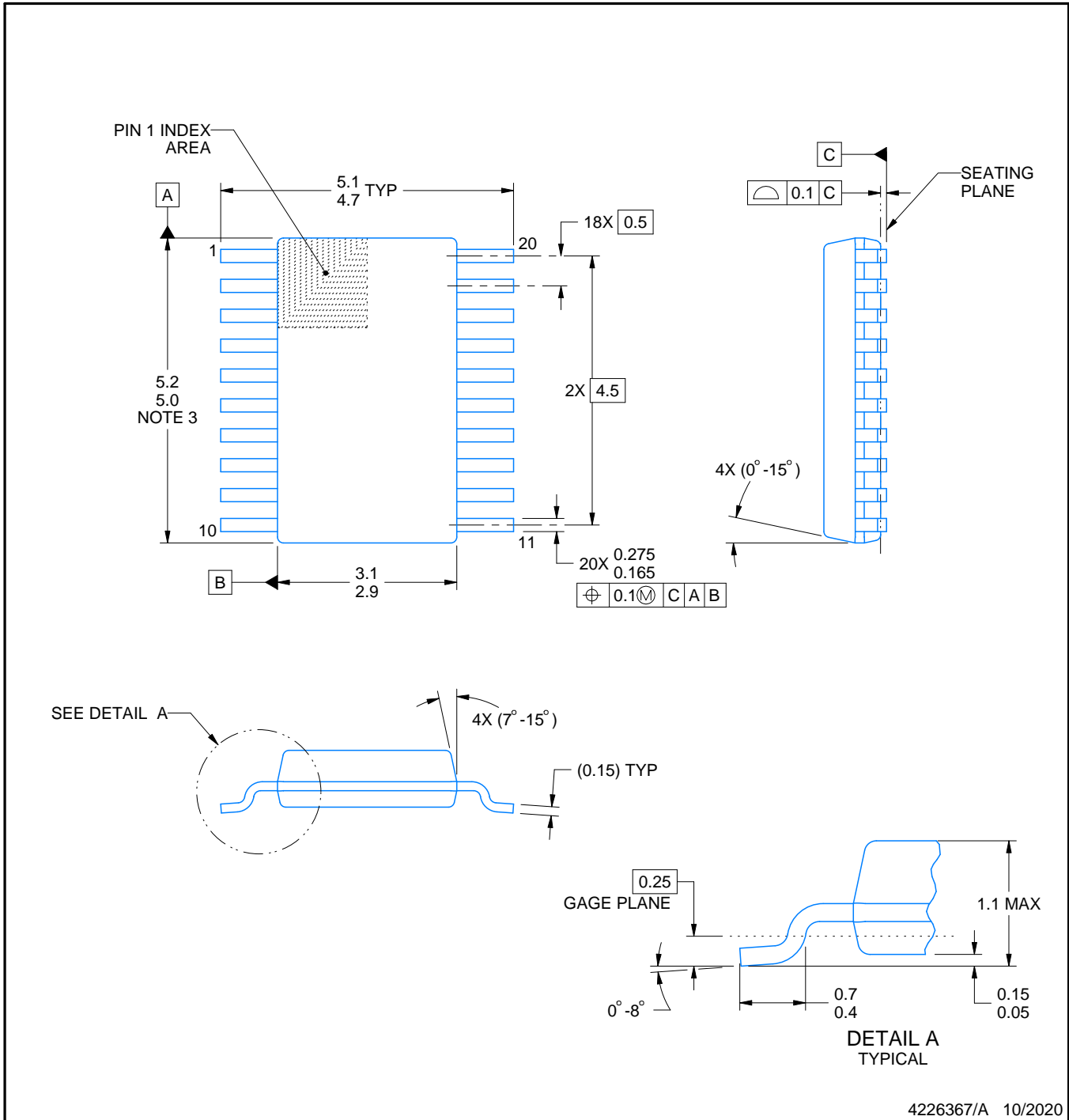
In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF MSPM0C1103-Q1, MSPM0C1104-Q1 :

- Catalog : [MSPM0C1103](#), [MSPM0C1104](#)

NOTE: Qualified Version Definitions:

- Catalog - TI's standard catalog product



NOTES:

PowerPAD is a trademark of Texas Instruments.

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. No JEDEC registration as of September 2020.
5. Features may differ or may not be present.

EXAMPLE BOARD LAYOUT

DGS0020A

VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



4226367/A 10/2020

NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.
8. This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature numbers SLMA002 (www.ti.com/lit/slma002) and SLMA004 (www.ti.com/lit/slma004).
9. Size of metal pad may vary due to creepage requirement.
10. Vias are optional depending on application, refer to device data sheet. It is recommended that vias under paste be filled, plugged or tented.

EXAMPLE STENCIL DESIGN

DGS0020A

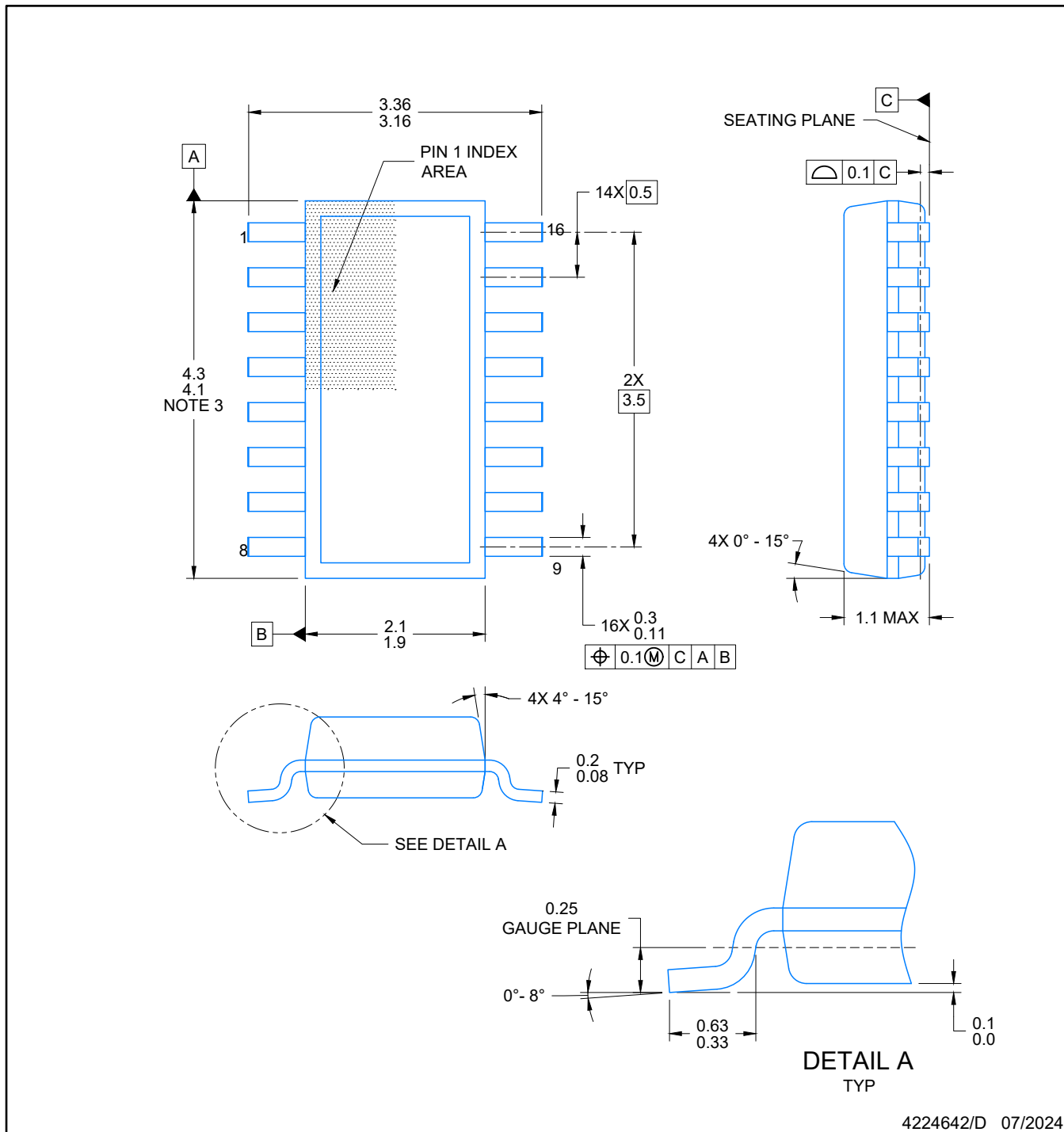
VSSOP - 1.1 mm max height

SMALL OUTLINE PACKAGE



NOTES: (continued)

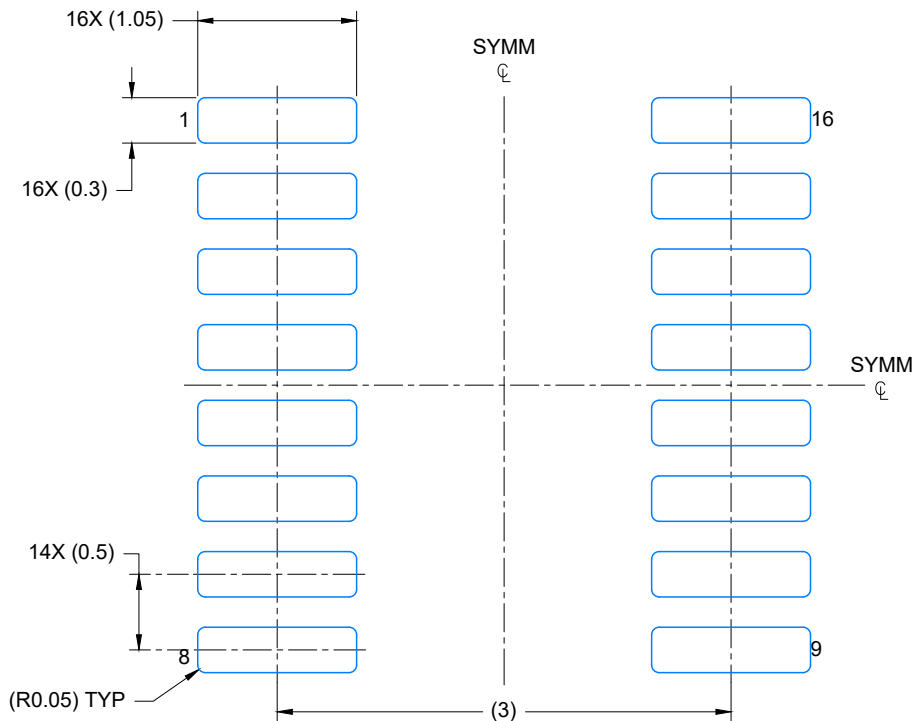
11. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
12. Board assembly site may have different recommendations for stencil design.



4224642/D 07/2024

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
5. Reference JEDEC Registration MO-345, Variation AA



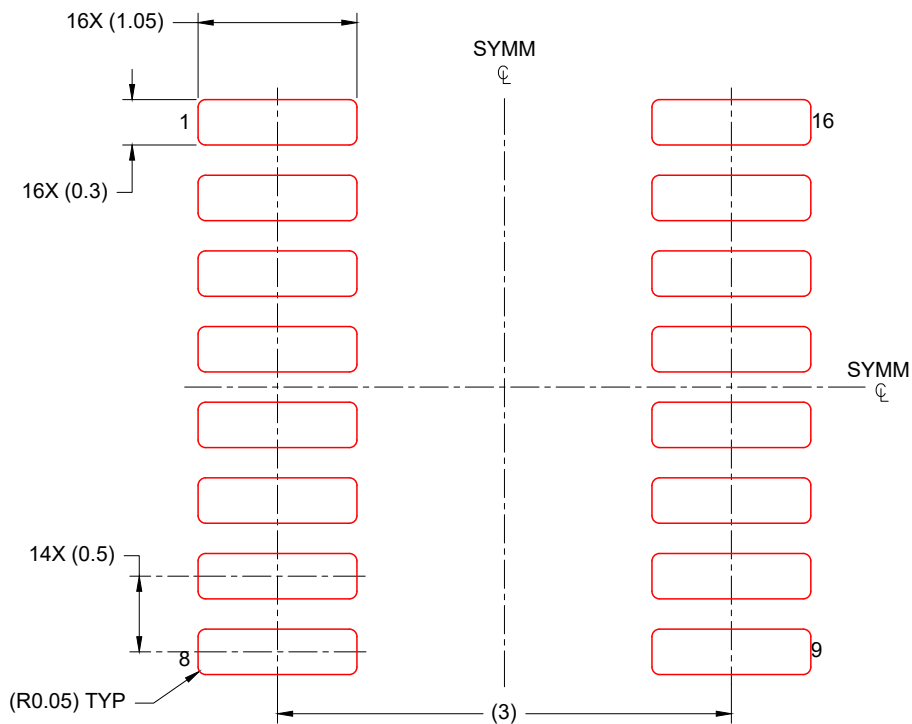
LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 20X



4224642/D 07/2024

NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 20X

4224642/D 07/2024

NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.

DDF0008A



PACKAGE OUTLINE

SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE



4222047/E 07/2024

NOTES:

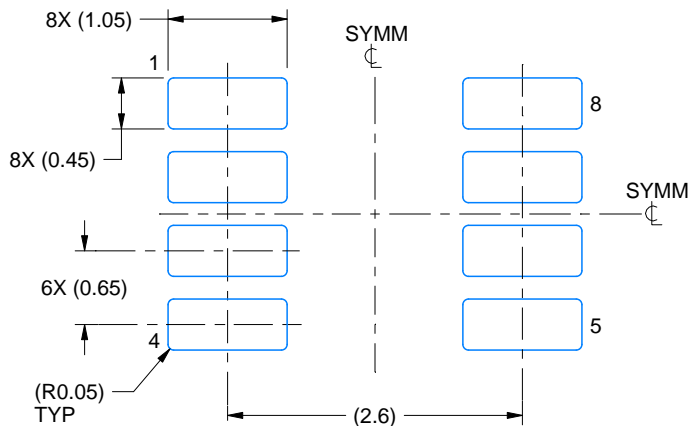
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.

EXAMPLE BOARD LAYOUT

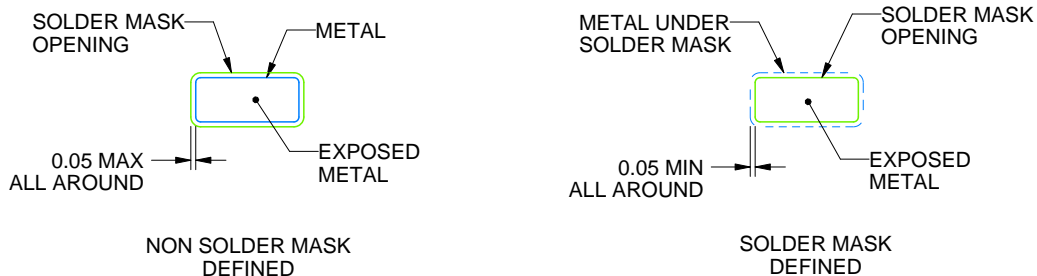
DDF0008A

SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:15X



SOLDER MASK DETAILS

4222047/E 07/2024

NOTES: (continued)

- 4. Publication IPC-7351 may have alternate designs.
- 5. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DDF0008A

SOT-23-THIN - 1.1 mm max height

PLASTIC SMALL OUTLINE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE:15X

4222047/E 07/2024

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
7. Board assembly site may have different recommendations for stencil design.

GENERIC PACKAGE VIEW

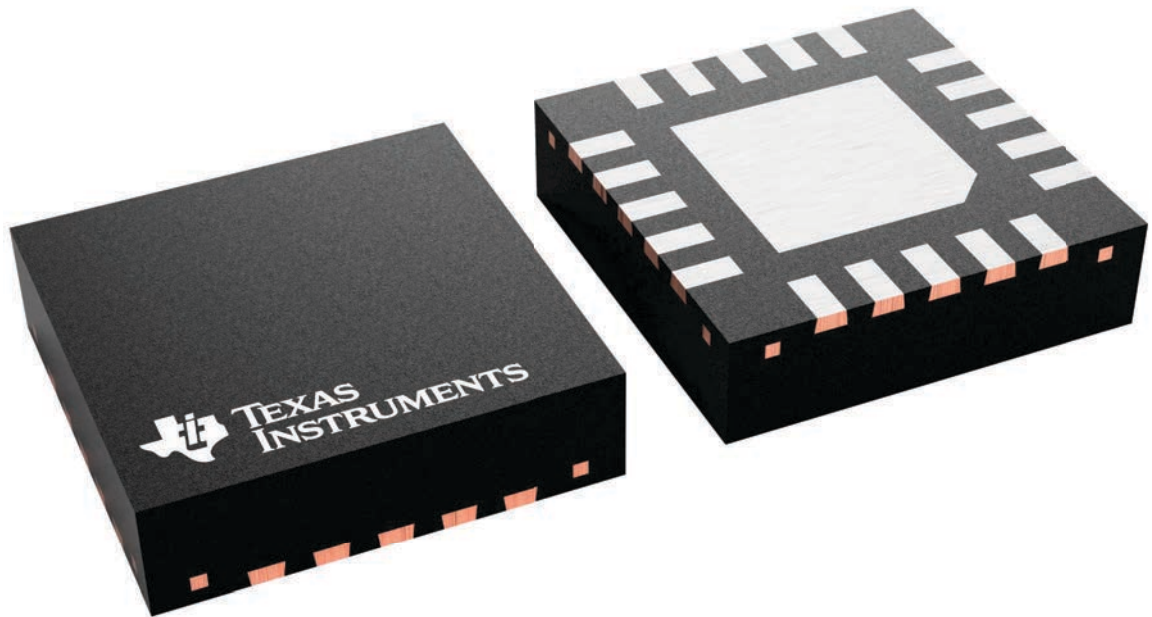
RUK 20

WQFN - 0.8 mm max height

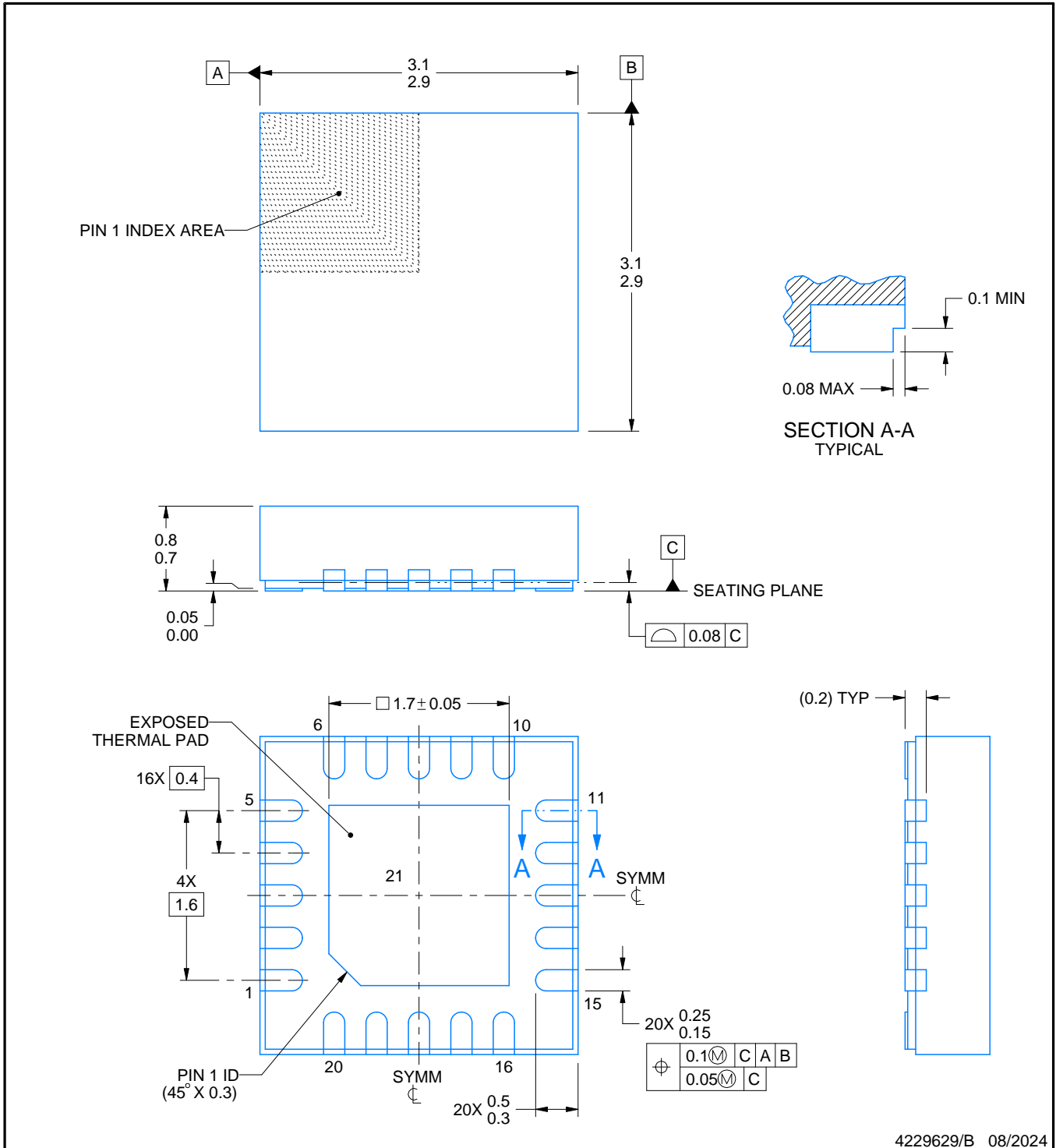
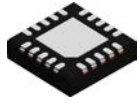
3 x 3, 0.4 mm pitch

PLASTIC QUAD FLATPACK - NO LEAD

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



4229651/A



4229629/B 08/2024

NOTES:

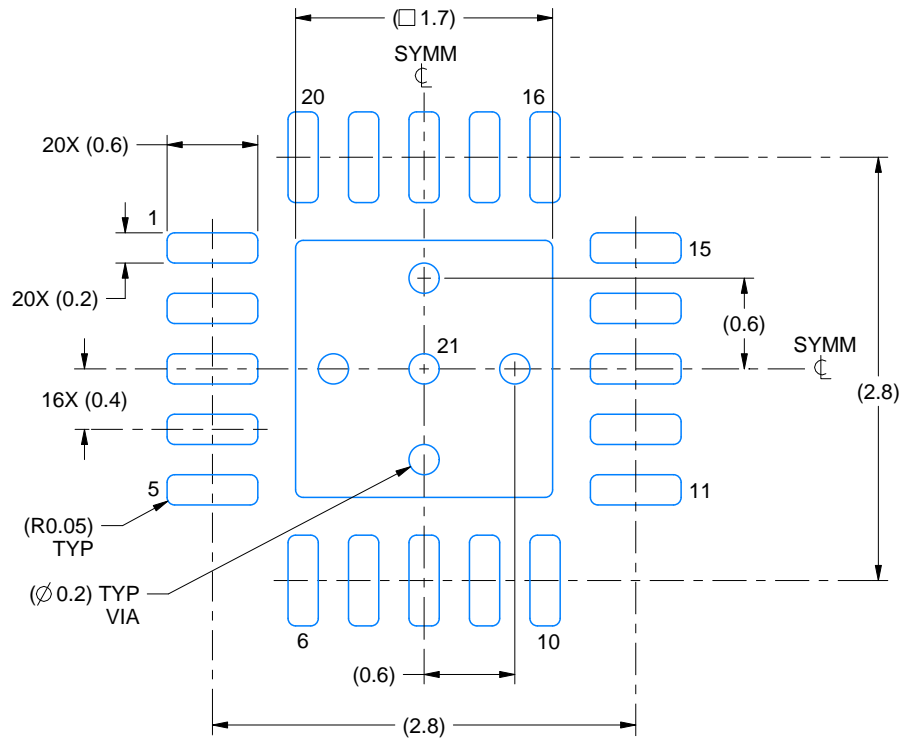
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

EXAMPLE BOARD LAYOUT

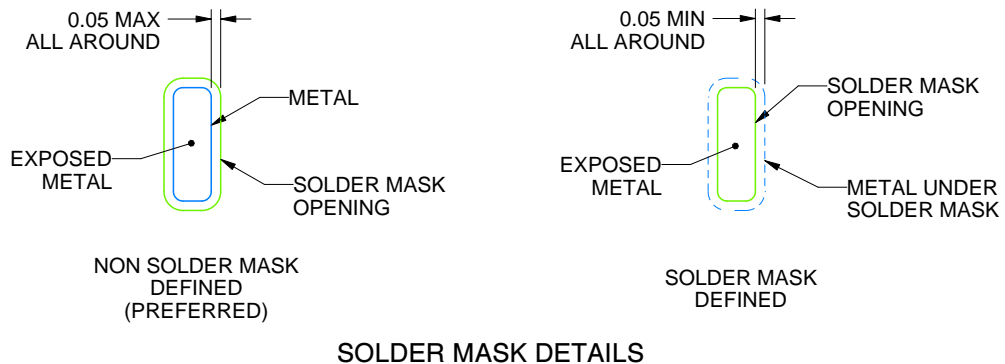
RUK0020C

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:20X



SOLDER MASK DETAILS

4229629/B 08/2024

NOTES: (continued)

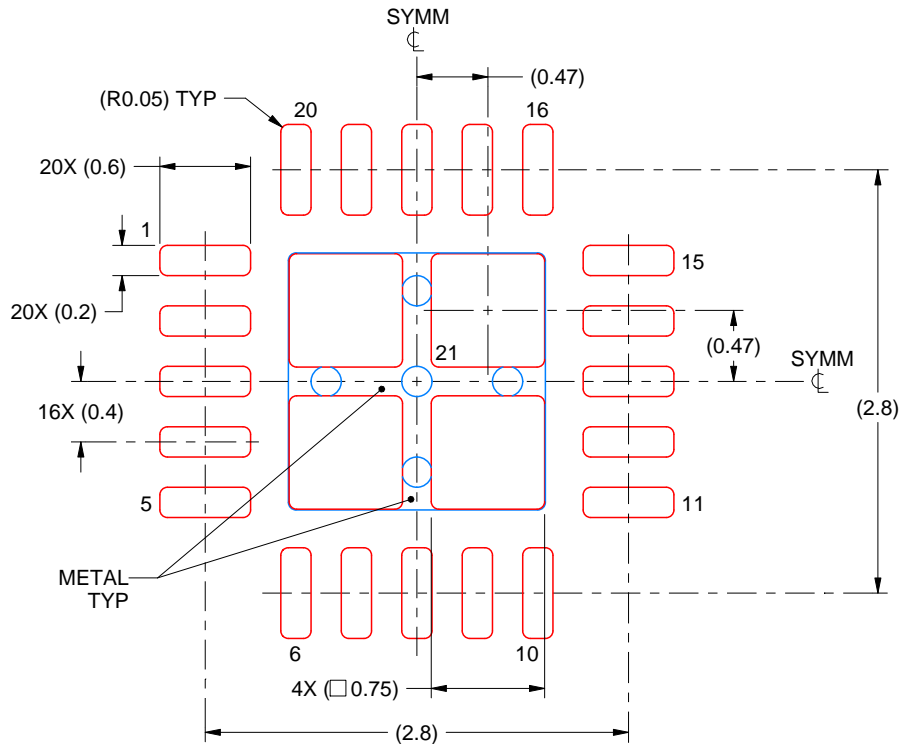
- This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

EXAMPLE STENCIL DESIGN

RUK0020C

WQFN - 0.8 mm max height

PLASTIC QUAD FLATPACK - NO LEAD



SOLDER PASTE EXAMPLE
BASED ON 0.1 mm THICK STENCIL

EXPOSED PAD 21:
78% PRINTED SOLDER COVERAGE BY AREA UNDER PACKAGE
SCALE:20X

4229629/B 08/2024

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

GENERIC PACKAGE VIEW

DSG 8

WSON - 0.8 mm max height

2 x 2, 0.5 mm pitch

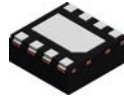
PLASTIC SMALL OUTLINE - NO LEAD

This image is a representation of the package family, actual package may vary.
Refer to the product data sheet for package details.



4224783/A

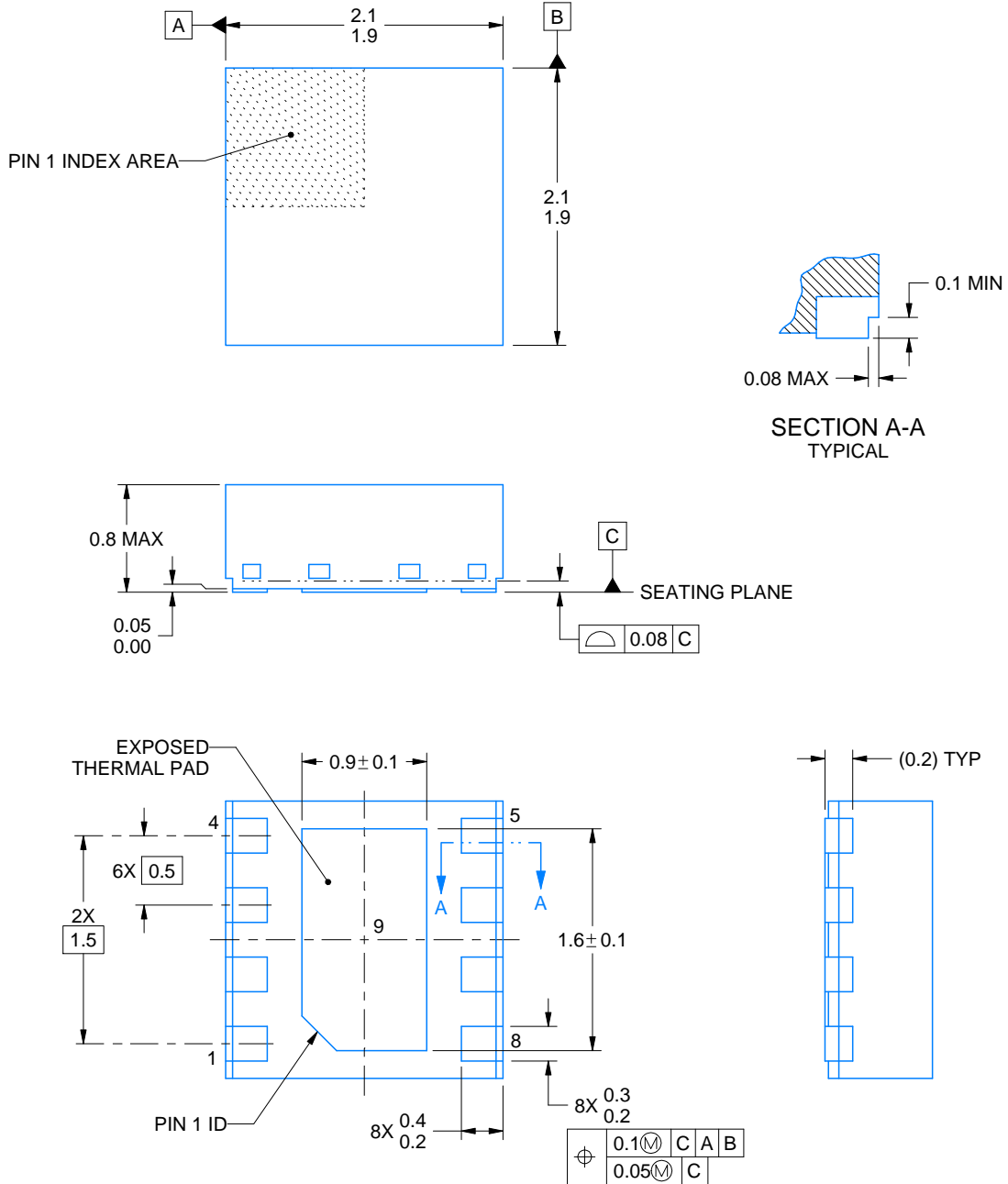
DSG0008D



PACKAGE OUTLINE

WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



4231093/A 08/2024

NOTES:

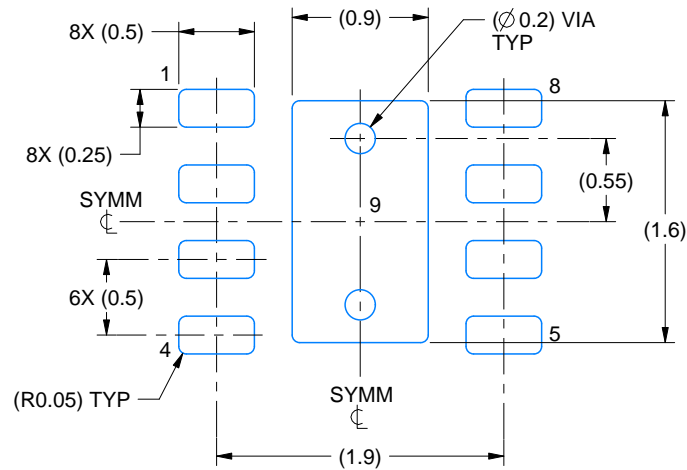
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. The package thermal pad must be soldered to the printed circuit board for thermal and mechanical performance.

EXAMPLE BOARD LAYOUT

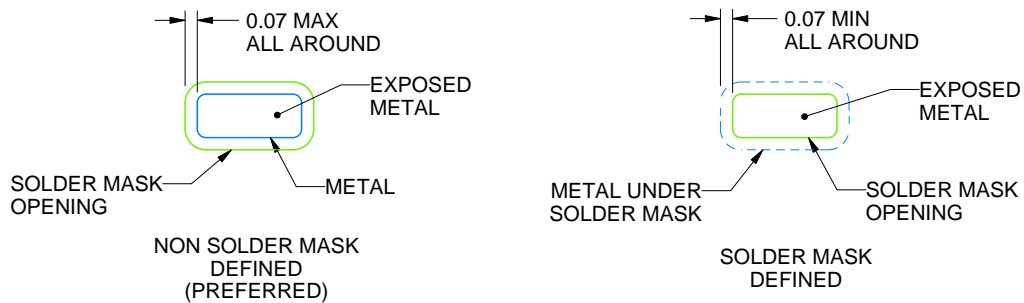
DSG0008D

WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE:20X



SOLDER MASK DETAILS

4231093/A 08/2024

NOTES: (continued)

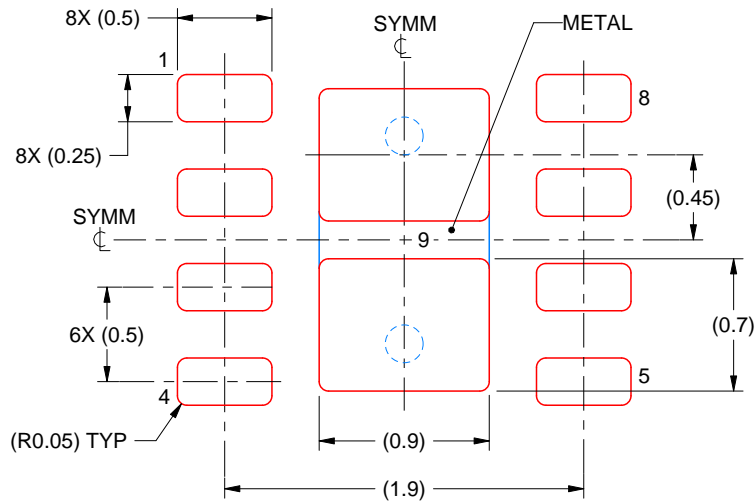
- This package is designed to be soldered to a thermal pad on the board. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).
- Vias are optional depending on application, refer to device data sheet. If any vias are implemented, refer to their locations shown on this view. It is recommended that vias under paste be filled, plugged or tented.

EXAMPLE STENCIL DESIGN

DSG0008D

WSON - 0.8 mm max height

PLASTIC SMALL OUTLINE - NO LEAD



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL

EXPOSED PAD 9:
87% PRINTED SOLDER COVERAGE BY AREA UNDER PACKAGE
SCALE:25X

4231093/A 08/2024

NOTES: (continued)

6. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

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